



Relion® 670 series

Busbar protection REB670 2.0 ANSI Commissioning Manual



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This product includes software developed by the OpenSSL Project for use in the OpenSSL Toolkit. (<http://www.openssl.org/>)

This product includes cryptographic software written/developed by: Eric Young (eay@cryptsoft.com) and Tim Hudson (tjh@cryptsoft.com).

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Conformity

This product complies with the directive of the Council of the European Communities on the approximation of the laws of the Member States relating to electromagnetic compatibility (EMC Directive 2004/108/EC) and concerning electrical equipment for use within specified voltage limits (Low-voltage directive 2006/95/EC). This conformity is the result of tests conducted by ABB in accordance with the product standard EN 60255-26 for the EMC directive, and with the product standards EN 60255-1 and EN 60255-27 for the low voltage directive. The product is designed in accordance with the international standards of the IEC 60255 series and ANSI C37.90.

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Section 1 Introduction

1.1 This manual

The commissioning manual contains instructions on how to commission the IED. The manual can also be used by system engineers and maintenance personnel for assistance during the testing phase. The manual provides procedures for the checking of external circuitry and energizing the IED, parameter setting and configuration as well as verifying settings by secondary injection. The manual describes the process of testing an IED in a substation which is not in service. The chapters are organized in the chronological order in which the IED should be commissioned. The relevant procedures may be followed also during the service and maintenance activities.

1.2 Intended audience

This manual addresses the personnel responsible for commissioning, maintenance and taking the IED in and out of normal service.

The commissioning personnel must have a basic knowledge of handling electronic equipment. The commissioning and maintenance personnel must be well experienced in using protection equipment, test equipment, protection functions and the configured functional logics in the IED.

1.3 Product documentation

1.3.1 Product documentation set

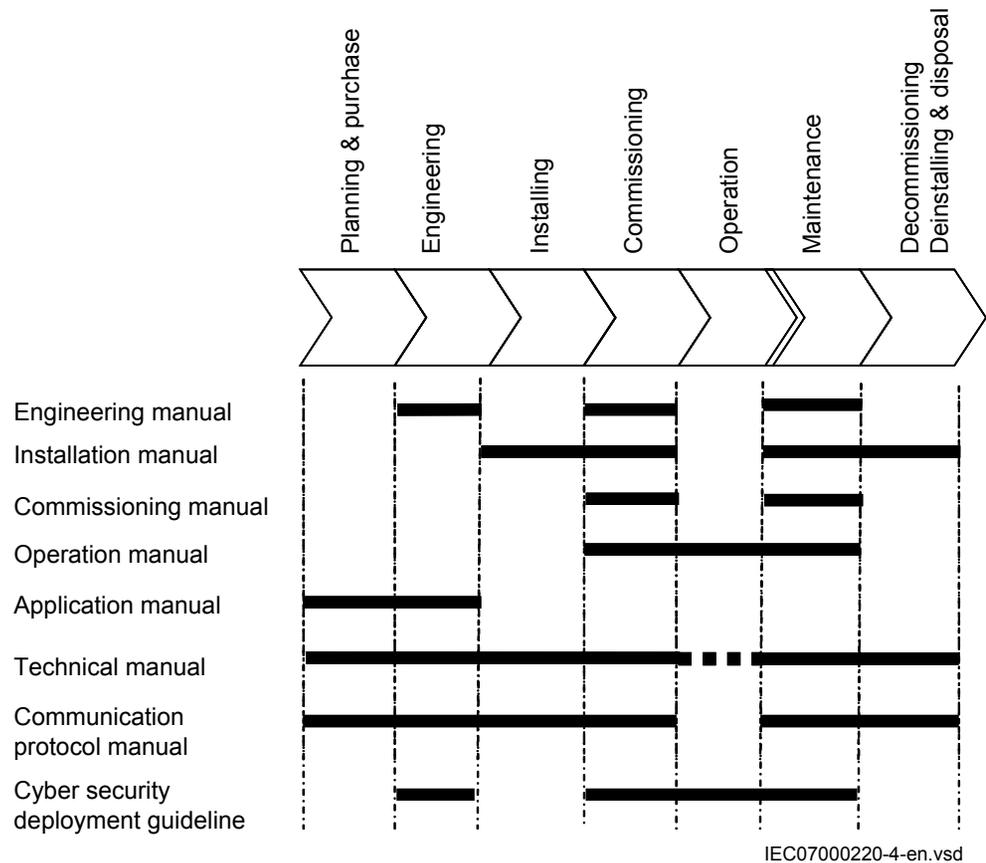


Figure 1: The intended use of manuals throughout the product lifecycle

The engineering manual contains instructions on how to engineer the IEDs using the various tools available within the PCM600 software. The manual provides instructions on how to set up a PCM600 project and insert IEDs to the project structure. The manual also recommends a sequence for the engineering of protection and control functions, LHMI functions as well as communication engineering for IEC 60870-5-103, IEC 61850 and DNP3.

The installation manual contains instructions on how to install the IED. The manual provides procedures for mechanical and electrical installation. The chapters are organized in the chronological order in which the IED should be installed.

The commissioning manual contains instructions on how to commission the IED. The manual can also be used by system engineers and maintenance personnel for assistance during the testing phase. The manual provides procedures for the checking of external circuitry and energizing the IED, parameter setting and configuration as well as verifying settings by secondary injection. The manual describes the process of testing an IED in a substation which is not in service. The chapters are organized in the chronological order in which the IED should be commissioned. The relevant procedures may be followed also during the service and maintenance activities.

The operation manual contains instructions on how to operate the IED once it has been commissioned. The manual provides instructions for the monitoring, controlling and setting of the IED. The manual also describes how to identify disturbances and how to view calculated and measured power grid data to determine the cause of a fault.

The application manual contains application descriptions and setting guidelines sorted per function. The manual can be used to find out when and for what purpose a typical protection function can be used. The manual can also provide assistance for calculating settings.

The technical manual contains application and functionality descriptions and lists function blocks, logic diagrams, input and output signals, setting parameters and technical data, sorted per function. The manual can be used as a technical reference during the engineering phase, installation and commissioning phase, and during normal service.

The communication protocol manual describes the communication protocols supported by the IED. The manual concentrates on the vendor-specific implementations.

The point list manual describes the outlook and properties of the data points specific to the IED. The manual should be used in conjunction with the corresponding communication protocol manual.

The cyber security deployment guideline describes the process for handling cyber security when communicating with the IED. Certification, Authorization with role based access control, and product engineering for cyber security related events are described and sorted by function. The guideline can be used as a technical reference during the engineering phase, installation and commissioning phase, and during normal service.

1.3.2

Document revision history

Document revision/date	History
-/May 2014	First release

1.3.3

Related documents

Documents related to REB670	Identify number
Application manual	1MRK 505 302-UUS
Commissioning manual	1MRK 505 304-UUS
Product guide	1MRK 505 305-BUS
Technical manual	1MRK 505 303-UUS
Type test certificate	1MRK 505 305-TUS

670 series manuals	Identify number
Operation manual	1MRK 500 118-UUS
Engineering manual	1MRK 511 308-UUS
Installation manual	1MRK 514 019-UUS
Communication protocol manual, DNP3	1MRK 511 301-UUS
Communication protocol manual, IEC 61850 Edition 2	1MRK 511 303-UUS
Accessories guide	1MRK 514 012-BUS
Connection and Installation components	1MRK 513 003-BEN
Test system, COMBITEST	1MRK 512 001-BEN

1.4

Document symbols and conventions

1.4.1

Symbols



The electrical warning icon indicates the presence of a hazard which could result in electrical shock.



The warning icon indicates the presence of a hazard which could result in personal injury.



The caution hot surface icon indicates important information or warning about the temperature of product surfaces.



The caution icon indicates important information or warning related to the concept discussed in the text. It might indicate the presence of a hazard which could result in corruption of software or damage to equipment or property.



The information icon alerts the reader of important facts and conditions.



The tip icon indicates advice on, for example, how to design your project or how to use a certain function.

Although warning hazards are related to personal injury, it is necessary to understand that under certain operational conditions, operation of damaged equipment may result in degraded process performance leading to personal injury or death. It is important that the user fully complies with all warning and cautionary notices.

1.4.2

Document conventions

- Abbreviations and acronyms in this manual are spelled out in the glossary. The glossary also contains definitions of important terms.
- Push button navigation in the LHMI menu structure is presented by using the push button icons.
For example, to navigate between the options, use  and .
- HMI menu paths are presented in bold.
For example, select **Main menu/Settings**.
- LHMI messages are shown in Courier font.
For example, to save the changes in non-volatile memory, select `Yes` and press .
- Parameter names are shown in italics.
For example, the function can be enabled and disabled with the *Operation* setting.
- Each function block symbol shows the available input/output signal.
 - the character ^ in front of an input/output signal name indicates that the signal name may be customized using the PCM600 software.
 - the character * after an input/output signal name indicates that the signal must be connected to another function block in the application configuration to achieve a valid application configuration.
- Logic diagrams describe the signal logic inside the function block and are bordered by dashed lines.

- Signals in frames with a shaded area on their right hand side represent setting parameter signals that are only settable via the PST or LHMI.
 - If an internal signal path cannot be drawn with a continuous line, the suffix -int is added to the signal name to indicate where the signal starts and continues.
 - Signal paths that extend beyond the logic diagram and continue in another diagram have the suffix ”-cont.”
- Dimensions are provided both in inches and mm. If it is not specifically mentioned then the dimension is in mm.

1.4.3

IEC61850 edition 1 / edition 2 mapping

Table 1: IEC61850 edition 1 / edition 2 mapping

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
AEGPVOC	AEGGAPC	AEGPVOC
AGSAL	SECLLN0 AGSAL	AGSAL
ALMCALH		ALMCALH
ALTIM		ALTIM
ALTMS		ALTMS
ALTRK		ALTRK
BCZSPDIF	BCZSPDIF	BCZSPDIF
BCZTPDIF	BCZTPDIF	BCZTPDIF
BDCGAPC	SWSGGIO	BDCGAPC
BRCPTOC	BRCPTOC	BRCPTOC
BTIGAPC	B16IFCVI	BTIGAPC
BUSPTRC_B1	BBSPLL0 BUSPTRC	LLN0 BUSPTRC
BUSPTRC_B2	BUSPTRC	BUSPTRC
BUSPTRC_B3	BUSPTRC	BUSPTRC
BUSPTRC_B4	BUSPTRC	BUSPTRC
BUSPTRC_B5	BUSPTRC	BUSPTRC
BUSPTRC_B6	BUSPTRC	BUSPTRC
BUSPTRC_B7	BUSPTRC	BUSPTRC
BUSPTRC_B8	BUSPTRC	BUSPTRC
BUSPTRC_B9	BUSPTRC	BUSPTRC
BUSPTRC_B10	BUSPTRC	BUSPTRC
BUSPTRC_B11	BUSPTRC	BUSPTRC
BUSPTRC_B12	BUSPTRC	BUSPTRC

Table continues on next page

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
BUSPTRC_B13	BUSPTRC	BUSPTRC
BUSPTRC_B14	BUSPTRC	BUSPTRC
BUSPTRC_B15	BUSPTRC	BUSPTRC
BUSPTRC_B16	BUSPTRC	BUSPTRC
BUSPTRC_B17	BUSPTRC	BUSPTRC
BUSPTRC_B18	BUSPTRC	BUSPTRC
BUSPTRC_B19	BUSPTRC	BUSPTRC
BUSPTRC_B20	BUSPTRC	BUSPTRC
BUSPTRC_B21	BUSPTRC	BUSPTRC
BUSPTRC_B22	BUSPTRC	BUSPTRC
BUSPTRC_B23	BUSPTRC	BUSPTRC
BUSPTRC_B24	BUSPTRC	BUSPTRC
BUTPTRC_B1	BBTPLL0 BUTPTRC	LLN0 BUTPTRC
BUTPTRC_B2	BUTPTRC	BUTPTRC
BUTPTRC_B3	BUTPTRC	BUTPTRC
BUTPTRC_B4	BUTPTRC	BUTPTRC
BUTPTRC_B5	BUTPTRC	BUTPTRC
BUTPTRC_B6	BUTPTRC	BUTPTRC
BUTPTRC_B7	BUTPTRC	BUTPTRC
BUTPTRC_B8	BUTPTRC	BUTPTRC
BZNSPDIF_A	BZNSPDIF	BZNSGAPC BZNSPDIF
BZNSPDIF_B	BZNSPDIF	BZNSGAPC BZNSPDIF
BZNTPDIF_A	BZNTPDIF	BZNTGAPC BZNTPDIF
BZNTPDIF_B	BZNTPDIF	BZNTGAPC BZNTPDIF
CBPGAPC	CBPLL0 CBPMMXU CBPPTRC HOLPTOV HPH1PTOV PH3PTOC PH3PTUC RP3PDOP	LLN0 CBPPTRC HOLPTOV HPH1PTOV PH3PTOC PH3PTUC RP3PDOP
CCPDSC	CCRPLD	CCPDSC
CCRBRF	CCRBRF	CCRBRF
CCSRBRF	CCSRBRF	CCSRBRF
CCSSPVC	CCSRDIF	CCSSPVC
Table continues on next page		

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
CMMXU	CMMXU	CMMXU
CMSQI	CMSQI	CMSQI
COUVGAPC	COUVLLN0 COUVPTOV COUVPTUV	LLN0 COUVPTOV COUVPTUV
CVGAPC	GF2LLN0 GF2MMXN GF2PHAR GF2PTOV GF2PTUC GF2PTUV GF2PVOC PH1PTRC	LLN0 GF2MMXN GF2PHAR GF2PTOV GF2PTUC GF2PTUV GF2PVOC PH1PTRC
CVMMXN	CVMMXN	CVMMXN
DPGAPC	DPGGIO	DPGAPC
DRPRDRE	DRPRDRE	DRPRDRE
ECPSCH	ECPSCH	ECPSCH
ECRWPSCH	ECRWPSCH	ECRWPSCH
EF4PTOC	EF4LLN0 EF4PTRC EF4RDIR GEN4PHAR PH1PTOC	LLN0 EF4PTRC EF4RDIR GEN4PHAR PH1PTOC
EFPIOC	EFPIOC	EFPIOC
ETPMTR	ETPMTR	ETPMTR
FDPSPDIS	FDPSPDIS	FDPSPDIS
FMPSPDIS	FMPSPDIS	FMPSPDIS
FRPSPDIS	FPSRPDIS	FPSRPDIS
FTAQFVR	FTAQFVR	FTAQFVR
FUFSPVC	SDDRFUF	FUFSPVC
GENPDIF	GENPDIF	LLN0 GENGAPC GENPDIF GENPHAR GENPTRC
GOPPDOP	GOPPDOP	LLN0 GOPPDOP PH1PTRC
GRPTTR	GRPTTR	LLN0 GRPTTR GRPTUC
GSPTTR	GSPTTR	GSPTTR
GUPPDUP	GUPPDUP	LLN0 GUPPDUP PH1PTRC
Table continues on next page		

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
HZPDIF	HZPDIF	HZPDIF
INDCALCH		INDCALH
ITBGAPC	IB16FCVB	ITBGAPC
L3CPDIF	L3CPDIF	LLN0 L3CGAPC L3CPDIF L3CPHAR L3CPTRC
L4UFCNT	L4UFCNT	L4UFCNT
L6CPDIF	L6CPDIF	LLN0 L6CGAPC L6CPDIF L6CPHAR L6CPTRC
LAPPGAPC	LAPLLN0 LAPPPDUP LAPPPUPF	LLN0 LAPPPDUP LAPPPUPF
LCCRPTRC	LCCRPTRC	LCCRPTRC
LCNSPTOC	LCNSPTOC	LCNSPTOC
LCNSPTOV	LCNSPTOV	LCNSPTOV
LCP3PTOC	LCP3PTOC	LCP3PTOC
LCP3PTUC	LCP3PTUC	LCP3PTUC
LCPTTR	LCPTTR	LCPTTR
LCZSPTOC	LCZSPTOC	LCZSPTOC
LCZSPTOV	LCZSPTOV	LCZSPTOV
LD0LLN0	LLN0	LLN0
LDLPSC	LDLPDIF	LDLPSC
LDRGFC	STSGGIO	LDRGFC
LEXPDIS	LEXPDIS	LLN0 LEXPDIS LEXPTRC
LFPTTR	LFPTTR	LFPTTR
LMBRFLO	LMBRFLO	LMBRFLO
LOVPTUV	LOVPTUV	LOVPTUV
LPHD	LPHD	LPHD
LT3CPDIF	LT3CPDIF	LLN0 LT3CGAPC LT3CPDIF LT3CPHAR LT3CPTRC
Table continues on next page		

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
LT6CPDIF	LT6CPDIF	LLN0 LT6CGAPC LT6CPDIF LT6CPHAR LT6CPTRC
MVGAPC	MVGGIO	MVGAPC
NS2PTOC	NS2LLN0 NS2PTOC NS2PTRC	LLN0 NS2PTOC NS2PTRC
NS4PTOC	EF4LLN0 EF4PTRC EF4RDIR GEN4PHAR PH1PTOC	LLN0 EF4PTRC EF4RDIR PH1PTOC
OC4PTOC	OC4LLN0 GEN4PHAR PH3PTOC PH3PTRC	LLN0 GEN4PHAR PH3PTOC PH3PTRC
OEXPVPH	OEXPVPH	OEXPVPH
OOSPPAM	OOSPPAM	LLN0 OOSPPAM OOSPTRC
OV2PTOV	GEN2LLN0 OV2PTOV PH1PTRC	LLN0 OV2PTOV PH1PTRC
PAPGAPC	PAPGAPC	PAPGAPC
PCFCNT	PCGGIO	PCFCNT
PH4SPTOC	OCNDLLN0 GEN4PHAR PH1BPTOC PH1PTRC	LLN0 GEN4PHAR PH1BPTOC PH1PTRC
PHPIOC	PHPIOC	PHPIOC
PRPSTATUS	RCHLCCH	RCHLCCH SCHLCCH
PSLPSC	ZMRPSL	PSLPSC
PSPPPAM	PSPPPAM	LLN0 PSPPPAM PSPPTRC
QCBAY	QCBAY	LLN0
QCRSV	QCRSV	QCRSV
REFPDIF	REFPDIF	REFPDIF
ROTIPHIZ	ROTIPHIZ	LLN0 ROTIPHIZ ROTIPTRC
ROV2PTOV	GEN2LLN0 PH1PTRC ROV2PTOV	LLN0 PH1PTRC ROV2PTOV
Table continues on next page		

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
SAPFRC	SAPFRC	SAPFRC
SAPTOF	SAPTOF	SAPTOF
SAPTUF	SAPTUF	SAPTUF
SCCVPTOC	SCCVPTOC	SCCVPTOC
SCILO	SCILO	SCILO
SCSWI	SCSWI	SCSWI
SDEPSDE	SDEPSDE	LLN0 SDEPSDE SDEPTOC SDEPTOV SDEPTRC
SESRSYN	RSY1LLN0 AUT1RSYN MAN1RSYN SYNRSYN	LLN0 AUT1RSYN MAN1RSYN SYNRSYN
SINGLELCCH		SCHLCCH
SLGAPC	SLGGIO	SLGAPC
SMBRREC	SMBRREC	SMBRREC
SMPPTRC	SMPPTRC	SMPPTRC
SP16GAPC	SP16GGIO	SP16GAPC
SPC8GAPC	SPC8GGIO	SPC8GAPC
SPGAPC	SPGGIO	SPGAPC
SSCBR	SSCBR	SSCBR
SSIMG	SSIMG	SSIMG
SSIML	SSIML	SSIML
STBPTOC	STBPTOC	STBPTOC
STEFPHIZ	STEFPHIZ	STEFPHIZ
STTIPHIZ	STTIPHIZ	STTIPHIZ
SXCBR	SXCBR	SXCBR
SXSWI	SXSWI	SXSWI
T2WPDIF	T2WPDIF	LLN0 T2WGAPC T2WPDIF T2WPHAR T2WPTRC
T3WPDIF	T3WPDIF	LLN0 T3WGAPC T3WPDIF T3WPHAR T3WPTRC
TCLYLTC	TCLYLTC	TCLYLTC
TCMYLTC	TCMYLTC	TCMYLTC
Table continues on next page		

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
TEIGAPC	TEIGGIO	TEIGAPC
TMAGAPC	TMAGGIO	TMAGAPC
TR1ATCC	TR1ATCC	TR1ATCC
TR8ATCC	TR8ATCC	TR8ATCC
TRPTTR	TRPTTR	TRPTTR
UV2PTUV	GEN2LLN0 PH1PTRC UV2PTUV	LLN0 PH1PTRC UV2PTUV
VDCPTOV	VDCPTOV	VDCPTOV
VDSPVC	VDRFUF	VDSPVC
VMMXU	VMMXU	VMMXU
VMSQI	VMSQI	VMSQI
VNMMXU	VNMMXU	VNMMXU
VRPVOC	VRLLN0 PH1PTRC PH1PTUV VRPVOC	LLN0 PH1PTRC PH1PTUV VRPVOC
VSGAPC	VSGGIO	VSGAPC
WRNCALH		WRNCALH
ZC1PPSCH	ZPCPSCH	ZPCPSCH
ZC1WPSCH	ZPCWPSCH	ZPCWPSCH
ZCLCPSCH	ZCLCPLAL	LLN0 ZCLCPSCH
ZCPSCH	ZCPSCH	ZCPSCH
ZCRWPSCH	ZCRWPSCH	ZCRWPSCH
ZCVPSOF	ZCVPSOF	ZCVPSOF
ZGVPDIS	ZGVLLN0 PH1PTRC ZGVPDIS ZGVPTUV	LLN0 PH1PTRC ZGVPDIS ZGVPTUV
ZMCAPDIS	ZMCAPDIS	ZMCAPDIS
ZMCPDIS	ZMCPDIS	ZMCPDIS
ZMFCPDIS	ZMFLLN0 PSFPDIS ZMFPDIS	LLN0 PSFPDIS ZMFPDIS
ZMFPDIS	ZMFLLN0 PSFPDIS ZMFPDIS	LLN0 PSFPDIS ZMFPDIS
ZMHPDIS	ZMHPDIS	ZMHPDIS
ZMMAPDIS	ZMMAPDIS	ZMMAPDIS
ZMMPDIS	ZMMPDIS	ZMMPDIS
Table continues on next page		

Function block name	Edition 1 logical nodes	Edition 2 logical nodes
ZMQAPDIS	ZMQAPDIS	ZMQAPDIS
ZMQPDIS	ZMQPDIS	ZMQPDIS
ZMRAPDIS	ZMRAPDIS	ZMRAPDIS
ZMRPDIS	ZMRPDIS	ZMRPDIS
ZMRPSB	ZMRPSB	ZMRPSB
ZSMGAPC	ZSMGAPC	ZSMGAPC

Section 2 Safety information

2.1 Symbols on the product



All warnings must be observed.



Read the entire manual before doing installation or any maintenance work on the product. All warnings must be observed.



Do not touch the unit in operation. The installation shall take into account the worst case temperature.

2.2 Warnings

Observe the warnings during all types of work related to the product.



Only electrically skilled persons with the proper authorization and knowledge of any safety hazards are allowed to carry out the electrical installation.



National and local electrical safety regulations must always be followed. Working in a high voltage environment requires serious approach to avoid human injuries and damage to equipment.



Do not touch circuitry during operation. Potentially lethal voltages and currents are present.



Always use suitable isolated test pins when measuring signals in open circuitry. Potentially lethal voltages and currents are present.



Never connect or disconnect a wire and/or a connector to or from a IED during normal operation. Hazardous voltages and currents are present that may be lethal. Operation may be disrupted and IED and measuring circuitry may be damaged.



Dangerous voltages can occur on the connectors, even though the auxiliary voltage has been disconnected.



Always connect the IED to protective ground, regardless of the operating conditions. This also applies to special occasions such as bench testing, demonstrations and off-site configuration. This is class 1 equipment that shall be grounded.



Never disconnect the secondary connection of current transformer circuit without short-circuiting the transformer's secondary winding. Operating a current transformer with the secondary winding open will cause a massive potential build-up that may damage the transformer and may cause injuries to humans.



Never remove any screw from a powered IED or from a IED connected to powered circuitry. Potentially lethal voltages and currents are present.



Take adequate measures to protect the eyes. Never look into the laser beam.



The IED with accessories should be mounted in a cubicle in a restricted access area within a power station, substation or industrial or retail environment.



Whenever changes are made in the IED, measures should be taken to avoid inadvertent tripping.



The IED contains components which are sensitive to electrostatic discharge. ESD precautions shall always be observed prior to touching components.



Always transport PCBs (modules) using certified conductive bags.



Do not connect live wires to the IED. Internal circuitry may be damaged



Always use a conductive wrist strap connected to protective ground when replacing modules. Electrostatic discharge (ESD) may damage the module and IED circuitry.



Take care to avoid electrical shock during installation and commissioning.



Changing the active setting group will inevitably change the IEDs operation. Be careful and check regulations before making the change.

2.3

Note signs



Observe the maximum allowed continuous current for the different current transformer inputs of the IED. See technical data.

Section 3 Available functions

3.1 Main protection functions

2	= number of basic instances
0-3	= option quantities
3- A03	= optional function included in packages A03 (refer to ordering details)

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
Differential protection				
BUTPTRC, BCZTPDIF, BZNTPDIF, BZITGGIO, BUTSM4	87B	Busbar differential protection, 2 zones, three phase/4 bays		
BUTPTRC, BCZTPDIF, BZNTPDIF, BZITGGIO, BUTSM8	87B	Busbar differential protection, 2 zones, three phase/8 bays	1	1
BUSPTRC, BCZSPDIF, BZNSPDIF, BZISGGIO, BUSSM12	87B	Busbar differential protection, 2 zones, single phase/12 bays		
BUSPTRC, BCZSPDIF, BZNSPDIF, BZISGGIO, BUSSM24	87B	Busbar differential protection, 2 zones, single phase/24 bays	1	
BDCGAPC		Status of primary switching object for busbar protection zone selection	96	40

3.2 Back-up protection functions

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
Current protection				
OC4PTOC	51_67 ¹⁾	Four step phase overcurrent protection	0-8	8-C07
PH4SPTOC	51	Four step single phase overcurrent protection	0-24	
EF4PTOC	51N 67N ²⁾	Four step residual overcurrent protection	0-8	
NS4PTOC	46I2	Four step directional negative phase sequence overcurrent protection	0-8	
TRPTTR	49	Thermal overload protection, two time constant	0-2	
CCRBFR	50BF	Breaker failure protection	0-8	8-C11
CCSRBRF	50BF	Breaker failure protection, single phase version	0-24	
GUPPDUP	37	Directional underpower protection	0-4	
GOPPDOP	32	Directional overpower protection	0-4	
CBPGAPC		Capacitor bank protection	0-2	
Voltage protection				
UV2PTUV	27	Two step undervoltage protection	0-2	
OV2PTOV	59	Two step overvoltage protection	0-2	
ROV2PTOV	59N	Two step residual overvoltage protection	0-2	
VDCPTOV	60	Voltage differential protection	0-2	
LOVPTUV	27	Loss of voltage check	0-2	
Frequency protection				
SAPTUF	81	Underfrequency protection	0-6	
SAPTOF	81	Overfrequency protection	0-6	
SAPFRC	81	Rate-of-change frequency protection	0-6	
Multipurpose protection				
CVGAPC		General current and voltage protection	0-6	

- 1) 67 requires voltage
2) 67N requires voltage

3.3 Control and monitoring functions

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
Control				
SESRYSN	25	Synchrocheck, energizing check and synchronizing	0-3	
SMBRREC	79	Autorecloser	0-2	2-H05
APC30	3	Apparatus control for up to 6 bays, max 30 apparatuses (6CBs) incl. interlocking	0-1	
QCBAY		Apparatus control	1+5/APC30	1
LOCREM		Handling of LRswitch positions	1+5/APC30	1
LOCREMCTRL		LHMI control of PSTO	1+5/APC30	1
SLGAPC		Logic rotating switch for function selection and LHMI presentation	15	15
VSGAPC		Selector mini switch	20	20
DPGAPC		Generic communication function for Double Point indication	16	16
SPC8GAPC		Single point generic control 8 signals	5	5
AUTOBITS		AutomationBits, command function for DNP3.0	3	3
SINGLECMD		Single command, 16 signals	4	4
I103CMD		Function commands for IEC 60870-5-103	1	1
I103GENCMD		Function commands generic for IEC 60870-5-103	50	50
I103POSCMD		IED commands with position and select for IEC 60870-5-103	50	50
I103IEDCMD		IED commands for IEC 60870-5-103	1	1
I103USRCMD		Function commands user defined for IEC 60870-5-103	1	1
Secondary system supervision				
FUFSPVC		Fuse failure supervision	0-2	
VDSPVC	60	Fuse failure supervision based on voltage difference	0-2	
Logic				
TMAGAPC		Trip matrix logic	12	
ALMCALH		Logic for group alarm	5	
WRNCALH		Logic for group warning	5	
INDCALH		Logic for group indication	5	

Table continues on next page

Section 3 Available functions

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
AND, OR, INV, PULSETIMER, GATE, TIMERSET, XOR, LLD, SRMEMORY, RSMEMORY		Configurable logic blocks	40-420	40-280
ANDQT, ORQT, INVERTERQT, XORQT, SRMEMORYQT, RSMEMORYQT, TIMERSETQT, PULSETIMERQT, INVALIDQT, INDCOMBSPQT, INDEXTSPQT		Configurable logic blocks Q/T	0-1	
SLGAPC, VSGAPC, AND, OR, PULSETIMER, GATE, TIMERSET, XOR, LLD, SRMEMORY, INV		Extension logic package	0-1	
FXDSIGN		Fixed signal function block	1	1
B16I		Boolean 16 to Integer conversion	18	18
BTIGAPC		Boolean 16 to Integer conversion with Logic Node representation	16	16
IB16		Integer to Boolean 16 conversion	18	18
ITBGAPC		Integer to Boolean 16 conversion with Logic Node representation	16	16
TEIGAPC		Elapsed time integrator with limit transgression and overflow supervision	12	12
Monitoring				
CVMMXN, CMMXU, VMMXU, CMSQI, VMSQI, VNMMXU		Measurements	6	6

Table continues on next page

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
AISVBAS		Function block for service value presentation of secondary analog inputs	1	1
EVENT		Event function	20	20
DRPRDRE, A1RADR, A2RADR, A3RADR, A4RADR, B1RBDR, B2RBDR, B3RBDR, B4RBDR, B5RBDR, B6RBDR		Disturbance report	1	1
SPGAPC		Generic communication function for Single Point indication	64	64
SP16GAPC		Generic communication function for Single Point indication 16 inputs	16	16
MVGAPC		Generic communication function for Measured Value	24	24
BINSTATREP		Logical signal status report	3	3
RANGE_XP		Measured value expander block	28	28
SSIMG	63	Gas medium supervision	21	21
SSIML	71	Liquid medium supervision	3	3
SSCBR		Circuit breaker monitoring	0-8	24- M14
I103MEAS		Measurands for IEC 60870-5-103	1	1
I103MEASUSR		Measurands user defined signals for IEC 60870-5-103	3	3
I103AR		Function status auto-recloser for IEC 60870-5-103	1	1
I103EF		Function status earth-fault for IEC 60870-5-103	1	1
I103FLTPROT		Function status fault protection for IEC 60870-5-103	1	1
I103IED		IED status for IEC 60870-5-103	1	1
I103SUPERV		Supervision status for IEC 60870-5-103	1	1
I103USRDEF		Status for user defiend signals for IEC 60870-5-103	20	20
L4UFCNT		Event counter with limit supervision	30	30
Metering				
PCFCNT		Pulse-counter logic	16	
ETPMTR		Function for energy calculation and demand handling	6	

3.4 Communication

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
Station communication				
LONSPA, SPA		SPA communication protocol	1	1
ADE		LON communication protocol	1	1
HORZCOMM		Network variables via LON	1	1
PROTOCOL		Operation selection between SPA and IEC 60870-5-103 for SLM	1	1
RS485PROT		Operation selection for RS485	1	1
RS485GEN		RS485	1	1
DNPGEN		DNP3.0 communication general protocol	1	1
DNPGENTCP		DNP3.0 communication general TCP protocol	1	1
CHSERRS485		DNP3.0 for EIA-485 communication protocol	1	1
CH1TCP, CH2TCP, CH3TCP, CH4TCP		DNP3.0 for TCP/IP communication protocol	1	1
CHSEROPT		DNP3.0 for TCP/IP and EIA-485 communication protocol	1	1
MST1TCP, MST2TCP, MST3TCP, MST4TCP		DNP3.0 for serial communication protocol	1	1
DNPFREC		DNP3.0 fault records for TCP/IP and EIA-485 communication protocol	1	1
IEC61850-8-1		Parameter setting function for IEC 61850	1	1
GOOSEINTLK RCV		Horizontal communication via GOOSE for interlocking	59	59
GOOSEBINR CV		Goose binary receive	16	16
GOOSEDPRC V		GOOSE function block to receive a double point value	64	64
GOOSEINTR CV		GOOSE function block to receive an integer value	32	32
GOOSEMVR CV		GOOSE function block to receive a measurand value	60	60

Table continues on next page

IEC 61850	ANSI	Function description	Busbar	Busbar
			REB670	REB670 (A31A)
GOOSEPRCV		GOOSE function block to receive a single point value	64	64
MULTICMDRCV, MULTICMDSND		Multiple command and transmit	60/10	60/10
FRONT, LANABI, LANAB, LANCDI, LANCD		Ethernet configuration of links	1	1
GATEWAY		Ethernet configuration of link one	1	1
OPTICAL103		IEC 60870-5-103 Optical serial communication	1	1
RS485103		IEC 60870-5-103 serial communication for RS485	1	1
AGSAL		Generic security application component	1	1
LD0LLN0		IEC 61850 LD0 LLN0	1	1
SYSSLN0		IEC 61850 SYS LLN0	1	1
LPHD		Physical device information	1	1
PCMACCS		IED Configuration Protocol	1	1
SECALARM		Component for mapping security events on protocols such as DNP3 and IEC103	1	1
FSTACCS		Field service tool access via SPA protocol over ethernet communication	1	1
ACTIVLOG		Activity logging parameters	1	1
ALTRK		Service Tracking	1	1
SINGLELCCH		Single ethernet port link status	1	1
PRPSTATUS		Dual ethernet port link status	1	1
PRP		IEC 62439-3 parallel redundancy protocol	0-1	1-P03
Remote communication				
		Binary signal transfer receive/transmit	6/36	6/36
		Transmission of analog data from LDCM	1	1
		Receive binary status from remote LDCM	6/3/3	6/3/3

3.5 Basic IED functions

Table 2: *Basic IED functions*

IEC 61850 or function name	Description
INTERRSIG	Self supervision with internal event list
SELSUPEVLST	Self supervision with internal event list
TIMESYNCHGEN	Time synchronization module
SYNCHBIN, SYNCHCAN, SYNCHCMPPS, SYNCHLON, SYNCHPPH, SYNCHPPS, SYNCHSNTP, SYNCHSPA, SYNCHCMPPS	Time synchronization
TIMEZONE	Time synchronization
DSTBEGIN, DSTENABLE, DSTEND	GPS time synchronization module
IRIG-B	Time synchronization
SETGRPS	Number of setting groups
ACTVGRP	Parameter setting groups
TESTMODE	Test mode functionality
CHNGLCK	Change lock function
SMBI	Signal matrix for binary inputs
SMBO	Signal matrix for binary outputs
SMMI	Signal matrix for mA inputs
SMAI1 - SMAI20	Signal matrix for analog inputs
3PHSUM	Summation block 3 phase
ATHSTAT	Authority status
ATHCHCK	Authority check
AUTHMAN	Authority management
FTPACCS	FTP access with password
SPACOMMMAP	SPA communication mapping
SPATD	Date and time via SPA protocol
DOSFRNT	Denial of service, frame rate control for front port
DOSLANAB	Denial of service, frame rate control for OEM port AB
DOSLANCD	Denial of service, frame rate control for OEM port CD
DOSSCKT	Denial of service, socket flow control

Table continues on next page

IEC 61850 or function name	Description
GBASVAL	Global base values for settings
PRIMVAL	Primary system values
ALTMS	Time master supervision
ALTIM	Time management
ALTRK	Service tracking
ACTIVLOG	Activity logging parameters
FSTACCS	Field service tool access via SPA protocol over ethernet communication
PCMACCS	IED Configuration Protocol
SECALARM	Component for mapping security events on protocols such as DNP3 and IEC103
DNPGEN	DNP3.0 communication general protocol
DNPGENTCP	DNP3.0 communication general TCP protocol
CHSEROPT	DNP3.0 for TCP/IP and EIA-485 communication protocol
MSTSER	DNP3.0 for serial communication protocol
OPTICAL103	IEC 60870-5-103 Optical serial communication
RS485103	IEC 60870-5-103 serial communication for RS485
IEC61850-8-1	Parameter setting function for IEC 61850
HORZCOMM	Network variables via LON
LONSPA	SPA communication protocol
LEDGEN	General LED indication part for LHMI

Section 4 Starting up

4.1 Factory and site acceptance testing

Testing the proper IED operation is carried out at different occasions, for example:

- Acceptance testing
- Commissioning testing
- Maintenance testing

This manual describes the workflow and the steps to carry out the commissioning testing.

Factory acceptance testing (FAT) is typically done to verify that the IED and its corresponding configuration meet the requirements of the utility or industry. This test is the most complex and in depth, as it is done to familiarize the user with a new product or to verify a new configuration. The complexity of this testing depends on several factors, such as:

- New IED type
- New configuration
- Modified configuration

Site acceptance testing (SAT or commissioning testing) is typically done to verify that the installed IED is correctly set and connected to the power system. SAT requires that the acceptance testing has been performed and that the application configuration is verified.

Maintenance testing is a periodic verification that the IED is healthy and has correct settings, depending on changes in the power system. There are also other types of maintenance testing.

4.2 Commissioning checklist

Before starting up commissioning at site, check that the following items are available.

- Single line diagram
- Protection block diagram
- Circuit diagram
- Setting list and configuration

- RJ-45 Ethernet cable (CAT 5)
- Three-phase test kit or other test equipment depending on the complexity of the configuration and functions to be tested.
- PC with PCM600 installed along with the connectivity packages corresponding to the IEDs to be tested.
- Administration rights on the PC, to set up IP addresses
- Product documentation (engineering manual, installation manual, commissioning manual, operation manual, technical manual and communication protocol manual)

4.3 Checking the power supply

Check that the auxiliary supply voltage remains within the permissible input voltage range under all operating conditions. Check that the polarity is correct before energizing the IED.

4.4 Energizing the IED

4.4.1 Checking the IED operation

Check all connections to external circuitry to ensure correct installation, before energizing the IED and carrying out the commissioning procedures.

The user could also check the software version, the IED's serial number and the installed modules and their ordering number to ensure that the IED is according to delivery and ordering specifications.

Energize the power supply of the IED to pickup. This could be done in a number of ways, from energizing a whole cubicle to energizing a single IED. The user should re-configure the IED to activate the hardware modules in order to enable the self supervision function to detect possible hardware errors. Set the IED time if no time synchronization source is configured. Check also the self-supervision function in **Main menu/Diagnostics/Monitoring** menu in local HMI to verify that the IED operates properly.

4.4.2 IED start-up sequence

When the IED is energized, the green LED starts flashing instantly. After approximately 55 seconds the window lights up and the window displays 'IED Startup'. The main menu is displayed and the upper row should indicate 'Available' after about 90 seconds. A steady green light indicates a successful startup.

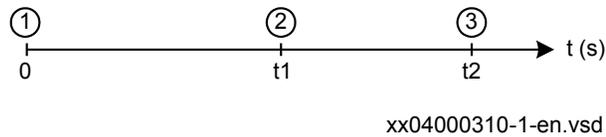


Figure 2: Typical IED start-up sequence

- 1 IED energized. Green LED instantly starts flashing
- 2 LCD lights up and "IED startup" is displayed
- 3 The main menu is displayed. A steady green light indicates a successful startup.

If the upper row in the window indicates 'Fail' instead of 'Available' and the green LED flashes, an internal failure in the IED has been detected. See section "[Checking the self supervision function](#)" to investigate the fault.

4.5 Setting up communication between PCM600 and the IED

The communication between the IED and PCM600 is independent of the communication protocol used within the substation or to the NCC.

The communication media is always Ethernet and the used protocol is TCP/IP.

Each IED has an RJ-45 Ethernet interface connector on the front. The front Ethernet connector shall be used for communication with PCM600.

When an Ethernet-based station protocol is used, PCM600 communication can use the same Ethernet port and IP address.

To connect PCM600 to the IED, two basic variants must be considered.

- Direct point-to-point link between PCM600 and the IED front port. The front port can be seen as a service port.
- Indirect link via a station LAN or from remote via a network.

The physical connection and the IP address must be configured in both cases to enable communication.

The communication procedures are the same in both cases.

1. If needed, set the IP address for the IEDs.
2. Set up the PC or workstation for a direct link (point-to-point), or
3. Connect the PC or workstation to the LAN/WAN network.
4. Configure the IED IP addresses in the PCM600 project for each IED to match the IP addresses of the physical IEDs.

Setting up IP addresses

The IP address and the corresponding mask must be set via the LHMI for each available Ethernet interface in the IED. Each Ethernet interface has a default factory IP address when the IED is delivered. This is not given when an additional Ethernet interface is installed or an interface is replaced.

- The default IP address for the IED front port is 10.1.150.3 and the corresponding subnetwork mask is 255.255.255.0, which can be set via the local HMI path **Main menu/Configuration/Communication/Ethernet configuration/FRONT:1**.

Setting up the PC or workstation for point-to-point access to IEDs front port

A special cable is needed to connect two physical Ethernet interfaces together without a hub, router, bridge or switch in between. The Tx and Rx signal wires must be crossed in the cable to connect Tx with Rx on the other side and vice versa. These cables are known as cross over cables. The maximum length is 2 m. The connector type is RJ-45.

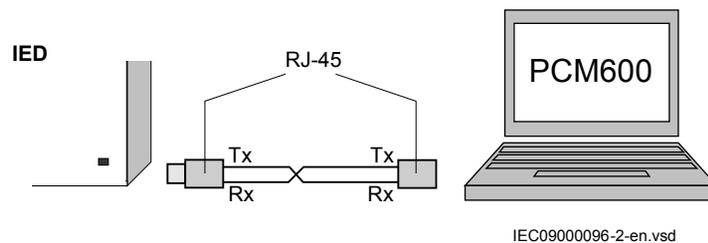


Figure 3: Point-to-point link between IED and PCM600 using a null-modem cable

The following description is an example valid for standard PCs using Microsoft Windows operating system. The example is taken from a Laptop with one Ethernet interface.



Administrator rights are required to change the PC communication setup. Some PCs have the feature to automatically detect that Tx signals from the IED are received on the Tx pin on the PC. Thus, a straight (standard) Ethernet cable can be used.

1. Select **Search programs and files** in the **Start menu** in Windows.

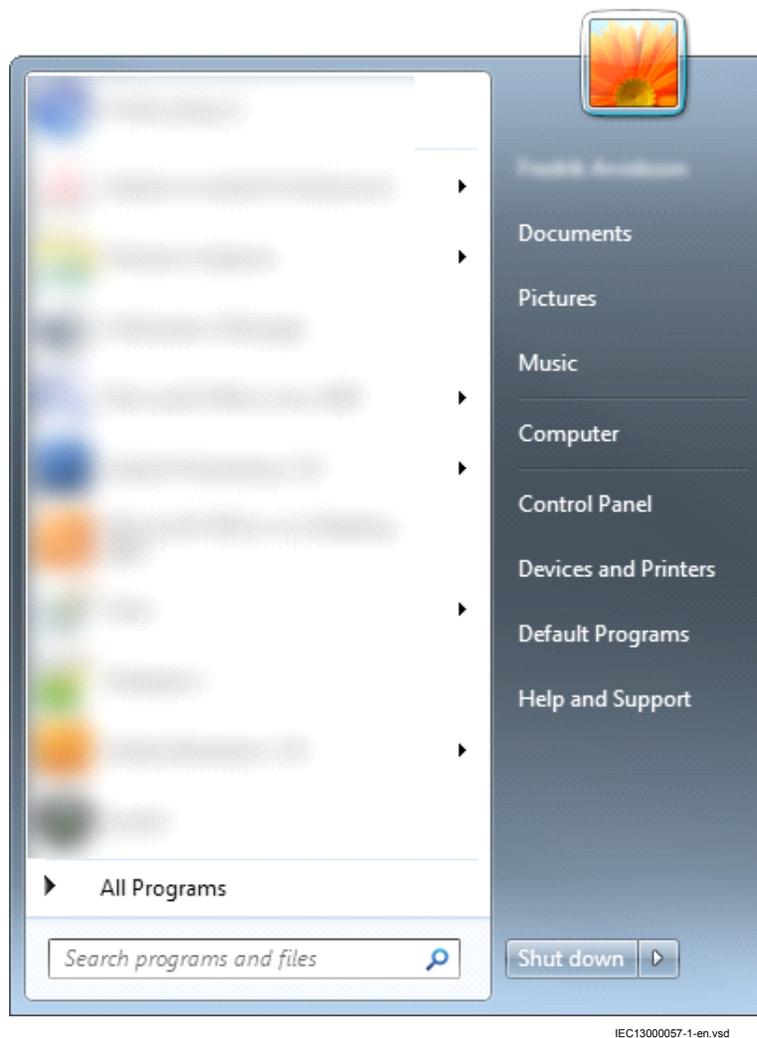
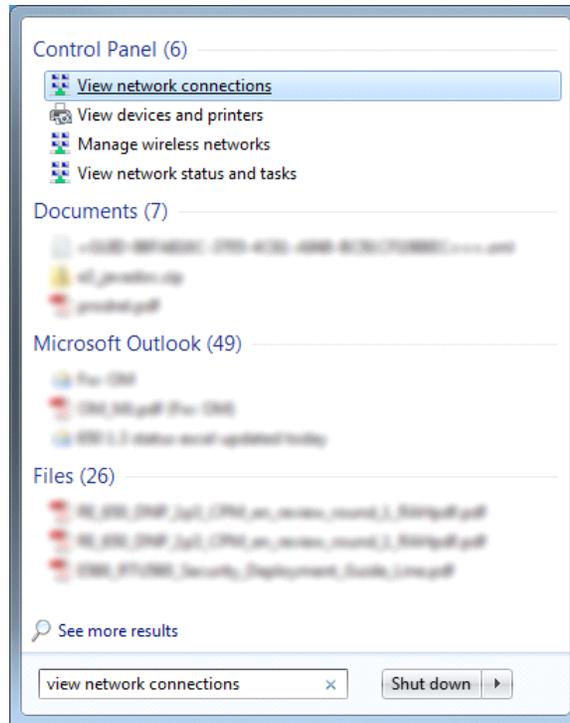


Figure 4: Select: Search programs and files

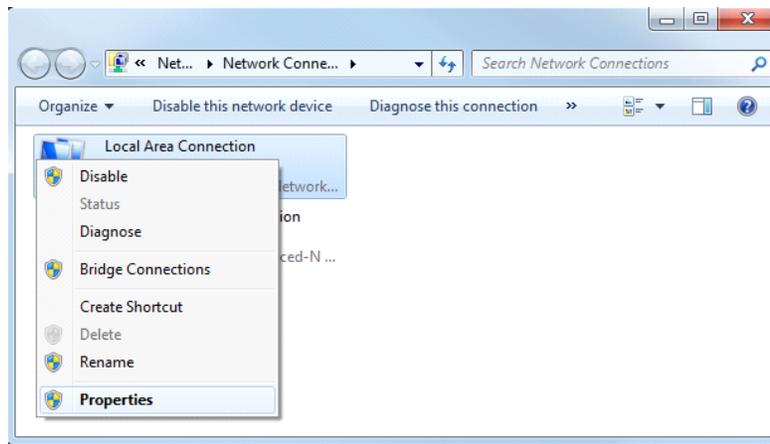
2. Type **View network connections** and click on the **View network connections** icon.



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Figure 5: Click View network connections

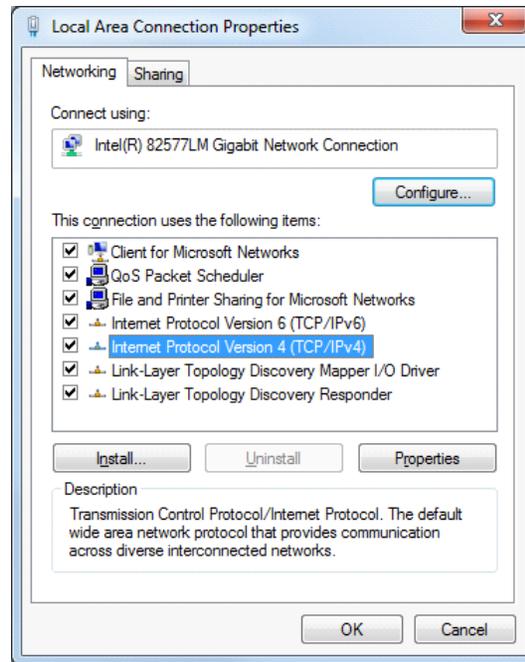
3. Right-click and select **Properties**.



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Figure 6: Right-click Local Area Connection and select Properties

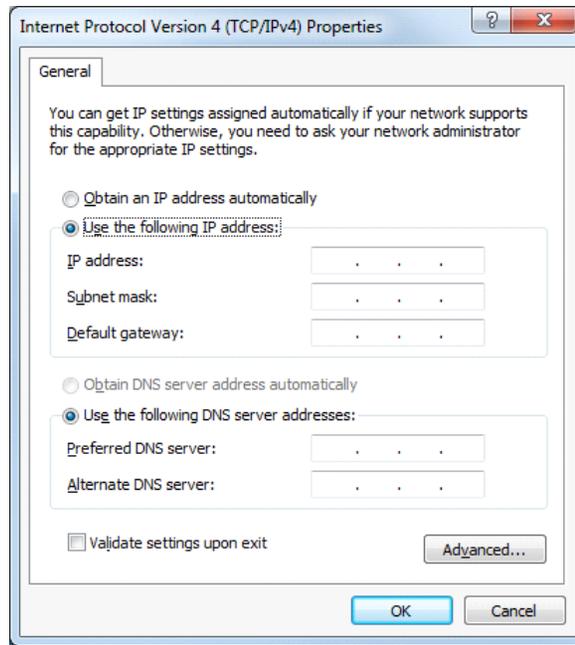
4. Select the TCP/IPv4 protocol from the list of configured components using this connection and click **Properties**.



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Figure 7: Select the TCP/IPV4 protocol and open Properties

5. Select **Use the following IP address** and define *IP address* and *Subnet mask* if the front port is used and if the *IP address* is not set to be obtained automatically by the IED, see [Figure 8](#). The IP address must be different from the IP address chosen for the IED.



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Figure 8: Select: Use the following IP address

6. Use the *ping* command to verify connectivity with the IED.
7. Close all open windows and start PCM600.

Setting up the PC to access the IED via a network

This task depends on the used LAN/WAN network.



The PC and IED must belong to the same subnetwork for this set-up to work.

4.6

Writing an application configuration to the IED

When writing a configuration to the IED with the application configuration tool, the IED is automatically set in configuration mode. When the IED is set in configuration mode, all functions are blocked. The red LED on the IED flashes, and the green LED is lit while the IED is in the configuration mode.

When the configuration is written and completed, the IED is automatically set into normal mode. For further instructions please refer to the users manuals for PCM600.

4.7 Checking CT circuits



Check that the wiring is in strict accordance with the supplied connection diagram.

The CTs must be connected in accordance with the circuit diagram provided with the IED, both with regards to phases and polarity. The following tests shall be performed on every primary CT connected to the IED:

- Primary injection test to verify the current ratio of the CT, the correct wiring up to the protection IED and correct phase sequence connection (that is A, B, C.)
- Polarity check to prove that the predicted direction of secondary current flow is correct for a given direction of primary current flow. This is an essential test for the proper operation of the differential function and directional protection functions.
- CT secondary loop resistance measurement to confirm that the current transformer secondary loop DC resistance is within the specification for the connected protection functions. When the measured loop resistance is near the calculated value for maximum DC resistance, perform a complete burden test.
- CT excitation test in order to confirm that the current transformer is of the correct accuracy rating and that there are no shorted turns in the current transformer windings. Manufacturer's design curves must be available for the current transformer to compare the actual results.
- Grounding check of the individual CT secondary circuits to verify that each three-phase set of main CTs is properly connected to the station ground and only at one electrical point.
- Insulation resistance check.



While the CT primary is energized, the secondary circuit shall never be open circuited because extremely dangerous high voltages may arise.



Both the primary and the secondary sides must be disconnected from the line and the IED when plotting the excitation characteristics.



If the CT secondary circuit ground connection is removed without the current transformer primary being de-energized, dangerous voltages may result in the secondary CT circuits.

4.8 Checking VT circuits

Check that the wiring is in strict accordance with the supplied connection diagram.



Correct possible errors before continuing to test the circuitry.

Test the circuitry.

- Polarity check when applicable; this test is often omitted for CVTs
- VT circuit voltage measurement (primary injection test)
- Grounding check
- Phase relationship
- Insulation resistance check

The primary injection test verifies the VT ratio and the wiring all the way from the primary system to the IED. Injection must be performed for each phase-to-neutral circuit.



While testing VT secondary circuit and associated secondary equipment, care shall be exercised to isolate the VT from the circuit being tested to avoid backcharging the VT from the secondary side.

4.9 Using the RTXP test switch

The RTXP test switch is designed to provide the means of safe testing of the IED. This is achieved by the electromechanical design of the test switch and test plug handle. When the test plug handle is inserted, it first blocks the trip and alarm circuits then it short circuits the CT secondary circuit and opens the VT secondary circuits making the IED available for secondary injection.

When pulled out, the test handle is mechanically stopped in half withdrawn position. In this position, the current and voltage enter the protection, but the alarm and trip circuits are still isolated and the IED is in test mode. Before removing the test handle, check the measured values in the IED.

Not until the test handle is completely removed, the trip and alarm circuits are restored for operation.



Verify that the contact sockets have been crimped correctly and that they are fully inserted by tugging on the wires. Never do this with current circuits in service.

Current circuit

1. Verify that the contacts are of current circuit type.
2. Verify that the short circuit jumpers are located in the correct slots.

Voltage circuit

1. Verify that the contacts are of voltage circuit type.
2. Check that no short circuit jumpers are located in the slots dedicated for voltage.

Trip and alarm circuits

1. Check that the correct types of contacts are used.

4.10 Checking the binary I/O circuits

4.10.1 Binary input circuits

Preferably, disconnect the binary input connector from the binary input cards. Check all connected signals so that both input level and polarity are in accordance with the IED specifications.

4.10.2 Binary output circuits

Preferably, disconnect the binary output connector from the binary output cards. Check all connected signals so that both load and polarity are in accordance with IED specifications.

Section 5 Configuring the IED and changing settings

5.1 Overview

The customer specific values for each setting parameter and a configuration file have to be available before the IED can be set and configured, if the IED is not delivered with a configuration.

Use the configuration tools in PCM600 to verify that the IED has the expected configuration. A new configuration is done with the application configuration tool. The binary outputs can be selected from a signal list where the signals are grouped under their function names. It is also possible to specify a user-defined name for each input and output signal.

Each function included in the IED has several setting parameters, which have to be set in order to make the IED behave as intended. A factory default value is provided for each parameter. A setting file can be prepared using the Parameter Setting tool, which is available in PCM600.

All settings can be

- Entered manually through the local HMI.
- Written from a PC, either locally or remotely using PCM600. Front or rear port communication has to be established before the settings can be written to the IED.



It takes a minimum of three minutes for the IED to save the new settings, during this time the DC supply must not be turned off.

The IED uses a FLASH disk for storing configuration data and process data like counters, object states, Local/Remote switch position etc. Since FLASH memory is used, measures have been taken in software to make sure that the FLASH disk is not worn out by too intensive storing of data. These mechanisms make it necessary to think about a couple of issues in order to not lose configuration data, especially at commissioning time.

After the commissioning is complete, the configuration data is always stored to FLASH, so that is not an issue. But other things, like objects states and the Local/Remote switch position is stored in a slightly different way, where the save of data to FLASH is performed more and more seldom to eliminate the risk of wearing out the

FLASH disk. In worst case, the time between saves of this kind of data is around one hour.

This means, that to be absolutely sure that all data have been saved to FLASH, it is necessary to leave the IED with auxiliary power connected after all the commissioning is done (including setting the Local/Remote switch to the desired position) for at least one hour after the last commissioning action performed on the IED.

After that time has elapsed, it will be safe to turn the IED off, no data will be lost.

5.2 Configuring analog CT inputs

The analog input channels must be configured to get correct measurement results as well as correct protection functionality. Because all protection algorithms in the IED utilize the primary system quantities, it is extremely important to make sure that connected current transformer settings are done properly. These data are calculated by the system engineer and normally set by the commissioning personnel from the local HMI or from PCM600.

The analog inputs on the transformer input module are dimensioned for either 1A or 5A. Each transformer input module has a unique combination of current and voltage inputs. Make sure the input current rating is correct and that it matches the order documentation.

The primary CT data are entered via the HMI menu under **Main menu/Settings/General Settings/Analog modules/AnalogInputs**

The following parameter shall be set for every current transformer connected to the IED:

Table 3: *CT configuration*

Parameter description	Parameter name	Range	Default
Rated CT primary current in A	CT Prim Input	from -10000 to +10000	0

This parameter defines the primary rated current of the CT. For two set of CTs with ratio 1000/1 and 1000/5 this parameter is set to the same value of 1000 for both CT inputs. Negative values (that is -1000) can be used in order to reverse the direction of the CT current by software for the differential function. This might be necessary if two sets of CTs have different neutral (WYE) point locations in relation to the protected busbar. It is recommended that this parameter is set to zero, for all unused CT inputs.

For main CTs with 2A rated secondary current, it is recommended to connect the secondary wiring to the 1A input.



Take the rated permissive overload values for the current inputs into consideration.

5.3 Reconfiguring the IED

I/O modules configured as logical I/O modules (BIM, BOM or IOM) are supervised.

I/O modules that are not configured are not supervised.

Each logical I/O module has an error flag that indicates signal or module failure. The error flag is also set when the physical I/O module of the correct type is not detected in the connected slot.

Section 6 Establishing connection and verifying the SPA/IEC communication

6.1 Entering settings

If the IED is connected to a monitoring or control system via the rear SPA/IEC port, the SPA/IEC port has to be set either for SPA or IEC use.

6.1.1 Entering SPA settings

The SPA/IEC port is located on the rear side of the IED. Two types of interfaces can be used:

- for plastic fibres with connector type HFBR
- for glass fibres with connectors type ST

When using the SPA protocol, the rear SPA/IEC port must be set for SPA use.

Procedure

1. Set the operation of the rear optical SPA/IEC port to “SPA”.
The operation of the rear SPA port can be found on the local HMI under **Main menu/Configuration/Communication/Station communication/Port configuration/SLM optical serial port/PROTOCOL:1**
When the setting is entered the IED restarts automatically. After the restart the SPA/IEC port operates as a SPA port.
2. Set the slave number and baud rate for the rear SPA port
The slave number and baud rate can be found on the local HMI under **Main menu/Configuration/Communication/Station communication/SPA/SPA:1**
Set the same slave number and baud rate as set in the SMS system for the IED.

6.1.2 Entering IEC settings

When using the IEC protocol, the rear SPA/IEC port must be set for IEC use.

Two types of interfaces can be used:

- for plastic fibres with connector type HFBR
- for glass fibres with connectors type ST

Procedure

1. Set the operation of the rear SPA/IEC port to “IEC”.
The operation of the rear SPA/IEC port can be found on the local HMI under **Main menu/Configuration/Communication/SLM configuration/Rear optical SPA-IEC-DNP port/PROTOCOL:1**
When the setting is entered the IED restarts automatically. After the restart the selected IEC port operates as an IEC port.
2. Set the slave number and baud rate for the rear IEC port.
The slave number and baud rate can be found on the local HMI under **Main menu/Configuration/Communication/SLM configuration/Rear optical SPA-IEC-DNP port/IEC60870-5-103**
Set the same slave number and baud rate as set in the IEC master system for the IED.

6.2 Verifying the communication

To verify that the rear communication with the SMS/SCS system is working, there are some different methods. Choose one of the following.

6.2.1 Verifying SPA communication

Procedure

1. Use a SPA-emulator and send “RF” to the IED. The answer from the IED should be the type and version of it, for example, “REL670 2.0...”.
2. Generate one binary event by activating a function, which is configured to an event block where the used input is set to generate events on SPA. The configuration must be made with the PCM600 software. Verify that the event is presented in the SMS/SCS system.

During the following tests of the different functions in the IED, verify that the events and indications in the SMS/SCS system are as expected.

6.2.2 Verifying IEC communication

To verify that the IEC communication with the IEC master system is working, there are some different methods. Choose one of the following.

Procedure

1. Check that the master system time-out for response from the IED, for example after a setting change, is > 40 seconds.
2. Use a protocol analyzer and record the communication between the IED and the IEC master. Check in the protocol analyzer's log that the IED answers the master messages.
3. Generate one binary event by activating a function that is configured to an event block where the used input is set to generate events on IEC. The configuration must be made with the PCM600 software. Verify that the event is presented in the IEC master system.

During the following tests of the different functions in the IED, verify that the events and indications in the IEC master system are as expected.

6.3 Fibre optic loop

The SPA communication is mainly used for SMS. It can include different numerical IEDs with remote communication possibilities. The fibre optic loop can contain < 20-30 IEDs depending on requirements on response time. Connection to a personal computer (PC) can be made directly (if the PC is located in the substation) or by telephone modem through a telephone network with ITU (CCITT) characteristics.

Table 4: *Max distances between IEDs/nodes*

glass	< 1000 m according to optical budget
plastic	< 25 m (inside cubicle) according to optical budget

6.4 Optical budget calculation for serial communication with SPA/IEC

Table 5: Example

	Distance 1 km Glass	Distance 25 m Plastic
Maximum attenuation	- 11 dB	- 7 dB
4 dB/km multi mode: 820 nm - 62.5/125 um	4 dB	-
0.16 dB/m plastic: 620 nm - 1mm	-	4 dB
Margins for installation, aging, and so on	5 dB	1 dB
Losses in connection box, two contacts (0.5 dB/contact)	1 dB	-
Losses in connection box, two contacts (1 dB/contact)	-	2 dB
Margin for 2 repair splices (0.5 dB/splice)	1 dB	-
Maximum total attenuation	11 dB	7 dB

Section 7 Establishing connection and verifying the LON communication

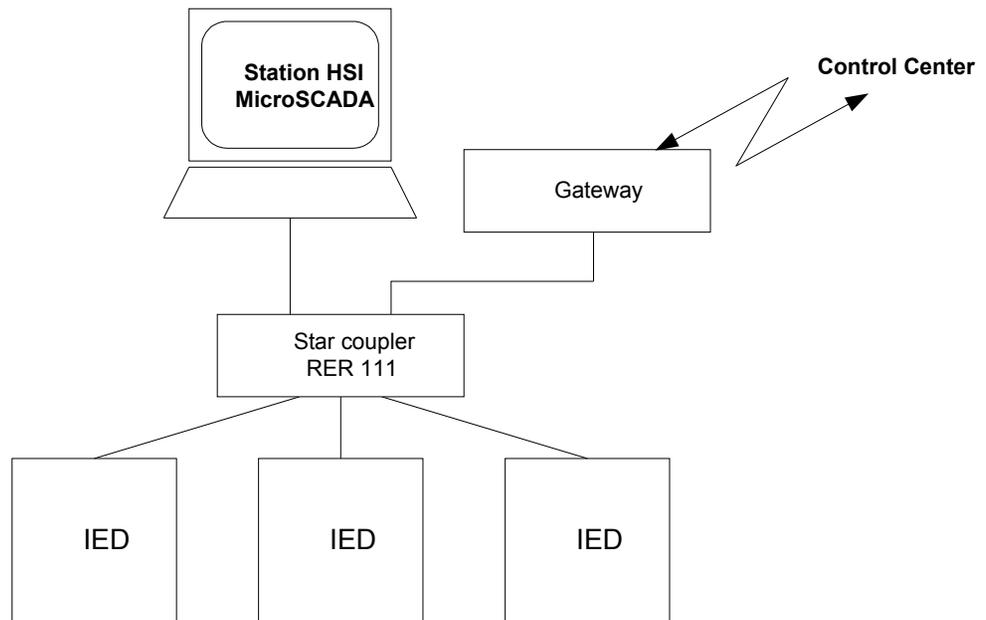
7.1 Communication via the rear ports

7.1.1 LON communication

LON communication is normally used in substation automation systems. Optical fiber is used within the substation as the physical communication link.

The test can only be carried out when the whole communication system is installed. Thus, the test is a system test and is not dealt with here.

The communication protocol Local Optical Network (LON) is available for 670 IED series.



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Figure 9: Example of LON communication structure for a substation automation system

An optical network can be used within the substation automation system. This enables communication with the IEDs in the 670 series through the LON bus from the operator's workplace, from the control center and also from other IEDs via bay-to-bay horizontal communication.

The fibre optic LON bus is implemented using either glass core or plastic core fibre optic cables.

Table 6: *Specification of the fibre optic connectors*

	Glass fibre	Plastic fibre
Cable connector	ST-connector	snap-in connector
Cable diameter	62.5/125 m	1 mm
Max. cable length	1000 m	10 m
Wavelength	820-900 nm	660 nm
Transmitted power	-13 dBm (HFBR-1414)	-13 dBm (HFBR-1521)
Receiver sensitivity	-24 dBm (HFBR-2412)	-20 dBm (HFBR-2521)

7.2.1

The LON Protocol

The LON protocol is specified in the LonTalkProtocol Specification Version 3 from Echelon Corporation. This protocol is designed for communication in control networks and is a peer-to-peer protocol where all the devices connected to the network can communicate with each other directly. For more information of the bay-to-bay communication, refer to the section Multiple command function.

7.2.2

Hardware and software modules

The hardware needed for applying LON communication depends on the application, but one very central unit needed is the LON Star Coupler and optical fibres connecting the star coupler to the IEDs. To interface the IEDs from MicroSCADA, the application library LIB670 is required.

The HV Control 670 software module is included in the LIB520 high-voltage process package, which is a part of the Application Software Library within MicroSCADA applications.

The HV Control 670 software module is used for control functions in IEDs in the 670 series. This module contains the process picture, dialogues and a tool to generate the process database for the control application in MicroSCADA.

Use the LON Network Tool (LNT) to set the LON communication. This is a software tool applied as one node on the LON bus. To communicate via LON, the IEDs need to know

Establishing connection and verifying the LON communication

- The node addresses of the other connected IEDs.
- The network variable selectors to be used.

This is organized by LNT.

The node address is transferred to LNT via the local HMI by setting the parameter *ServicePinMsg = Yes*. The node address is sent to LNT via the LON bus, or LNT can scan the network for new nodes.

The communication speed of the LON bus is set to the default of 1.25 Mbit/s. This can be changed by LNT.

The setting parameters for the LON communication are set via the local HMI. Refer to the technical manual for setting parameters specifications.

The path to LON settings in the local HMI is **Main menu/Configuration/Communication/SLM configuration/Rear optical LON port**

If the LON communication from the IED stops, caused by setting of illegal communication parameters (outside the setting range) or by another disturbance, it is possible to reset the LON port of the IED.

Path in the local HMI under **Main menu/Configuration/Communication/SLM configuration/Rear optical LON port**

These parameters can only be set with the LON Network Tool (LNT).

Table 7: *Setting parameters for the LON communication*

Parameter	Range	Default	Unit	Parameter description
DomainID	0	0	-	Domain identification number
SubnetID*	0 - 255 Step: 1	0	-	Subnet identification number
NodeID*	0 - 127 Step: 1	0	-	Node identification number
*Can be viewed in the local HMI				

Path in the local HMI under **Main menu/Configuration/Communication/SLM configuration/Rear optical LON port**

These parameters can only be set with the LON Network Tool (LNT).

Table 8: *LON node information parameters*

Parameter	Range	Default	Unit	Parameter description
NeuronID*	0 - 12	Not loaded	-	Neuron hardware identification number in hexadecimal code
Location	0 - 6	No value	-	Location of the node
*Can be viewed in the local HMI				

Path in the local HMI under **Main menu/Configuration/Communication/SLM configuration/Rear optical LON port**

Table 9: *ADE Non group settings (basic)*

Name	Values (Range)	Unit	Step	Default	Description
Operation	Disabled Enabled	-	-	Disabled	Operation
TimerClass	Slow Normal Fast	-	-	Slow	Timer class

Path in the local HMI under **Main menu/Configuration/Communication/SLM configuration/Rear optical LON port**

Table 10: *LON commands*

Command	Command description
ServicePinMsg	Command with confirmation. Transfers the node address to the LON Network Tool.

7.2

Optical budget calculation for serial communication with LON

Table 11: *Example*

	Distance 1 km Glass	Distance 10 m Plastic
Maximum attenuation	-11 dB	- 7 dB
4 dB/km multi mode: 820 nm - 62.5/125 um	4 dB	-
0.3 dB/m plastic: 620 nm - 1mm	-	3 dB
Margins for installation, aging, and so on	5 dB	2 dB
Losses in connection box, two contacts (0.75 dB/contact)	1.5 dB	-
Table continues on next page		

	Distance 1 km Glass	Distance 10 m Plastic
Losses in connection box, two contacts (1dB/contact)	-	2 dB
Margin for repair splices (0.5 dB/splice)	0.5 dB	-
Maximum total attenuation	11 dB	7 dB

Section 8 Establishing connection and verifying the IEC 61850 communication

8.1 Overview

The rear OEM ports are used for substation bus (IEC 61850-8-1) communication.

For IEC 61850-8-1 redundant communication, both rear OEM ports are utilized. In this case IEC 61850-9-2LE communication can not be used.



IEC 61850-9-2LE process bus communication is not supported in the IED.

8.2 Setting the station communication

To enable IEC 61850 communication the corresponding OEM ports must be activated. The rear OEM port AB and CD is used for IEC 61850-8-1 communication. For IEC 61850-8-1 redundant communication, both OEM port AB and CD are used exclusively.

To enable IEC 61850 station communication:

1. Enable IEC 61850-8-1 (substation bus) communication for port AB.
 - 1.1. Set values for the rear ports AB and CD.
Navigate to: **Main menu/Configuration/Communication/Ethernet configuration/LANAB:1**
Set values for *Mode*, *IPAddress* and *IPMask*. *Mode* must be set to *Normal*.
Check that the correct IP address is assigned to the port.
 - 1.2. Enable IEC 61850-8-1 communication.
Navigate to: **Main menu/Configuration/Communication/Station communication/IEC61850-8-1/IEC61850-8-1:1**
Set *Operation* to *Enabled* and *PortSelGOOSE* to the port used (for example *LANAB*).
2. Enable redundant IEC 61850-8-1 communication for port AB and CD
 - 2.1. Enable redundant communication.

Navigate to: **Main menu/Configuration/Communication/Ethernet configuration/PRP:1**

Set values for *Operation*, *IPAddress* and *IPMask*. *Operation* must be set to *Enabled*.

The IED will restart after confirmation. Menu items **LANAB:1** and **LANCD:1** are hidden in local HMI after restart but are visible in PST where the values for parameter *Mode* is set to *Duo*.

8.3 Verifying the communication

Connect your PC to the substation network and ping the connected IED and the Substation Master PC, to verify that the communication is working (up to the transport layer).

The best way to verify the communication up to the application layer is to use protocol analyzer connected to the substation bus, and monitor the communication.

Verifying redundant IEC 61850-8-1 communication

Ensure that the IED receives IEC 61850-8-1 data on both port AB and CD. Browse in the local HMI to **Main menu/Diagnostics/Communication/Redundant PRP** and check that both signals LAN-A-STATUS and LAN-B-STATUS are shown as *Ok*. Remove the optical connection to one of the ports AB or CD. Verify that either signal LAN-A-STATUS or LAN-B-STATUS (depending on which connection that was removed) are shown as *Error* and the that other signal is shown as *Ok*. Be sure to re-connect the removed connection after completed verification.

Section 9 Testing IED operation

9.1 Preparing for test

9.1.1 Preparing the IED to verify settings

If a test switch is included, start preparation by making the necessary connections to the test switch. This means connecting the test equipment according to a specific and designated IED terminal diagram.

Put the IED into the test mode to facilitate the test of individual functions and prevent unwanted operation caused by other functions. The busbar differential protection is not included in the test mode and is not prevented to operate during the test operations. The test switch should then be connected to the IED.

Verify that analog input signals from the analog input module are measured and recorded correctly by injecting currents and voltages required by the specific IED.

To make testing even more effective, use PCM600. PCM600 includes the Signal monitoring tool, which is useful in reading the individual currents and voltages, their amplitudes and phase angles. In addition, PCM600 contains the Disturbance handling tool. The content of reports generated by the Disturbance handling tool can be configured which makes the work more efficient. For example, the tool may be configured to only show time tagged events and to exclude analog information and so on.

Check the disturbance report settings to ensure that the indications are correct.

For information about the functions to test, for example signal or parameter names, see the technical manual. The correct initiation of the disturbance recorder is made on pickup and/or release or trip from a function. Also check that the wanted recordings of analog (real and calculated) and binary signals are achieved.



Parameters can be entered into different setting groups. Make sure to test functions for the same parameter setting group. If needed, repeat the tests for all different setting groups used. The difference between testing the first parameter setting group and the remaining is that there is no need for testing the connections.

During testing, observe that the right testing method, that corresponds to the actual parameters set in the activated parameter setting group, is used.

Set and configure the function(s) before testing. Most functions are highly flexible and permit a choice of functional and tripping modes. The various modes are checked at the factory as part of the design verification. In certain cases, only modes with a high probability of coming into operation need to be checked when commissioned to verify the configuration and settings.

9.2 Activating the test mode

Put the IED into the test mode before testing. The test mode blocks all protection functions and some of the control functions in the IED, and the individual functions to be tested can be unblocked to prevent unwanted operation caused by other functions. In this way, it is possible to test slower back-up measuring functions without the interference from faster measuring functions. The busbar differential protection is not included in the test mode and is not prevented to operate during the test operations. The test switch should then be connected to the IED. Test mode is indicated when the yellow PickupLED flashes.

1. Browse to the **TestMode** menu and press *E*.
The **TestMode** menu is found on the local HMI under **Main menu/Test/IED test mode/TestMode**
2. Use the up and down arrows to choose *Enabled* and press *E*.
3. Press the left arrow to exit the menu.
The dialog box *Save changes* appears.
4. Choose *Yes*, press *E* and exit the menu.
The yellow pickupLED above the LCD will start flashing when the IED is in test mode.

9.3 Preparing the connection to the test equipment

The IED can be equipped with a test switch of type RTXP8, RTXP18 or RTXP24 or FT. The test switch and its associated test plug handles are a part of the COMBITEST or FT system of ABB, which provides secure and convenient testing of the IED.

When using the COMBITEST, preparations for testing are automatically carried out in the proper sequence, that is, for example, blocking of tripping circuits, short circuiting of CTs, opening of voltage circuits, making IED terminals available for secondary injection. Terminals 1 and 8, 1 and 18 as well as 1 and 12 of the test switches RTXP8, RTXP18 and RTXP24 respectively are not disconnected as they supply DC power to the protection IED. When FT switch is used for testing, care shall be exercised to open the tripping circuit, ahead of manipulating the CT fingers.

The RTXH test-plug handle leads may be connected to any type of test equipment or instrument. When a number of protection IEDs of the same type are tested, the test-plug handle only needs to be moved from the test switch of one protection IED to the test switch of the other, without altering the previous connections.

Use COMBITEST test system to prevent unwanted tripping when the handle is withdrawn, since latches on the handle secure it in the half withdrawn position. In this position, all voltages and currents are restored and any re-energizing transients are given a chance to decay before the trip circuits are restored. When the latches are released, the handle can be completely withdrawn from the test switch, restoring the trip circuits to the protection IED.

If a test switch is not used, perform measurement according to the provided circuit diagrams.



Never disconnect the secondary connection of a current transformer circuit without first short-circuiting the transformer's secondary winding. Operating a current transformer with the secondary winding open will cause a massive potential build up that may damage the transformer and cause personal injury.

9.4

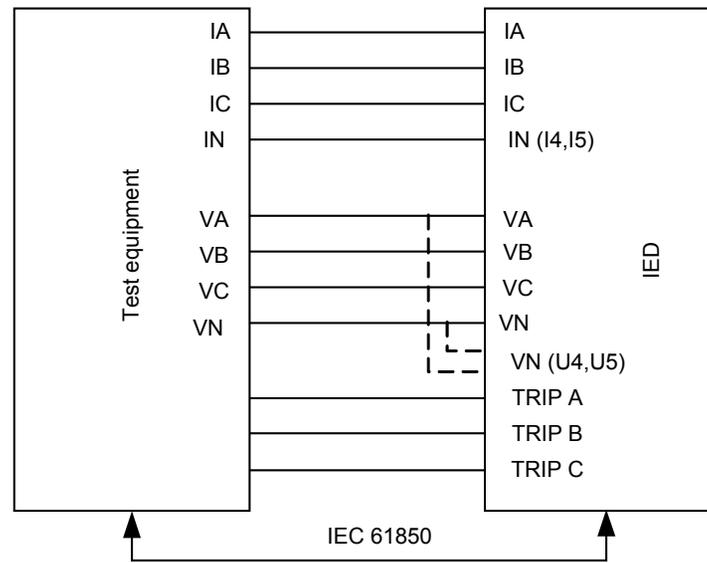
Connecting the test equipment to the IED

Connect the test equipment according to the IED specific connection diagram and the needed input and output signals for the function under test. An example of a connection is shown in figure [10](#).

Connect the current and voltage terminals. Pay attention to the current polarity. Make sure that the connection of input and output current terminals and the connection of the residual current conductor is correct. Check that the input and output logical signals in the logic diagram for the function under test are connected to the corresponding binary inputs and outputs of the IED under test.



To ensure correct results, make sure that the IED as well as the test equipment are properly grounded before testing.



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Figure 10: Connection example of the test equipment to the IED when test equipment is connected to the transformer input module

9.5 Releasing the function to be tested

Release or unblock the function to be tested. This is done to ensure that only the function or the chain of functions to be tested are in operation and that other functions are prevented from operating. Release the tested function(s) by setting the corresponding *Blocked* parameter under Function test modes to *No* in the local HMI.

When testing a function in this blocking feature, remember that not only the actual function must be activated, but the whole sequence of interconnected functions (from measuring inputs to binary output contacts), including logic must be activated. Before starting a new test mode session, scroll through every function to ensure that only the function to be tested (and the interconnected ones) have the parameters *Blocked* and eventually *EvDisable* set to *No* and *Yes* respectively. Remember that a function is also blocked if the BLOCK input signal on the corresponding function block is active, which depends on the configuration. Ensure that the logical status of the BLOCK input signal is equal to 0 for the function to be tested. Event function blocks can also be individually blocked to ensure that no events are reported to a remote station during the test. This is done by setting the parameter *EvDisable* to *Yes*.



Any function is blocked if the corresponding setting in the local HMI under **Main menu/Test/Function test modes** menu remains *Enabled*, that is, the parameter *Blocked* is set to *Yes* and the parameter *TestMode* under **Main menu/Test/IED test mode** remains active. All functions that were blocked or released in a previous test mode session, that is, the parameter *Test mode* is set to *Enabled*, are reset when a new test mode session is started.

Procedure

1. Click the **Function test modes** menu.
The Function test modes menu is located in the local HMI under **Main menu/Test/Function test modes**.
2. Browse to the function instance that needs to be released.
3. Set parameter *Blocked* for the selected function to *No*.

9.6 Verifying analog primary and secondary measurement

Verify that the connections are correct and that measuring and scaling is done correctly. This is done by injecting current and voltage to the IED.



Apply input signals as needed according to the actual hardware and the application configuration.

1. Inject a symmetrical three-phase voltage and current at rated value.
2. Compare the injected value with the measured values.
The voltage and current phasor menu in the local HMI is located under **Main menu/Measurements/Analog primary values** and **Main menu/Measurements/Analog secondary values**.
3. Compare the frequency reading with the set frequency and the direction of the power.
The frequency and active power are located under **Main menu/Measurements/Monitoring/ServiceValues(MMXN)/CVMMXN:x**. Then navigate to the bottom of the list to find the frequency.
4. Inject an unsymmetrical three-phase voltage and current, to verify that phases are correctly connected.

If some setting deviates, check the analog input settings under

Main menu/Settings/General settings/Analog modules

9.7 Testing the protection functionality

Each protection function must be tested individually by secondary injection.

- Verify operating levels (trip) and timers.
- Verify alarm and blocking signals.
- Use the disturbance handling tool in PCM600 to evaluate that the protection function has received the correct data and responded correctly (signaling and timing).
- Use the event viewer tool in PCM600 to check that only expected events have occurred.

Section 10 Testing functionality by secondary injection

10.1 Testing disturbance report

10.1.1 Disturbance recorder (DR)

A *Manual Trig* can be started at any time. This results in a recording of the actual values from all recorded channels.

The *Manual Trig* can be started in two ways:

1. From the local HMI under **Main menu/Disturbance records**.
 - 1.1. Enter on the row at the bottom of the HMI called **Manual trig**.
A new recording begins. The view is updated if you leave the menu and return.
 - 1.2. Navigate to **General information** or to **Trip values** to obtain more detailed information.
2. Open the Disturbance handling tool for the IED in the plant structure in PCM600.
 - 2.1. Right-click and select *Execute manual Trig* in the window *Available recordings in IED*.
 - 2.2. Read the required recordings from the IED.
 - 2.3. Refresh the window *Recordings* and select a recording.
 - 2.4. Right-click and select *Create Report* or *Open With* to export the recordings to any disturbance analyzing tool that can handle Comtrade formatted files.

Evaluation of the results from the disturbance recording function requires access to a PC either permanently connected to the IED or temporarily connected to the Ethernet port (RJ-45) on the front. The PCM600 software package must be installed in the PC.

Disturbance upload can be performed by the use of PCM600 or by any third party tool with IEC 61850 protocol. Reports can automatically be generated from PCM600. Disturbance files can be analyzed by any tool reading Comtrade formatted disturbance files.

It could be useful to have a printer for hard copies. The correct start criteria and behavior of the disturbance recording function can be checked when IED protective functions are tested.

When the IED is brought into normal service it is recommended to delete all recordings, made during commissioning to avoid confusion in future fault analysis.

All recordings in the IED can be deleted in two ways:

1. in the local HMI under **Main menu/Clear/Reset disturbances**, or
2. in the Disturbance handling tool in PCM600 by selecting *Delete all recordings in the IED...* in the window *Available Recordings in IED*.

10.1.2 Event recorder (ER) and Event list (EL)

The result from the event recorder and event list can be viewed on the local HMI or, after upload, in PCM600 as follows:

1. on the local HMI under **Main menu/Events**, or in more details via
2. the *Event Viewer* in PCM600.
The internal FIFO register of all events will appear when the event viewer is launched.

When the IED is brought into normal service it is recommended to delete all events resulting from commissioning tests to avoid confusion in future fault analysis. All events in the IED can be cleared in the local HMI under **Main Menu//Clear/Clear internal event list** or **Main menu/Clear/Clear process event list**. It is not possible to clear the event lists from PCM600.

When testing binary inputs, the event list (EL) might be used instead. No uploading or analyzing of registrations is then needed since the event list keeps running, independent of start of disturbance registration.

10.2 Differential protection

10.2.1 Busbar differential protection

10.2.1.1 General

Secondary injection testing is a normal part of the commissioning. The operating value of all protection functions, the output to the proper trip and alarm contacts and the operation of binary input signals is checked and documented for future reference.

The connection of the test set to REB670 is greatly simplified if test switch systems such as RTXP24 or FT are included. Specially with COMBIFLEX system, when the test handle RTXH 24 is inserted in the test switch, preparations for testing are automatically carried out in the proper sequence, that is, blocking of the tripping

circuits, short-circuiting of the current circuits on the transformer side, opening of current transformer circuits and making IED terminals accessible from the terminals on the test plug handle.

If the REB670 is not provided with a test switch, the IED has to be tested in the proper way from external circuit terminals. Make sure that the instrument transformers are isolated from the circuits connected to the test set. The secondary phase terminals of the current transformers must be short-circuited to neutral before the circuit is opened if any current can flow on the primary side. The testing requires a good understanding of the protection functionality of the REB670. A testing instruction is given for each type of protection function.



Note that CT inputs for the REB670 are designed for a maximum continuous current of four times rated value.

10.2.1.2

Operation of the differential protection from CTx input

Prepare the IED for verification of settings as outlined in section "" and section "Preparing for test" in this chapter.

The typical connection between the three-phase current test set and REB670 IEDs is shown in figure 11.

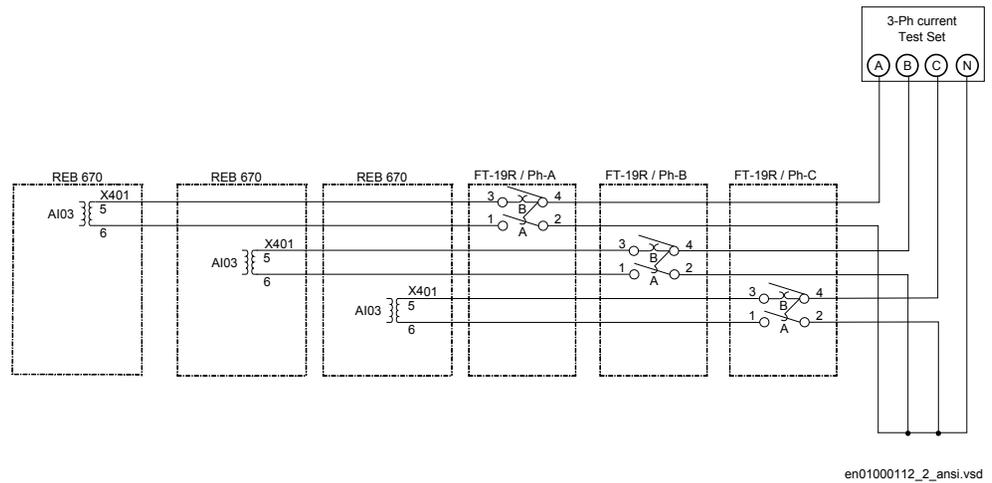


Figure 11: Typical test connection for CT3 current input when test switch is delivered together with one-phase REB670 IED

Testing will be explained from one general current input CT_x (that is $x=1, 2, \dots, N_{\max}$; where N_{\max} is equal to the maximum number of used CT inputs). Follow the following test instructions for all used current inputs in the REB670 IED.

Procedure

1. Connect the test set for injection of three-phase current (or if not available one-phase current) to the current terminals of CT_x input of REB670 terminal.
2. Check and write down the value for the configuration parameter *CT Prim Input x*, which should correspond to the rated primary CT current of the main CT connected to CT_x current input.
3. Check the value for the configuration parameter *ZoneSel/CT_x*. If this value is *Fixed to ZA*, *Fixed to ZB* or *Fixed to ZA & - ZB*, proceed with next point. (If this value is *CtrlIncludes*, energize the binary input *CTRLZA* to include the current from this current input into ZA measurement.)
4. If this value is *CtrlExcludes*, de-energize the binary input *CTRLZA* to include the current from this current input into ZA measurement.
5. Make sure that the check zone is properly set and enabled, when used.
6. Increase the current in phase A until the correct differential function (that is, either ZA or ZB) operates and note the incoming and differential currents at the moment of operation.
7. Check that trip and alarm contacts operate according to the scheme wiring.
8. Check that trip information is stored in the event list (if connected).
9. Switch off the current.
10. Check that trip reset information is stored in the event list (if connected).
11. Check in the same way the function by injecting current in phases B and C.
12. Inject a symmetrical three-phase current and note the operate value (possible with three-phase test set only).
13. Connect the timer and set the current to five times the set value for *DiffOperLevel* parameter.
14. Switch on the current and note the operate time.
15. If the value for the configuration parameter *ZoneSel/CT_x* is *CtrlIncludes*, de-energize the binary input *CTRLZA* and now energize the binary input *CTRLZB* to include the current from this current input into ZB measurement.
16. If the value for the configuration parameter *ZoneSel/CT_x* is *CtrlExcludes*, energize the binary input *CTRLZA* and now de-energize binary input *CTRLZB* to include the current from this current input into ZB measurement.
17. Repeat the steps from [4](#) to [12](#) for zone ZB
18. If the value for the configuration parameter *ZoneSel/CT_x* is *CtrlIncludes*, energize now both binary inputs *CTRLZA* and *CTRLZB* to include the current from this current input into both measuring zone simultaneously.
19. If the value for the configuration parameter *ZoneSel/CT_x* is *CtrlExcludes*, de-energize now both the binary inputs *CTRLZA* and *CTRLZB* to include the current from this current input into both measuring zone simultaneously.

20. Make sure that the dedicated binary output *ACTIVE* from the *Zone Interconnection* block has the logical value *One*.
21. Repeat the steps from 4 to 12.



Note that now both zones shall operate during these tests.

22. Check in the same way that the differential function properly operates for all used and connected CT inputs.

10.2.1.3 Stability of the busbar differential protection

For stability test one current input shall always be used as a reference input. The reference current input then shall be tested for stability against all other current inputs in the IED. It is recommended to use current input CT1 as the reference current input. The typical connection between the three-phase current test set and the IED for this type of tests is shown in figure 12.

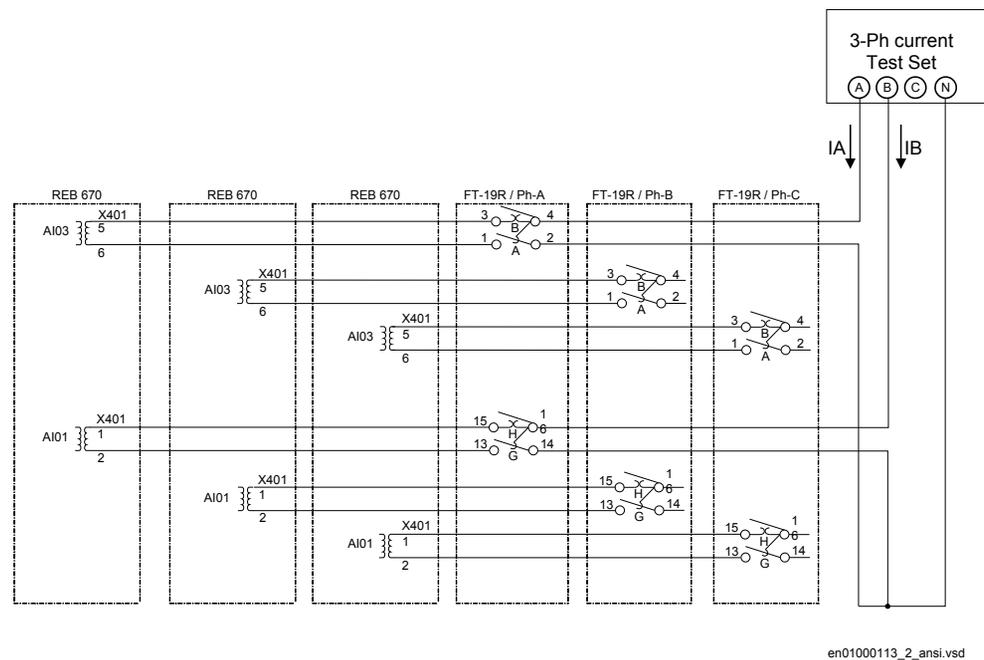


Figure 12: Typical test connection for CT3 and CT1 current input phase A when test switch is delivered together with the one-phase IED

The connections are shown for phase A only. Similar connection shall be used for testing phase B and C also.

Testing will be explained for one general current input CT_x (that is x=2, 3,...,N_{max}; where N_{max} is equal to the maximum number of used CT inputs).

Follow the following test instructions to perform this type of test.

Procedure

1. Connect the currents I₁ and I₂ from the three-phase test set to the current terminals of CT₁ and CT_x inputs of the IED as shown in figure 12.
2. Make sure that current measurement from CT₁ and CT_x inputs are included into the same differential zone (see previous test instruction for more details).
3. Set the current I₂ (that is, current connected to reference current input CT₁) to the nominal value of 5A (or to 1A if CT₁ is connected to a main CT with 5A secondary rating) at 0°.
4. Set the current I₁ (that is, connected to current input CT_x) to the value calculated by the following formula:

Figure 13:
$$I_1 = I_{Xr} \cdot (CT \text{ Prim Input1} / CT \text{ Prim Inputx})$$

where:

I_{Xr} is rated secondary current of the current input CT_x (that is, normally 1A or 5A)

CT Prim Input1 is the rated primary CT current of the main CT connected to CT₁ current input

CT Prim Inputx is the rated primary CT current of the main CT connected to CT_x current input

5. Set the phase angle of current I₁ to 180° if both current inputs (that is, CT₁ and CT_x) has the same sign for entered configuration parameters *CT Prim Input1* and *CT Prim Input3* (that is, both positive or both negative). Otherwise set the phase angle of current I₁ to 0°.
6. Inject these two currents into the IED. Differential function shall be stable. Write down the service values for incoming and differential currents for phase A. Differential current should be very small.
7. Switch off the currents.
8. Repeat the same test procedure for phases B and C.

10.2.1.4

Operation of fast open CT detection algorithm

For open CT test two current inputs shall always be used. The typical connection between the three-phase current test set and the IED for this type of tests is shown in figure 12.

The connections are shown for phase A only. Similar connection shall be used for testing phase B and C also.

Follow the following test instructions to perform this type of test.

Procedure

1. Connect the currents I1 and I2 from the three-phase test set test set to the current terminals of CT1 and CT3 inputs of the IED as shown in figure [12](#).
2. Make sure that current measurement from CT1 and CT3 inputs are included into the same differential zone (see previous test instructions for more details).
3. Set the current I2 (that is, current connected to input CT1) to the nominal value of 5A (or to 1A if CT1 is connected to a main CT with 5A secondary rating) at zero degree.
4. Set the current I1 (that is, connected to current input CT3) to the value calculated by the following formula:

Figure 14:
$$I1 = I3r \cdot (CT\ Prim\ Input1 / CT\ Prim\ Input3)$$

where:

$I3r$ is rated secondary current of the current input CT3 (that is, normally 1A or 5A)

$CT\ Prim\ Input1$ is the rated primary CT current of the main CT connected to CT1 current input

$CT\ Prim\ Input3$ is the rated primary CT current of the main CT connected to CT3 current input

5. Check that the value of the product $I1 \cdot CT\ Prim\ Input3$ is bigger than the value of the product $1.1 \cdot Open\ CT\ Level$ (this is just a check to see that enough current will be disconnected later during testing in order for open CT algorithm to operate).
6. Set the phase angle of current I1 to 180 degrees if both current inputs (that is, CT1 and CT3) have the same sign for entered configuration parameters $CT\ Prim\ Input1$ and $CT\ Prim\ Input3$ (that is, both positive or both negative). Otherwise set the phase angle of current I1 to 0°.
7. Inject these two currents into the IED for approximately 5s. Differential function shall be stable. Write down the service values for incoming and differential currents for phase A. Differential current should be very small.
8. Then switch off the current I2 only (that is, set its magnitude back to 0A).
9. Open CT condition shall be detected by the IED. The differential function will be blocked.
10. Check that open CT alarm contacts operate accordingly to the scheme wiring.
11. Check that open CT information is stored in the event list (if connected).
12. Switch off the currents.
13. Reset the open CT blocking in the reset menu of the local HMI.
14. Check that open CT reset information is stored in the event list (if connected).
15. Repeat the same test procedure for phases B and C.

10.2.1.5

Operation of slow open CT detection algorithm

For open CT test two current inputs shall be always used. The typical connection between the three-phase current test set and the IED for this type of tests is shown in figure [12](#).

The connections are shown for phase A only. Similar connection shall be used for testing phase B and C also.

Follow the following test instructions to perform this type of test.

Procedure

1. Connect the currents I1 and I2 from the three-phase test set to the current terminals of CT1 and CT3 inputs of the IED as shown in figure [12](#).
2. Make sure that current measurement from CT1 and CT3 inputs are included into the same differential zone (see previous test instructions for more details).
3. Set the current I2 (that is, current connected to current input CT1) to the nominal value of 5A (or to 1A if CT1 is connected to a main CT with 5A secondary rating) at zero degree.
4. Set the current I1 (that is, connected to current input CT3) to the value calculated by the following formula:

Figure 15:
$$I1 = 0.85 \cdot I3r \cdot (CT Prim Input1 / CT Prim Input3)$$

where:

$I3r$ is rated secondary current of the current input CT3 (that is, normally 1A or 5A)

$CT Prim Input1$ is the rated primary CT current of the main CT connected to CT1 current input

$CT Prim Input3$ is the rated primary CT current of the main CT connected to CT3 current input

5. Check that the value of the product $0.15 \cdot I1 \cdot CT Prim Input1$ is bigger than the pre-set value of $OCTOperLev$. If it is not, increase current into CT1 input until this condition is satisfied and change current into input CT3 accordingly.
6. Set the phase angle of current I1 to 180° if both current inputs (that is, CT1 and CT3) have the same sign for entered configuration parameters $CT Prim Input1$ and $CT Prim Input3$ (that is, both positive or both negative). Otherwise set the phase angle of current I1 to 0°.
7. Inject these two currents into the IED. Differential function shall be stable. Write down the service values for incoming and differential currents for phase A. Differential current should be approximately 15% of the incoming current.
8. After pre-set time determined by parameter $tSlow OCT$, open CT condition shall be detected by the IED. The differential function will be blocked.
9. Check that open CT alarm contacts operate accordingly to the scheme wiring.
10. Check that open CT information is stored in the event list (if connected).
11. Switch off the currents.
12. Reset the open CT blocking in the reset menu of the local HMI.
13. Check that open CT reset information is stored in the event list.
14. Repeat the same test procedure for phases B and C.

10.2.1.6 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.2.1.7 Check of trip circuits and circuit breakers

The trip circuits are tested as part of the secondary/primary injection test.

Check that the circuit breakers associated with the IED protection scheme operate when the tripping IEDs are activated. The trip IEDs are conveniently activated by secondary injection to activate a suitable protection function.

10.3 Current protection

10.3.1 Four step phase overcurrent protection 3-phase output OC4PTOC (51_67)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.3.1.1 Verifying the settings

1. Connect the test set for current injection to the appropriate IED phases.
If there is any configuration logic that is used to enable or block any of the four available overcurrent steps, make sure that the step under test is enabled (for example, end fault protection).
If *1 out of 3* currents for operation is chosen: Connect the injection current to phases A and neutral.
If *2 out of 3* currents for operation is chosen: Connect the injection current into phase A and out from phase B.
If *3 out of 3* currents for operation is chosen: Connect the symmetrical three-phase injection current into phases A, B and C.
2. Connect the test set for the appropriate three-phase voltage injection to the IED phases A, B and C. The protection shall be fed with a symmetrical three-phase voltage.
3. Set the injected polarizing voltage slightly larger than the set minimum polarizing voltage (default is 5% of *VBase*) and set the injection current to lag the appropriate voltage by an angle of about 80° if forward directional function is selected.

- If *1 out of 3* currents for operation is chosen: The voltage angle of phase A is the reference.
- If *2 out of 3* currents for operation is chosen: The voltage angle of phase A – the voltage angle of B is the reference.
- If *3 out of 3* currents for operation is chosen: The voltage angle of phase A is the reference.
- If reverse directional function is selected, set the injection current to lag the polarizing voltage by an angle equal to 260° (equal to $80^\circ + 180^\circ$).
4. Increase the injected current and note the trip value of the tested step of the function.
 5. Decrease the current slowly and note the reset value.
 6. If the test has been performed by injection of current in phase A, repeat the test, injecting current into phases B and C with polarizing voltage connected to phases B, respectively C (*1 out of 3* currents for operation).
 7. If the test has been performed by injection of current in phases AB, repeat the test, injecting current into phases BC and CA with the appropriate phase angle of injected currents.
 8. Block higher set stages when testing lower set stages by following the procedure described below.
 9. Connect a trip output contact to a timer.
 10. Set the injected current to 200% of the operate level of the tested stage, switch on the current and check the time delay.
For inverse time curves, check the trip time at a current equal to 110% of the trip current for *txMin*.
 11. Check that all trip and pickup contacts operate according to the configuration (signal matrixes)
 12. Reverse the direction of the injected current and check that the protection does not operate.
 13. If *2 out of 3* or *3 out of 3* currents for operation is chosen: Check that the function will not trip with current in one phase only.
 14. Repeat the above described tests for the higher set stages.
 15. Finally check that pickup and trip information is stored in the event menu.



Verification of the non-directional phase overcurrent function is done as instructed above, without applying any polarizing voltage.

10.3.1.2

Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.2 Four step single phase overcurrent protection PH4SPTOC(51)

Prepare the IED for verification of settings outlined in section [""](#) and section ["Preparing for test"](#) in this chapter.

Directional phase overcurrent current function

10.3.2.1 Verifying the settings

Procedure

1. Connect the test set for appropriate current injection to the appropriate IED terminals.
If there is any configuration logic, which is used to enable or block any of 4 available overcurrent steps, make sure that step under test is enabled (that is, end fault protection).
2. Increase the injected current and note the operated value of the studied step of the function.
3. Decrease the current slowly and note the reset value.
4. Block higher set stages when testing lower set stages according to below.
5. Connect a trip output contact to a timer.
6. Set the injected current to 200% of the trip level of the tested stage, switch on the current and check the time delay.
For inverse time curves, check the trip time at a current equal to 110% of the trip current for t_{min} .
7. Check that all trip and pickup contacts operate according to the configuration (signal matrixes)
8. Repeat the above described tests for the higher set stages.
9. Finally check that pickup and trip information is stored in the event menu.

10.3.2.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.3 Four step residual overcurrent protection, (Zero sequence or negative sequence directionality) EF4PTOC (51N/67N)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.3.3.1 Four step directional ground fault protection

1. Connect the test set for single current injection to the appropriate IED terminals. Connect the injection current to terminals A and neutral.
2. Set the injected polarizing voltage slightly larger than the set minimum polarizing voltage (default 5% of V_n) and set the injection current to lag the voltage by an angle equal to the set reference characteristic angle (*AngleRCA*), if the forward directional function is selected.
If reverse directional function is selected, set the injection current to lag the polarizing voltage by an angle equal to $RCA + 180^\circ$.
3. Increase the injected current and note the value at which the studied step of the function operates.
4. Decrease the current slowly and note the reset value.
5. If the test has been performed by injection of current in phase A, repeat the test, injecting current into terminals B and C with a polarizing voltage connected to terminals B, respectively C.
6. Block lower set steps when testing higher set steps according to the instructions that follow.
7. Connect a trip output contact to a timer.
8. Set the injected current to 200% of the operate level of the tested step, switch on the current and check the time delay.
For inverse time curves, check the operate time at a current equal to 110% of the operate current for *txMin*.
9. Check that all trip and trip contacts operate according to the configuration (signal matrixes)
10. Reverse the direction of the injected current and check that the step does not operate.
11. Check that the protection does not operate when the polarizing voltage is zero.
12. Repeat the above described tests for the higher set steps.
13. Finally, check that pickup and trip information is stored in the event menu.

10.3.3.2 Four step non-directional ground fault protection

1. Do as described in ["Four step directional ground fault protection"](#), but without applying any polarizing voltage.

10.3.3.3 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.4 Four step negative sequence overcurrent protection NS4PTOC (46I2)

Prepare the IED for verification of settings as outlined in section [""](#) and section ["Preparing for test"](#) in this chapter.



When inverse time overcurrent characteristic is selected, the operate time of the stage will be the sum of the inverse time delay and the set definite time delay. Thus, if only the inverse time delay is required, it is of utmost importance to set the definite time delay for that stage to zero.

Procedure

1. Connect the test set for injection of three-phase currents and voltages to the appropriate CT and VT inputs of the IED.
2. Inject pure negative sequence current, that is, phase currents with exactly same magnitude, reversed sequence and exactly 120° phase displaced into the IED with an initial value below negative sequence current pickup level. No output signals should be activated. Check under NS4PTOC function Service Values that correct I2 magnitude is measured by the function.
3. Set the injected negative sequence polarizing voltage slightly larger than the set minimum polarizing voltage (default 5 % of V_n) and set the injection current to lag the voltage by an angle equal to the set reference characteristic angle ($180^\circ - AngleRCA$) if the forward directional function is selected.
If reverse directional function is selected, set the injection current to lag the polarizing voltage by an angle equal to RCA.
4. Increase the injected current and note the value at which the studied step of the function operates.
5. Decrease the current slowly and note the reset value.
6. Block lower set steps when testing higher set steps according to the instructions that follow.
7. Connect a trip output contact to a timer.
8. Set the injected current to 200% of the operate level of the tested step, switch on the current and check the time delay.
For inverse time curves, check the operate time at a current equal to 110% of the operate current in order to test parameter $txmin$.
9. Check that all trip and pickup contacts operate according to the configuration (signal matrixes)
10. Reverse the direction of the injected current and check that the step does not operate.
11. Check that the protection does not operate when the polarizing voltage is zero.
12. Repeat the above-described tests for the higher set steps.
13. Finally, check that pickup and trip information is stored in the event menu.

10.3.4.1 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.5 Thermal overload protection, two time constants TRPTTR (49)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.3.5.1 Checking operate and reset values

1. Connect symmetrical three-phase currents to the appropriate current terminals of the IED.
2. Set the Time constant 1 (*Tau1*) and Time Constant 2 (*Tau2*) temporarily to 1 minute.
3. Set the three-phase injection currents slightly lower than the set operate value of stage *IBase1*, increase the current in phase A until stage *IBase1* operates and note the operate value.



Observe the maximum permitted overloading of the current circuits in the IED.

4. Decrease the current slowly and note the reset value.
Check, in the same way, the operate and reset values of *IBase1* for phases B and C.
5. Activate the cooling input signal, thus switching to base current *IBase2*.
6. Check the operate and reset values (for all three phases) for *IBase2* in the same way as described above for stage *IBase1*.
7. Deactivate the input signal for stage *IBase2*.
8. Set the time constant for *IBase1* in accordance with the setting plan.
9. Set the injection current for phase A to $1.50 \cdot I_{Base1}$.
10. Connect a trip output contact to the timer and monitor the output of contacts ALARM1 and ALARM2 to digital inputs in test equipment.
Read the heat content in the thermal protection from the local HMI and wait until the content is zero.
11. Switch on the injection current and check that ALARM1 and ALARM2 contacts operate at the set percentage level and that the operate time for tripping is in accordance with the set Time Constant 1 (*Tau1*).
With setting $I_{tr} = 101\% I_{Base1}$ and injection current $1.50 \cdot I_{Base1}$, the trip time from zero content in the memory shall be $0.60 \cdot \text{Time Constant 1 (Tau1)}$.

12. Check that all trip and alarm contacts operate according to the configuration logic.
13. Switch off the injection current and check from the service menu readings of thermal status and LOCKOUT that the lockout resets at the set percentage of heat content.
14. Activate the cooling input signal to switch over to base current I_{Base2} .
Wait 5 minutes to empty the thermal memory and set Time Constant 2 ($Tau2$) in accordance with the setting plan.
15. Test with injection current $1.50 \cdot I_{Base2}$ the thermal alarm level, the operate time for tripping and the lockout reset in the same way as described for stage I_{Base1} .
16. Finally check that pickup and trip information is stored in the event menu.

10.3.5.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.6 Breaker failure protection, phase segregated activation and output CCRBRF (50BF)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

The Breaker failure protection, 3-phase activation and output function CCRBRF (50BF) should normally be tested in conjunction with some other function that provides an initiate signal. An external BFI_3P signal can also be used.

To verify the settings in the most common back-up trip mode *1 out of 3*, it is sufficient to test phase-to-ground faults.

At mode *2 out of 4* the phase current setting, *Pickup_PH* can be checked by single-phase injection where the return current is connected to the summated current input. The value of residual (ground fault) current *IN* set lower than *Pickup_PH* is easiest checked in back-up trip mode *1 out of 4*.

10.3.6.1 Checking the phase current operate value, *Pickup_PH*

The check of the *Pickup_PH* current level is best made in *FunctionMode = Current* and *BuTripMode = 1 out of 3* or *2 out of 4*.

1. Apply the fault condition, including BFI_3P of CCRBRF (50BF), with a current below set *Pickup_PH*.
2. Repeat the fault condition and increase the current in steps until a trip occurs.
3. Compare the result with the set *Pickup_PH*.
4. Disconnect AC and BFI_3P input signals.



Note! If *No CBPos Check* or *Retrip off* is set, only back-up trip can be used to check set *IP>*.

10.3.6.2 Checking the residual (ground fault) current operate value *Pickup_N* set below *Pickup_PH*

Check the low set *Pickup_N* current where setting *FunctionMode = Current* and setting *BuTripMode = 1 out of 4*

1. Apply the fault condition, including BFI_3P of CCRBRF (50BF), with a current just below set *Pickup_N*.
2. Repeat the fault condition and increase the current in steps until trip appears.
3. Compare the result with the set *Pickup_N*.
4. Disconnect AC and BFI_3P input signals.

10.3.6.3 Checking the re-trip and back-up times

The check of the set times can be made in connection with the check of operate values above.

Choose the applicable function and trip mode, such as *FunctionMode = Current* and *RetripMode = CB Pos Check*.

1. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value. Measure time from BFI_3P of CCRBRF (50BF).
2. Check the re-trip *t1* and back-up trip times *t2* and *t3*.
In applicable cases, the back-up trip for multi-phase pickup *t2MPH* and back-up trip 2, *t2* and *t3* can also be checked. To check *t2MPH*, a two-phase or three-phase initiation shall be applied.
3. Disconnect AC and BFI_3P input signals.

10.3.6.4 Verifying the re-trip mode

Choose the mode below, which corresponds to the actual case.

In the cases below it is assumed that *FunctionMode = Current* is selected.

Checking the case without re-trip, *RetripMode = Retrip Off*

1. Set *RetripMode = Retrip Off*.
2. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value.
3. Verify that no re-trip, but back-up trip is achieved after set time.
4. Disconnect AC and BFI_3P input signals.

Checking the re-trip with current check, *RetripMode = CB Pos Check*

1. Set *RetripMode = CB Pos Check*.
2. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value.
3. Verify that re-trip is achieved after set time $t1$ and back-up trip after time $t2$
4. Apply the fault condition, including initiation of CCRBRF (50BF), with current below set current value.
5. Verify that no re-trip, and no back-up trip is obtained.
6. Disconnect AC and BFI_3P input signals.

Checking re-trip without current check, *RetripMode = No CBPos Check*

1. Set *RetripMode = No CBPos Check*.
2. Apply the fault condition, including initiation of CCRBRF (50BF), well above the set current value.
3. Verify that re-trip is achieved after set time $t1$, and back-up trip after time $t2$.
4. Apply the fault condition, including initiation of CCRBRF (50BF), with current below set current value.
5. Verify that re-trip is achieved after set time $t1$, but no back-up trip is obtained.
6. Disconnect AC and BFI_3P input signals.

10.3.6.5

Verifying the back-up trip mode

In the cases below it is assumed that *FunctionMode = Current* is selected.

Checking that back-up tripping is not achieved at normal CB tripping

Use the actual tripping modes. The case below applies to re-trip with current check.

1. Apply the fault condition, including initiation of CCRBRF (50BF), with phase current well above set value $Pickup_{PH}$.
2. Interrupt the current, with a margin before back-up trip time, $t2$. It may be made at issue of re-trip command.
3. Check that re-trip is achieved, if selected, but no back-up trip is obtained.
4. Disconnect AC and BFI_3P input signals.

The normal mode $BuTripMode = 1$ out of 3 should have been verified in the tests above. In applicable cases the modes 1 out of 4 and 2 out of 4 can be checked. Choose the mode below, which corresponds to the actual case.

Checking the case $BuTripMode = 1$ out of 4

It is assumed that the ground-fault current setting $Pickup_N$ is below phase current setting $Pickup_{PH}$.

1. Set $BuTripMode = 1$ out of 4.
2. Apply the fault condition, including initiation of CCRBRF (50BF), with one-phase current below set $Pickup_{PH}$ but above $Pickup_N$. The residual ground-fault should then be above set $Pickup_N$.
3. Verify that back-up trip is achieved after set time. If selected, re-trip should also appear.
4. Disconnect AC and BFI_3P input signals.

Checking the case $BuTripMode = 2$ out of 4

The ground-fault current setting $Pickup_N$ may be equal to or below phase-current setting $Pickup_{PH}$.

1. Set $BuTripMode = 2$ out of 4.
2. Apply the fault condition, including initiation of CCRBRF (50BF), with one-phase current above set $Pickup_{PH}$ and residual (ground fault) above set $Pickup_N$.
3. Verify that back-up trip is achieved after set time. If selected, re-trip should also appear.
4. Apply the fault condition, including initiation of CCRBRF (50BF), with at least one-phase current below set $Pickup_{PH}$ and residual (ground fault) above set $Pickup_N$. The current may be arranged by feeding three- (or two-) phase currents with equal phase angle (I0-component) below $Pickup_{PH}$, but of such value that the residual (ground fault) current ($3I_0$) will be above set value $Pickup_N$.
5. Verify that back-up trip is not achieved.
6. Disconnect AC and BFI_3P input signals.

10.3.6.6 Verifying instantaneous back-up trip at CB faulty condition

Applies in a case where a signal from CB supervision function regarding CB being faulty and unable to trip is connected to input 52FAIL.

1. Repeat the check of back-up trip time. Disconnect current and input signals.
2. Activate the input 52FAIL. The output CBALARM (CB faulty alarm) should appear after set time $t_{CBAlarm}$. Keep the input activated.
3. Apply the fault condition, including initiation of CCRBRF (50BF), with current above set current value.
4. Verify that back-up trip is obtained without intentional delay, for example within 20ms from application of initiation.
5. Disconnect injected AC and BFI_3Pinput signals.

10.3.6.7 Verifying the case *RetripMode = Contact*

It is assumed that re-trip without current check is selected, *RetripMode = Contact*.

1. Set *FunctionMode = Contact*
2. Apply input signal for CB closed to relevant input or inputs 52a_A (B or C).
3. Apply input signal, or signals for initiation of CCRBRF (50BF).
4. Verify that phase selection re-trip and back-up trip are achieved after set times.
5. Disconnect the trip signal(s). Keep the CB closed signal(s).
6. Apply input signal(s), for initiation of CCRBRF (50BF).
7. Arrange disconnection of CB closed signal(s) well before set back-up trip time t_2 .
8. Verify that back-up trip is not achieved.
9. Disconnect injected AC and BFI_3P input signals.

10.3.6.8 Verifying the function mode *Current&Contact*

To be made only when *FunctionMode = Current&Contact* is selected. It is suggested to make the tests in one phase only, or at three-pole trip applications for just three-pole tripping.

Checking the case with fault current above set value Pickup_PH

The operation shall be as in *FunctionMode = Current*.

1. Set *FunctionMode = Current&Contact*.
2. Leave the inputs for CB close inactivated. These signals should not influence.
3. Apply the fault condition, including initiation of CCRBRF (50BF), with current above the set *Pickup_PH* value.
4. Check that the re-trip, if selected, and back-up trip commands are achieved.
5. Disconnect injected AC and BFI_3P input signals.

Checking the case with fault current below set value Pickup_BlkCont

The case shall simulate a case where the fault current is very low and operation will depend on CB position signal from CB auxiliary contact. It is suggested that re-trip without current check is used, setting *RetripMode = No CBPos Check*.

1. Set *FunctionMode = Current&Contact*.
2. Apply input signal for CB closed to relevant input or inputs 52a_A (B or C)
3. Apply the fault condition with input signal(s) for initiation of CCRBRF (50BF). The value of current should be below the set value *Pickup_BlkCont*
4. Verify that phase selection re-trip (if selected) and back-up trip are achieved after set times. Failure to trip is simulated by keeping the signal(s) CB closed activated.
5. Disconnect the AC and the BFI_3P signal(s). Keep the CB closed signal(s).
6. Apply the fault and the initiation again. The value of current should be below the set value *Pickup_BlkCont*.
7. Arrange disconnection of BC closed signal(s) well before set back-up trip time *t2*. It simulates a correct CB tripping.
8. Verify that back-up trip is not achieved. Re-trip can appear for example, due to selection "Re-trip without current check".
9. Disconnect injected AC and BFI_3P input signals.

10.3.6.9

Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.7

Breaker failure protection, single phase version CCSRBRF (50BF)

Prepare the IED for verification of settings as outlined in section [""](#) and section ["Preparing for test"](#) in this chapter.

The breaker failure protection, single phase version function CCSRBRF (50BF) should normally be tested in conjunction with some other function that provides a BFI signal. An external BFI signal can also be used.

CCSRBRF (50BF) has to be set and configured before the testing can start. CCSRBRF (50BF) is highly flexible in that it permits a choice of functional and tripping modes. The various modes are checked at the factory as part of the design verification. In certain cases only modes with a high probability of coming into operation need to be checked, in order to verify the configuration and settings.

Testing requirements

- Calculated settings
- Valid configuration diagram for the IED
- Valid terminal diagram for the IED
- Technical reference manual
- Single phase test equipment

The technical reference manual contains application and functionality summaries, function blocks, logic diagrams, input and output signals, a list of setting parameters and technical data for the function.

The test equipment should be able to provide a single phase supply of currents. The magnitude of currents should be possible to vary.

Make sure the IED is prepared for test before starting the test session. Consider the logic diagram of the function when performing the test. The response from a test can be viewed in different ways:

- Binary output signals
- Service values in the local HMI (logical signal or phasors)
- A PC with PCM600 (configuration software) in debug mode

10.3.7.1

Checking the phase current operate value Pickup_{PH}

Procedure

1. Apply the fault condition, including BFI of CCSRBRF (50BF), with a current below set *Pickup_{PH}*.
2. Repeat the fault condition and increase the current in steps until a trip occurs.
3. Compare the result with the set *Pickup_{PH}*.
4. Disconnect the AC and initiate input signals.



Note! If “No CBPos Check” or “Retrip off” is set, only back-up trip can be used to check set *Pickup_{PH}*.

10.3.7.2

Checking the re-trip and back-up times

The check of the set times can be made in connection with the check of operate values above. Choose the applicable function and trip mode, such as *FunctMode = Current* and *RetripMode = CB Pos Check* .

Procedure

1. Apply the fault condition, including BFI of CCSRBRF (50BF), well above the set current value. Measure time from “Start of CCSRBRF (50BF)”.
2. Check the re-trip $t1$ and back-up trip times $t2$ and $t3$
3. Disconnect AC and initiate input signals.

10.3.7.3

Verifying the re-trip mode

Choose the mode below, which corresponds to the actual case. In the cases below it is assumed that *FunctionMode = Current* is selected.

Checking the case without re-trip, *RetripMode = Retrip Off*

Procedure

1. Set *RetripMode = Retrip Off*.
2. Apply the fault condition, including BFI of CCSRBRF, well above the set current value.
3. Verify that no re-trip, but back-up trip is achieved after set time.
4. Disconnect AC and initiate input signals.

Checking the re-trip with current check, *RetripMode = CB Pos Check*

Procedure

1. Set *RetripMode = CB Pos Check*.
2. Apply the fault condition, including BFI of CCSRBRF (50BF), well above the set current value.
3. Verify that retrip is achieved after set time $t1$ and back-up trip after time $t2$
4. Apply the fault condition, including BFI of CCSRBRF (50BF), with current below set current value.
5. Verify that no re-trip, and no back-up trip is obtained.
6. Disconnect AC and initiate input signals.

Checking re-trip without current check, *RetripMode = No CBPos Check*

Procedure

1. Set *RetripMode = No CBPos Check*.
2. Apply the fault condition, including BFI of CCSRBRF (50BF), well above the set current value.
3. Verify that re-trip is achieved after set time $t1$, and back-up trip after time $t2$.
4. Apply the fault condition, including BFI of CCSRBRF (50BF), with current below set current value.
5. Verify that re-trip is achieved after set time $t1$, but no back-up trip is obtained.
6. Disconnect AC and initiate input signals.

10.3.7.4 Verifying the back-up trip mode

In the cases below it is assumed that *FunctionMode = Current* is selected.

Checking that back-up tripping is not achieved at normal CB tripping

Use the actual tripping modes. The case below applies to re-trip with current check.

Procedure

1. Apply the fault condition, including BFI of CCSRBRF (50BF), with phase current well above set value *Pickup_PH*.
2. Arrange switching the current off, with a margin before back-up trip time, *t2*. It may be made at issue of re-trip command.
3. Check that re-trip is achieved, if selected, but no back-up trip.
4. Disconnect AC and initiate input signals.

10.3.7.5 Verifying instantaneous back-up trip at “CB faulty” condition

Applies in a case where signal “CB faulty and unable to trip” is connected to input 52FAIL.

Procedure

1. Repeat the check of back-up trip time. Disconnect current and BFI input signals.
2. Activate the input 52FAIL. The output CBALARM (CB faulty alarm) should appear after set time *tCBAlarm*. Keep the input activated.
3. Apply the fault condition, including BFI of CCSRBRF (50BF), with current above set current value.
4. Verify that back-up trip is obtained without intentional delay, for example, within 20ms from application of BFI.
5. Disconnect injected AC and input signals.

10.3.7.6 Verifying the case *FunctionMode = Contact*

It is assumed that re-trip without current check is selected, *RetripMode = No CBPos Check*.

Procedure

1. Set *FunctionMode = Contact*.
2. Apply input signal for CB closed to relevant input or inputs 52a
3. Apply input signal, or signals for BFI of CCSRBRF (50BF). The value of current could be low.
4. Verify that re-trip and back-up trip are achieved after set times.

5. Disconnect the BFI signal(s). Keep the CB closed signal(s).
6. Apply input signal(s), for BFI of CCSRBRF. The value of current could be low.
7. Arrange disconnection of CB closed signal(s) well before set back-up trip time $t2$.
8. Verify that back-up trip is not achieved.
9. Disconnect injected AC and BFI input signals.

10.3.7.7

Verifying the function mode *Curr&Cont Check*

To be made only when *FunctionMode = Current&Contact* is selected. It is suggested to make the tests in one phase only, or at three-pole trip applications for just three-pole tripping.

Checking the case with fault current above set value

The operation shall be as in *FunctionMode = Current*.

Set

RetripMode = CB Pos Check .

Procedure

1. Set *FunctionMode = Current/Contact*.
2. Leave the input for CB close inactivated. This signal should not influence. Leave the inputs for CB close inactivated. These signals should not influence.
3. Apply the fault condition, including BFI of CCSRBRF (50BF), with current above the set *Pickup_PH* value.
4. Check that the re-trip, if selected, and back-up trip commands are achieved.
5. Disconnect injected AC and BFI input signals.

Checking the case with fault current below set value

The case shall simulate a case where the fault current is very low and operation will depend on CB position signal from CB auxiliary contact. It is suggested that re-trip without current check is used; setting *RetripMode = No CBPos Check*.

Procedure

1. Set *FunctionMode = Current/Contact*.
2. Apply input signal for CB closed to relevant input 52a. Apply input signal for CB closed to relevant input or inputs 52a.
3. Apply the fault condition with input signal(s) for BFI of CCSRBRF 50BF. The value of current should be below the set value *Pickup_BlckCont*
4. Verify that re-trip (if selected) and back-up trip are achieved after set times. Failure to trip is simulated by keeping the signal CB closed activated. Failure to trip is simulated by keeping the signals CB closed activated.

5. Disconnect the AC and the BFI signals. Keep the CB closed signal. Disconnect the AC and the BFI signals. Keep the CB closed signals.
6. Apply the fault and the BFI again. The value of current should be below the set value *Pickup_BlkJCont*
7. Arrange disconnection of BC closed signal well before set back-up trip time *t2*. Arrange disconnection of BC closed signals well before set back-up trip time *t2*. It simulates a correct CB tripping.
8. Verify that back-up trip is not achieved. Re-trip can appear, for example, due to selection *RetripMode = No CBPos Check*.
9. Disconnect injected AC and BFI input signals.

10.3.7.8 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.8 Directional underpower protection GUPPDUP (37)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.3.8.1 Verifying the settings

The underpower protection shall be set to values according to the real set values to be used.

The test is made by means of injection of voltage and current where the amplitude of both current and voltage and the phase angle between the voltage and current can be controlled. During the test, the analog outputs of active and reactive power shall be monitored.

1. Connect the test set for injection of voltage and current corresponding to the mode to be used in the application. If a three-phase test set is available this could be used for all the modes. If a single-phase current/voltage test set is available the test set should be connected to a selected input for one-phase current and voltage.

Table 12: Calculation modes

Set value: Mode	Formula used for complex power calculation
A, B, C	$\bar{S} = \bar{V}_A \cdot \bar{I}_A^* + \bar{V}_B \cdot \bar{I}_B^* + \bar{V}_C \cdot \bar{I}_C^*$ <p style="text-align: right;">(Equation 4)</p>
Arone	$\bar{S} = \bar{V}_{AB} \cdot \bar{I}_A^* - \bar{V}_{BC} \cdot \bar{I}_C^*$ <p style="text-align: right;">(Equation 5)</p>
PosSeq	$\bar{S} = 3 \cdot \bar{V}_{PosSeq} \cdot \bar{I}_{PosSeq}^*$ <p style="text-align: right;">(Equation 6)</p>
AB	$\bar{S} = \bar{V}_{AB} \cdot (\bar{I}_A^* - \bar{I}_B^*)$ <p style="text-align: right;">(Equation 7)</p>
BC	$\bar{S} = \bar{V}_{BC} \cdot (\bar{I}_B^* - \bar{I}_C^*)$ <p style="text-align: right;">(Equation 8)</p>
CA	$\bar{S} = \bar{V}_{CA} \cdot (\bar{I}_C^* - \bar{I}_A^*)$ <p style="text-align: right;">(Equation 9)</p>
A	$\bar{S} = 3 \cdot \bar{V}_A \cdot \bar{I}_A^*$ <p style="text-align: right;">(Equation 10)</p>
B	$\bar{S} = 3 \cdot \bar{V}_B \cdot \bar{I}_B^*$ <p style="text-align: right;">(Equation 11)</p>
C	$\bar{S} = 3 \cdot \bar{V}_C \cdot \bar{I}_C^*$ <p style="text-align: right;">(Equation 12)</p>

- Adjust the injected current and voltage to the set values in % of I_{Base} and V_{Base} (converted to secondary current and voltage). The angle between the injected current and voltage shall be set equal to the set direction *Angle1*, angle for stage 1 (equal to 0° for low forward power protection and equal to 180° for reverse

- power protection). Check that the monitored active power is equal to 100% of rated power and that the reactive power is equal to 0% of rated power.
3. Change the angle between the injected current and voltage to $Angle1 + 90^\circ$. Check that the monitored active power is equal to 0% of rated power and that the reactive power is equal to 100% of rated power.
 4. Change the angle between the injected current and voltage back to 0° . Decrease the current slowly until the PICKUP1 signal, pickup of stage 1, is activated.
 5. Increase the current to 100% of I_{Base} .
 6. Switch the current off and measure the time for activation of TRIP1, trip of stage 1.
 7. If a second stage is used, repeat steps [2](#) to [6](#) for the second stage.

10.3.8.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.9 Directional overpower protection GOPPDOP (32)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.3.9.1 Verifying the settings

The overpower protection shall be set to values according to the real set values to be used. The test is made by means of injection of voltage and current where the amplitude of both current and voltage and the phase angle between the voltage and current can be controlled. During the test the analog outputs of active and reactive power shall be monitored.

1. Connect the test set for injection of voltage and current corresponding to the mode to be used in the application. If a three phase test set is available this could be used for all the modes. If a single phase current/voltage test set is available the test set should be connected to a selected input for one phase current and voltage.
2. Adjust the injected current and voltage to the set rated values in % of I_{Base} and V_{Base} (converted to secondary current and voltage). The angle between the injected current and voltage shall be set equal to the set direction $Angle1$, angle for stage 1 (equal to 0° for low forward power protection and equal to 180° for

- reverse power protection). Check that the monitored active power is equal to 100% of rated power and that the reactive power is equal to 0% of rated power.
3. Change the angle between the injected current and voltage to $Angle1 + 90^\circ$. Check that the monitored active power is equal to 0% of rated power and that the reactive power is equal to 100% of rated power.
 4. Change the angle between the injected current and voltage back to $Angle1$ value. Increase the current slowly from 0 until the PICKUP1 signal, pickup of stage 1, is activated. Check the injected power and compare it to the set value $Power1$, power setting for stage 1 in % of $Sbase$.
 5. Increase the current to 100% of $Ibase$ and switch the current off.
 6. Switch the current on and measure the time for activation of TRIP1, trip of stage 1.
 7. If a second stage is used, repeat steps [2](#) to [6](#) for the second stage.

10.3.9.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.3.10 Capacitor bank protection CBPGAPC

Prepare the IED for verification of settings as outlined in section ["Preparing for test"](#) in this chapter.

In this section it is shown how to test the capacitor bank protection function CBPGAPC for application on a 50Hz, 200MVar, 400kV SCB with 500/1A ratio CT.



Note that such SCB is shown in the application manual for this function. The same procedure can be used to test SCB with some other rating and different CT ratio.

As calculated in the application manual the base current for this particular SCB will be 289A on the primary side and 0.578A on the CT secondary side. Before any testing is commenced make sure that setting *Ibase* for this function is set to 289A (that is, setting for the base current corresponds to the rated current of the protected SCB). It will be also assumed that all other settings have values as shown in the setting example in the application manual for this SCB.

Test equipment

Connect the secondary test set to the CT inputs on the IED dedicated for the SCB currents. Single- or three-phase test equipment can be used but it may be required to have facility to vary the frequency of the injected current signal(s).

10.3.10.1

Verifying the settings and operation of the function

Reconnection inhibit feature

1. Inject SCB rated current (that is, 0.587A at 50Hz for this SCB) in at least one phase (preferably perform this test with three phase injection).
2. After couple of seconds stop injection of all currents (that is, set all currents back to 0A).
3. Check that function binary output signal RECINH is set to logical 1 and that only resets after the set time under parameter *tReconnInhibit* (for example 300s for this SCB) has expired.
4. If this binary signal is used to prevent CB closing make sure that it is properly connected/wired into the CB closing circuit.

Overcurrent feature



Note that during testing the overcurrent feature the harmonic voltage overload feature or reactive power overload feature may also give pickup and trip signals depending on their actual settings. Therefore it is best to switch them off during this test.

1. Inject current 20% bigger than the set overcurrent pickup level under setting parameter *PU 51* (for example, $1.2 \cdot 1.35 \cdot 0.587A = 0.951A$ at 50Hz for this SCB) in phase A only.
2. Check that function binary output signals *PU_51_A* and *PU_OC* are set to one.
3. Check that function binary output signals *TROC* and *TRIP* are set to one after the set time under parameter *tOC* (that is, 30s for this SCB) has expired.
4. If any of these signals are used for tripping, signaling and/or local/remote indication check that all relevant contacts and LEDs have operated and that all relevant GOOSE messages have been sent.
5. Check that service value from the function for current in phase A, on the local HMI under **Main menu/Test** is approximately 476A (that is, $0.951A \cdot (500/1) = 476A$).
6. Stop injection of all currents (that is, set all currents back to 0A).
7. Check that all above mentioned function binary output signals now have logical value zero.
8. Repeat above steps 1-7 for phase B and phase C.



Note that the operation of this feature is based on current peak value. That means that this overcurrent function is also able to operate for the same current magnitude but for different injected frequencies. If required repeat this injection procedure for example for the 3rd

harmonic by just simply injecting $3 \cdot 50 = 150\text{Hz}$ currents with the same magnitude. Obtain results shall be the same.

Undercurrent feature

1. Inject SCB rated current (that is, 0.587A at 50Hz for this SCB) in all three phases.
2. Lower phase A current 10% under the set value for setting parameter PU_37 (that is, $0.9 \cdot 0.7 \cdot 0.587\text{A} = 0.370\text{A}$ at 50Hz for this SCB).
3. Check that function binary output signals PU_37_A and PU_UC are set to one.
4. Check that function binary output signals $TRUC$ and $TRIP$ are set to one after the set time under parameter tUC (for example, 5s for this SCB) has expired.
5. If any of these signals are used for tripping, signaling and/or local/remote indication check that all relevant contacts and LEDs have operated and that all relevant GOOSE messages have been sent.
6. Check that service value from the function for current in phase A, on the local HMI under **Main menu/Test** is approximately 185A (that is, $0.370\text{A} \cdot (500/1) = 185\text{A}$).
7. Stop injection of all currents (that is, set all currents back to 0A).
8. Check that all above mentioned function binary output signals now have logical value zero because they will be automatically blocked by operation of built-in reconnection inhibit feature.
9. Repeat above steps 1-8 for phase B and phase C.

Reactive power overload feature



Note that during testing the reactive power overload feature the harmonic voltage overload feature or overcurrent feature may also give pickup and trip signals depending on their actual settings. Therefore it is recommended to switch them off during this test.

1. Inject current equal to the set reactive power overload pickup level under setting parameter UP_QOL (that is, $1.3 \cdot 0.587\text{A} = 0.763\text{A}$ at 50Hz for this SCB) in phase A only.
2. Check that function binary output signals PU_QOL_A and PU_QOL are set to one.
3. Check that function binary output signals $TRQOL$ and $TRIP$ are set to one after the set time under parameter $tQOL$ (for example, 60s for this SCB) has expired.
4. If any of these signals are used for tripping, signaling and/or local/remote indication check that all relevant contacts and LEDs have operated and that all relevant GOOSE messages have been sent.

5. Check that service value from the function for current in phase A, on the local HMI under **Main menu/Test** is approximately 382A (that is, $0.763A \cdot (500/1) = 382A$).
6. Check that service value from the function for reactive power in phase A, on the local HMI under **Main menu/Test** is approximately 169% (that is, $1.3 \cdot 1.3 = 1.69pu = 169\%$).
7. Stop injection of all currents (that is, set all currents back to 0A).
8. Check that all above mentioned function binary output signals now have logical value zero.
9. Repeat above steps 1 - 8 for phase B and phase C.



Note that operation of this feature is based on injected current and internally calculated true RMS values. That means that this feature is also able to operate for current signals with varying frequency. However due to relatively complex calculation procedure it is recommended to do secondary tests only with fundamental frequency current signals.

The following formula can be used to calculate SCB reactive power in per-unit system when current with different frequency from the rated frequency is injected.

$$Q[pu] = \frac{f_{rated}}{f_{injected}} \cdot I^2 [pu]$$

(Equation 13)

Harmonic voltage overload feature



Note that during testing the harmonic voltage overload feature the reactive power overload feature or overcurrent feature may also give pickup and trip signals depending on their actual settings. Therefore it is recommended to switch them off during this test.

Procedure to test inverse time delayed step:

The following points on the inverse curve are defined per relevant IEC/ANSI standards for time multiplier value set to $k_{HOL_IDMT}=1.0$

UpeakRMS [pu]	1.15	1.2	1.3	1.4	1.7	2.0	2.2
Time [s]	1800	300	60	15	1	0.3	0.12



Note that operation of this feature is based on internally calculated voltage peak RMS value. That means that this feature is also able to operate for current signals with varying frequency.

Here will be shown how to test the fourth point from the above table. Other points can be tested in the similar way:

1. Inject 140% of the base current (that is, $1.4 \cdot 0.587A = 0.822A$ at 50Hz for this SCB) in phase A only.
2. Check that function binary output signals PU_HOL_IDMT_A and PU_HOL are set to one.
3. Check that function binary output signals TRHOL and TRIP are set to one after the expected time (for example, 15s for this voltage level in accordance with the above table) has expired.
4. If any of these signals are used for tripping, signaling and/or local/remote indication, check that all relevant contacts and LEDs have operated and that all relevant GOOSE messages have been sent.
5. Check that service value for current in phase A, on the local HMI under **Main menu/Test** is approximately 411A (that is, $0.822A \cdot (500/1) = 411A$).
6. Check that service value for voltage across SCB in phase A, on the local HMI under **Main menu/Test** is approximately 140%.
7. Stop injection of all currents (that is, set all currents back to 0A).
8. Check that all above mentioned function binary output signals now have logical value zero.
9. Repeat above steps 1 - 8 for phase B and phase C.
10. Repeat above steps 1 - 8 to test different points from the above table.

Operation of this feature is based on internally calculated peak RMS voltage value. That means that this feature is also able to operate for current signals with varying frequency. Note that for the fundamental frequency injection, internally calculated voltage in percent corresponds directly to the injected current value given in percent. However if it is required to test IDMT characteristic with a varying frequency, the magnitude of the injected current must be adjusted accordingly. The following formula can be used to calculate required current RMS value in percent at the desired injection frequency in order to archive voltage percentage value given in the above table:

$$I_{inj} [\%] = \frac{f_{injected}}{f_{rated}} \cdot V [\%]$$

(Equation 14)



Note that it is recommended to test IDMT operating times by injected current with the rated frequency.

Above procedure can also be used to test definite time step. Pay attention that IDMT step can also operate during such injection. Therefore make sure that appropriate settings are entered in order to insure correct test results for definite time step.

10.3.10.2 Completing the test

Continue to test another functions or end the test by changing the Test mode setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes. Make sure that all built-in features for this function, which shall be in operation, are enabled and with correct settings.

10.4 Voltage protection

10.4.1 Two step undervoltage protection UV2PTUV (27)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.4.1.1 Verifying the settings

Verification of PICKUP value and time delay to operate for Step 1

1. Check that the IED settings are appropriate, especially the PICKUP value, the definite time delay and the *1 out of 3* operation mode.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly decrease the voltage in one of the phases, until the PICKUP signal appears.
4. Note the operate value and compare it with the set value.



The operate value in secondary volts is calculated according to the following equations:

For phase-to-ground measurement:

$$\frac{V_{pickup}}{100} < \frac{V_{Base}}{\sqrt{3}} \times \frac{VT_{sec}}{VT_{prim}}$$

(Equation 15)

For phase-to-phase measurement:

$$\frac{V_{pickup}}{100} < V_{Base} \times \frac{VT_{sec}}{VT_{prim}}$$

(Equation 16)

5. Increase the measured voltage to rated load conditions.
6. Check that the PICKUP signal resets.
7. Instantaneously decrease the voltage in one phase to a value about 20% lower than the measured operate value.
8. Measure the time delay for the TRIP signal, and compare it with the set value.
9. Check the inverse time delay by injecting a voltage corresponding to $0.8 \times V_{pickup<}$.



For example, if the inverse time curve A is selected, the trip signals TRST1 and TRIP operate after a time corresponding to the equation:

$$t(s) = \frac{TD1}{\left(1 - \frac{V}{V_{pickup<}}\right)}$$

(Equation 17)

where:

t(s)	Operate time in seconds
TD1	Settable time multiplier of the function for step 1
V	Measured voltage
Vpickup<	Set pickup voltage for step 1

For example, if the measured voltage jumps from the rated value to 0.8 times the set pickup voltage level and time multiplier TD1 is set to 0.05 s (default value), then the TRST1 and TRIP signals operate at a time equal to 0.250 s ± tolerance.

10. The test above can be repeated to check the inverse time characteristic at different voltage levels.
11. Repeat the above-described steps for Step 2 of the function.

Extended testing

The tests above can be repeated for *2 out of 3* and for *3 out of 3* operation mode.

10.4.1.2

Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.4.2 Two step overvoltage protection OV2PTOV (59)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.4.2.1 Verifying the settings

Verification of single-phase voltage and time delay to operate for Step 1

1. Apply single-phase voltage below the set value *Pickup1*.
2. Slowly increase the voltage until the PU_ST1 signal appears.
3. Note the operate value and compare it with the set value.



The operate value in secondary volts is calculated according to the following equations:

For phase-to-ground measurement:

$$\frac{V_{pickup >}}{100} \times \frac{V_{Base}}{\sqrt{3}} \times \frac{VT_{sec}}{VT_{prim}}$$

(Equation 18)

For phase-to-phase measurement:

$$\frac{V_{pickup >}}{100} \times V_{Base} \times \frac{VT_{sec}}{VT_{prim}}$$

(Equation 19)

4. Decrease the voltage slowly and note the reset value.
5. Set and apply about 20% higher voltage than the measured operate value for one phase.
6. Measure the time delay for the TRST1 signal and compare it with the set value.
7. Check the inverse time delay by injecting a voltage corresponding to $1.2 \times V_{pickup >}$.



For example, if the inverse time curve A is selected, the trip signals TRST1 and TRIP operate after a time corresponding to the equation:

$$t(s) = \frac{TD1}{\left(\frac{V}{V_{pickup >}} - 1\right)}$$

(Equation 20)

where:

t(s)	Operate time in seconds
TD1	Settable time multiplier of the function for step 1
V	Measured voltage
Vpickup>	Set pickup voltage for step 1

For example, if the measured voltage jumps from 0 to 1.2 times the set pickup voltage level and time multiplier TD1 is set to 0.05 s (default value), then the TRST1 and TRIP signals operate at a time equal to 0.250 s ± tolerance.

8. The test above can be repeated to check the inverse time characteristic at different voltage levels.
9. Repeat the above-described steps for Step 2 of the function.

10.4.2.2 Extended testing

1. The tests above can be repeated for *2 out of 3* and for *3 out of 3* operation mode.

10.4.2.3 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.4.3 Two step residual overvoltage protection ROV2PTOV (59N)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.4.3.1 Verifying the settings

1. Apply the single-phase voltage either to a single-phase voltage input or to a residual voltage input with the pickup value below the set value *Pickup1*.
2. Slowly increase the value until PU_ST1 appears.
3. Note the operate value and compare it with the set value.
4. Decrease the voltage slowly and note the reset value.
5. Set and apply about 20% higher voltage than the measured operate value for one phase.

6. Measure the time delay for the TRST1 signal and compare it with the set value.
7. Check the inverse time delay by injecting a voltage corresponding to $1.2 \times V_{pickup}$.



For example, if the inverse time curve A is selected, the trip signals TRST1 and TRIP operate after a time corresponding to the equation:

$$t(s) = \frac{TD1}{\left(\frac{V}{V_{pickup}} - 1\right)}$$

(Equation 21)

where:

t(s)	Operate time in seconds
TD1	Settable time multiplier of the function for step 1
V	Measured voltage
Vpickup>	Set pickup voltage for step 1

For example, if the measured voltage jumps from 0 to 1.2 times the set pickup voltage level and time multiplier TD1 is set to 0.05 s (default value), then the TRST1 and TRIP signals operate at a time equal to 0.250 s ± tolerance.

8. Repeat the test for Step 2 of the function.

10.4.3.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.4.4 Voltage differential protection VDCPTOV (60)

Prepare the IED for verification of settings as outlined in section [""](#) and section ["Preparing for test"](#) in this chapter.

10.4.4.1 Check of undervoltage levels

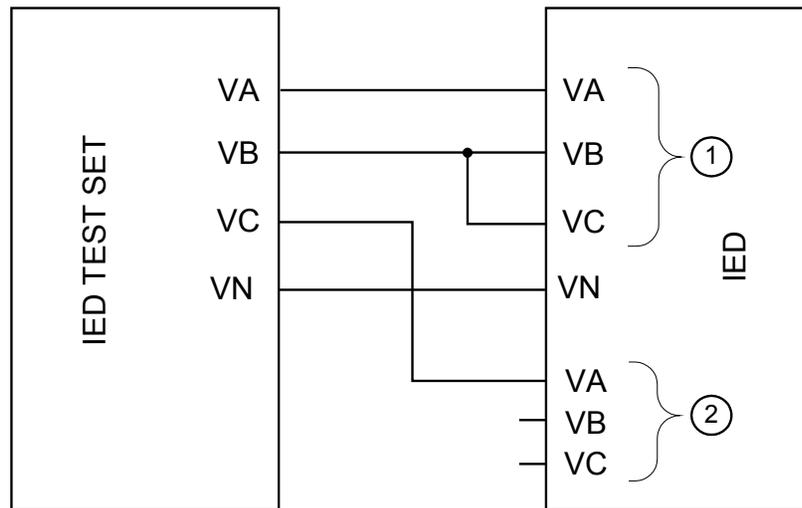
This test is relevant if the setting *BlkDiffAtVLow* = *Yes*.

Check of $V1Low$

Procedure

1. Connect voltages to the IED according to valid connection diagram and figure 16.
2. Apply voltage higher than the highest set value of $VDTrip$, $V1Low$ and $V2Low$ to the V1 three-phase inputs and to one phase of the V2 inputs according to figure 16.

The voltage differential PICKUP signal is set.



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Figure 16: Connection of the test set to the IED for test of $V1$ block level

where:

- 1 is three-phase voltage group1 (V1)
- 2 is three-phase voltage group2 (V2)

3. Decrease slowly the voltage in phase VA of the test set until the PICKUP signal resets.
4. Check V1 blocking level by comparing the voltage level at reset with the set undervoltage blocking $V1Low$.
5. Repeat steps 2 to 4 to check $V1Low$ for the other phases.

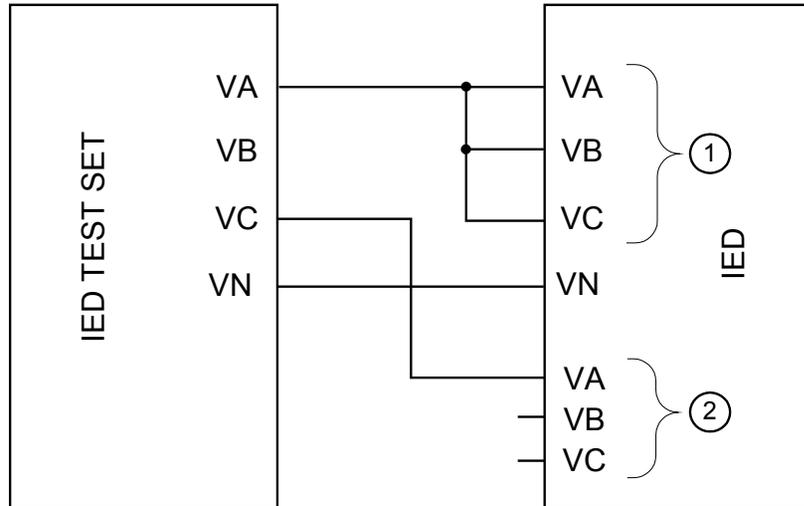


The connections to V1 must be shifted to test another phase. (VA to VB, VB to VC, VC to VA)

Check of V2Low

Procedure

1. Connect voltages to the IED according to valid connection diagram and figure 17.



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Figure 17: Connection of the test set to the IED for test of V2 block level

where:

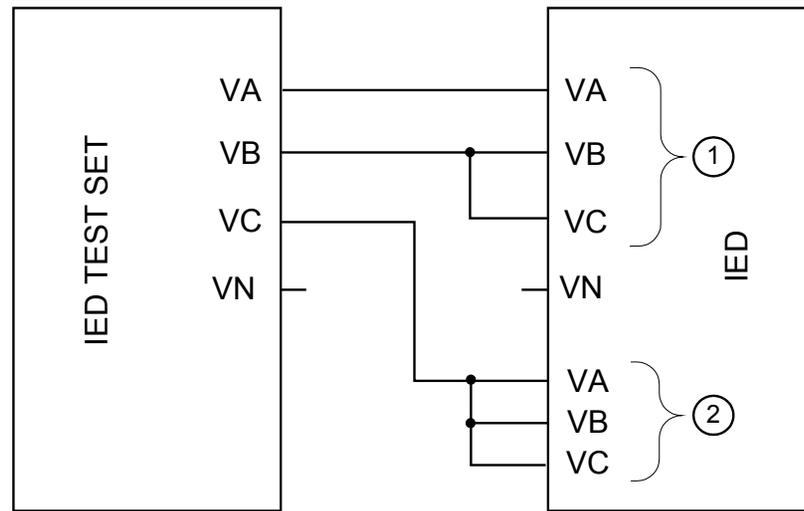
- 1 is three-phase voltage group1 (V1)
- 2 is three-phase voltage group2 (V2)

2. Apply voltage higher than the highest set value of $VDTrip$, $VILow$ and $V2Low$ to the V1 three-phase inputs and to one phase of the V2 inputs according to figure 17.
The voltage differential PICKUP signal is set.
3. Decrease slowly the voltage in phase VC of the test set until the PICKUP signal resets.
4. Check V2 blocking level by comparing the voltage level at reset with the set undervoltage blocking $V2Low$.

10.4.4.2**Check of voltage differential trip and alarm levels**

Procedure

1. Connect voltages to the IED according to valid connection diagram and figure 18.



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Figure 18: Connection of the test set to the IED for test of alarm levels, trip levels and trip timer

where:

- 1 is three-phase voltage group1 (V1)
- 2 is three-phase voltage group2 (V2)

2. Apply $1.2 \cdot V_n$ (rated voltage) to the V1 and V2 inputs.
3. Decrease slowly the voltage of in phase VA of the test set until the ALARM signal is activated.



The ALARM signal is delayed with timer t_{Alarm}

4. Check the alarm operation level by comparing the differential voltage level at ALARM with the set alarm level VD_{Alarm} .
5. Continue to slowly decrease the voltage until PICKUP signal is activated.
6. Check the differential voltage operation level by comparing the differential voltage level at PICKUP with the set trip level VD_{Trip} .
7. Repeat steps 1 to 6 to check the other phases.
Observe that the connections to V1 must be shifted to test another phase. (VA to VB, VB to VC, VC to VA)

10.4.4.3 Check of trip and trip reset timers

Procedure

1. Connect voltages to the IED according to valid connection diagram and figure [18](#).
2. Set V_n (rated voltage) to the V1 inputs and increase V2 voltage until differential voltage is $1.5 \cdot$ operating level (VD_{Trip}).
3. Switch on the test set. Measure the time from activation of the PICKUP signal until TRIP signal is activated.
4. Check the measured time by comparing it to the set trip time t_{Trip} .
5. Increase the voltage until PICKUP signal resets. Measure the time from reset of PICKUP signal to reset of TRIP signal.
6. Check the measured time by comparing it to the set trip reset time t_{Reset} .

10.4.4.4 Final adjustment of compensation for VT ratio differences

Procedure

1. With the protection in test mode, view the differential voltage service values in each phase on the local HMI under **Main menu/Test/Function status/Voltage protection/VoltageDiff(PTOV,60)/VDCPTOV:x**.



The IED voltage inputs should be connected to the VTs according to valid connection diagram.

2. Record the differential voltages.
3. Calculate the compensation factor RF_x for each phase.
For information about calculation of the compensation factor, see the application manual.
4. Set the compensation factors on the local HMI under **Main menu/Settings/Settings group N/Voltage protection/VoltageDiff(PTOV,60)/VDCPTOV:x**
5. Check that the differential voltages are close to zero.

10.4.4.5 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.4.5 Loss of voltage check LOVPTUV (27)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.4.5.1 Measuring the operate limit of set values

1. Check that the input logical signals BLOCK, CBOPEN and BLKU are logical zero.
2. Supply a three-phase rated voltage in all three phases and note on the local HMI that the TRIP logical signal is equal to the logical 0.
3. Switch off the voltage in all three phases.
After set t_{Trip} time a TRIP signal appears on the corresponding binary output or on the local HMI.



Note that TRIP at this time is a pulse signal, duration should be according to set t_{Pulse} .

4. Inject the measured voltages at rated values for at least set $t_{Restore}$ time.
5. Activate the CBOPEN binary input.
6. Simultaneously disconnect all the three-phase voltages from the IED.
No TRIP signal should appear.
7. Inject the measured voltages at rated values for at least set $t_{Restore}$ time.
8. Activate the BLKU binary input.
9. Simultaneously disconnect all the three-phase voltages from the IED.
No TRIP signal should appear.
10. Reset the BLKU binary input.
11. Inject the measured voltages at rated values for at least set $t_{Restore}$ time.
12. Activate the BLOCK binary input.
13. Simultaneously disconnect all the three-phase voltages from the IED.
No TRIP signal should appear.
14. Reset the BLOCK binary input.

10.4.5.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.5 Frequency protection

10.5.1 Underfrequency protection SAPTUF (81)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.5.1.1 Verifying the settings

Verification of PICKUP value and time delay to trip

1. Check that the IED settings are appropriate, for example the PICKUP value and the time delay.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly decrease the frequency of the applied voltage, until the PICKUP signal appears.
4. Note the trip value and compare it with the set value.
5. Increase the frequency until rated operating levels are reached.
6. Check that the PICKUP signal resets.
7. Instantaneously decrease the frequency of the applied voltage to a value about 1% lower than the trip value (a step change more than 2% will increase the time delay).
8. Measure the time delay of the TRIP signal, and compare it with the set value. Note that the measured time consists of the set value for time delay plus minimum trip time of the pickup start function (80 - 90 ms).

Extended testing

1. The test above can be repeated to check the time to reset.
2. The tests above can be repeated to test the frequency dependent inverse time characteristic.

Verification of the low voltage magnitude blocking

1. Check that the IED settings are appropriate, for example the *PUFrequency*, *VMin*, and the *tDelay*.
2. Supply the IED with three-phase voltages at rated values.
3. Slowly decrease the magnitude of the applied voltage, until the BLKDMAGN signal appears.
4. Note the voltage magnitude value and compare it with the set value *VMin*.

5. Slowly decrease the frequency of the applied voltage, to a value below *PUFrequency*.
6. Check that the PICKUP signal does not appear.
7. Wait for a time corresponding to *tDelay*, make sure that the TRIP signal does not appear.

10.5.1.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.5.2 Overfrequency protection SAPTOF (81)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.5.2.1 Verifying the settings

Verification of PICKUP value and time delay to trip

1. Check that the settings in the IED are appropriate, for example the PICKUP value and the time delay.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly increase the frequency of the applied voltage, until the PICKUP signal appears.
4. Note the trip value and compare it with the set value.
5. Decrease the frequency to rated operating conditions.
6. Check that the PICKUP signal resets.
7. Instantaneously increase the frequency of the applied voltage to a value about 1% lower than the trip value (a step change more than 2% will increase the time delay).
8. Measure the time delay for the TRIP signal, and compare it with the set value. Note that the measured time consists of the set value for time delay plus minimum trip time of the pickup function (80 - 90 ms).

Extended testing

1. The test above can be repeated to check the time to reset.

Verification of the low voltage magnitude blocking

1. Check that the settings in the IED are appropriate, for example the *PUFrequency*, *VMin*, and the *tDelay*.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly decrease the magnitude of the applied voltage, until the BLKDMAGN signal appears.
4. Note the voltage magnitude value and compare it with the set value, *VMin*.
5. Slowly increase the frequency of the applied voltage, to a value above *PUFrequency*.
6. Check that the PICKUP signal does not appear.
7. Wait for a time corresponding to *tDelay*, make sure that the TRIP signal does not appear.

10.5.2.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.5.3 Rate-of-change frequency protection SAPFRC (81)

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

10.5.3.1 Verifying the settings

PICKUP value and time delay to operate

1. Check that the settings in the IED are appropriate, especially the PICKUP value and the definite time delay. Set *PickupFreqgrad*, to a rather small negative value.
2. Supply the IED with three-phase voltages at their rated values.
3. Slowly decrease the frequency of the applied voltage, with an increasing rate-of-change that finally exceeds the setting of *PickupFreqgrad*, and check that the PICKUP signal appears.
4. Note the operate value and compare it with the set value.
5. Increase the frequency to rated operating conditions, and zero rate-of-change.
6. Check that the PICKUP signal resets.
7. Instantaneously decrease the frequency of the applied voltage to a value about 20% lower than the nominal value.
8. Measure the time delay for the TRIP signal, and compare it with the set value.

Extended testing

1. The test above can be repeated to check a positive setting of *PickupFreqGrad*.
2. The tests above can be repeated to check the time to reset.
3. The tests above can be repeated to test the RESTORE signal, when the frequency recovers from a low value.

10.5.3.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.6 Multipurpose protection

10.6.1 General current and voltage protection CVGAPC

Prepare the IED for verification of settings as outlined in section [""](#) and section ["Preparing for test"](#) in this chapter.

One of the new facilities within the general current and voltage protection function CVGAPC is that the value, which is processed and used for evaluation in the function, can be chosen in many different ways by the setting parameters *CurrentInput* and *VoltageInput*.

These setting parameters decide what kind of preprocessing the connected three-phase CT and VT inputs shall be subjected to. That is, for example, single-phase quantities, phase-to-phase quantities, positive sequence quantities, negative sequence quantities, maximum quantity from the three-phase group, minimum quantity from the three-phase group, difference between maximum and minimum quantities (unbalance) can be derived and then used in the function.

Due to the versatile possibilities of CVGAPC itself, but also the possibilities of logic combinations in the application configuration of outputs from more than one CVGAPC function block, it is hardly possible to define a fully covering general commissioning test.

10.6.1.1 Built-in overcurrent feature (non-directional)

Procedure

1. Go to **Main menu/Test/Function test modes/Multipurpose protection/GeneralCurrentVoltage(GAPC)/CVGAPC:x** and make sure that CVGAPC to

be tested is unblocked and other functions that might disturb the evaluation of the test are blocked.

2. Connect the test set for injection of three-phase currents to the appropriate current terminals of the IED in the 670 series.
3. Inject current(s) in a way that relevant measured current (according to setting parameter *CurrentInput*) is created from the test set. Increase the current(s) until the low set stage operates and check against the set operate value.
4. Decrease the current slowly and check the reset value.
5. Block high set stage if the injection current will activate the high set stage when testing the low set stage according to below.
6. Connect a TRIP output contact to the timer.
7. Set the current to 200% of the operate value of low set stage, switch on the current and check the time delay.
For inverse time curves, check the operate time at a current equal to 110% of the operate current at $t_{MinTripDelay}$.
8. Check that TRIP and PICKUP contacts operate according to the configuration logic.
9. Release the blocking of the high set stage and check the operate and reset value and the time delay for the high set stage in the same way as for the low set stage.
10. Finally check that PICKUP and TRIP information is stored in the event menu.



Information on how to use the event menu is found in the operator's manual.

10.6.1.2

Overcurrent feature with current restraint

The current restraining value has also to be measured or calculated and the influence on the operation has to be calculated when the testing of the operate value is done.

Procedure

1. Operate value measurement
The current restraining value has also to be measured or calculated and the influence on the operation has to be calculated when the testing of the operate value is done.

10.6.1.3

Overcurrent feature with voltage restraint

Procedure

1. Connect the test set for injection of three-phase currents and three-phase voltages to the appropriate current and voltage terminals of the IED.
2. Inject current(s) and voltage(s) in a way that relevant measured (according to setting parameter *CurrentInput* and *VoltageInput*) currents and voltages are created from the test set.
Overall check in principal as above (non-directional overcurrent feature)
3. Operate value measurement
The relevant voltage restraining value (according to setting parameter *VoltageInput*) has also to be injected from the test set and the influence on the operate value has to be calculated when testing of the operate value is done.
4. Operate time measurement
Definite times may be tested as above (non-directional overcurrent feature). For inverse time characteristics the PICKUP value (to which the overcurrent ratio has to be calculated) is the actual pickup value as got with actual restraining from the voltage restraining quantity.

10.6.1.4

Overcurrent feature with directionality

Please note that the directional characteristic can be set in two different ways either just dependent on the angle between current and polarizing voltage (setting parameter *DirPrinc_OC1* or *DirPrinc_OC2* set to or in a way that the operate value also is dependent on the angle between current and polarizing voltage according to the $I \cdot \cos(\Phi)$ law (setting parameter *DirPrinc_OC1* or *DirPrinc_OC2* set to $I \cdot \cos(\Phi)$). This has to be known if a more detailed measurement of the directional characteristic is made, than the one described below.

Procedure

1. Connect the test set for injection of three-phase currents and three-phase voltages to the appropriate current and voltage terminals of the IED.
2. Inject current(s) and voltage(s) in a way that relevant measured (according to setting parameter *CurrentInput* and *VoltageInput*) currents and voltages are created from the test set.
3. Set the relevant measuring quantity current to lag or lead (lag for negative RCA angle and lead for positive RCA angle) the relevant polarizing quantity voltage by an angle equal to the set IED characteristic angle (*rca-dir*) when forward directional feature is selected and the *CTWYEpoint* configuration parameter is set to *ToObject*.
If reverse directional feature is selected or *CTWYEpoint* configuration parameter is set to *FromObject*, the angle between current and polarizing voltage shall be set equal to $rca-dir+180^\circ$.

4. Overall check in principal as above (non-directional overcurrent feature)
5. Reverse the direction of the injection current and check that the protection does not operate.
6. Check with low polarization voltage that the feature becomes non-directional, blocked or with memory according to the setting.

10.6.1.5 Over/Undervoltage feature

Procedure

1. Connect the test set for injection three-phase voltages to the appropriate voltage terminals of the IED.
2. Inject voltage(s) in a way that relevant measured (according to setting parameter *VoltageInput*) voltages are created from the test set.
3. Overall check in principal as above (non-directional overcurrent feature) and correspondingly for the undervoltage feature.

10.6.1.6 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.7 Secondary system supervision

10.7.1 Fuse failure supervision FUFSPVC

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

The verification is divided in two main parts. The first part is common to all fuse failure supervision options, and checks that binary inputs and outputs operate as expected according to actual configuration. In the second part the relevant set operate values are measured.

10.7.1.1 Checking that the binary inputs and outputs operate as expected

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.
2. Connect the nominal dc voltage to the 89bS binary input.

-
- The signal BLKV should appear with almost no time delay.
 - The signals BLKZ and 3PH should not appear on the IED.
 - Only the distance protection function can operate.
 - Undervoltage-dependent functions must not operate.
3. Disconnect the dc voltage from the 89b binary input terminal.
 4. Connect the nominal dc voltage to the MCBOP binary input.
 - The BLKV and BLKZ signals should appear without any time delay.
 - All undervoltage-dependent functions must be blocked.
 5. Disconnect the dc voltage from the MCBOP binary input terminal.
 6. Disconnect one of the phase voltages and observe the logical output signals on the binary outputs of the IED.

BLKV and BLKZ signals should appear simultaneously whether the BLKV and BLKZ reset depends on the setting *SealIn* “on” or “off”. If “on” no reset, if “off” reset.
 7. After more than 5 seconds disconnect the remaining two-phase voltages and all three currents.
 - There should be no change in the high status of the output signals BLKV and BLKZ.
 - The signal 3PH will appear.
 8. Establish normal voltage and current operating conditions simultaneously and observe the corresponding output signals.

They should change to logical 0 as follows:

 - Signal 3PH after about 25ms
 - Signal BLKV after about 50ms
 - Signal BLKZ after about 200ms

10.7.1.2

Measuring the operate value for the negative sequence function

Measure the operate value for the negative sequence function, if included in the IED.

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.
2. Slowly decrease the measured voltage in one phase until the BLKV signal appears.
3. Record the measured voltage and calculate the corresponding negative-sequence voltage according to the equation (observe that the voltages in the equation are phasors):

$$3 \cdot \overline{V}_2 = \overline{V}_A + a^2 \cdot \overline{V}_B + a \cdot \overline{V}_C$$

(Equation 22)

Where:

 $\overline{V}_A, \overline{V}_B$ and \overline{V}_C are the measured phase voltages

$$a = 1 \cdot e^{j \frac{2\pi}{3}} = -0.5 + j \frac{\sqrt{3}}{2}$$

4. Compare the result with the set value of the negative-sequence operating voltage (consider that the set value $3V2PU$ is in percentage of the base voltage $VBase$).
5. Repeat steps [1](#) and [2](#). Then slowly increase the measured current in one phase until the BLKV signal disappears.
6. Record the measured current and calculate the corresponding negative-sequence current according to the equation (observe that the currents in the equation are phasors):

$$3 \cdot \overline{I}_2 = \overline{I}_A + a^2 \cdot \overline{I}_B + a \cdot \overline{I}_C$$

(Equation 25)

Where:

 $\overline{I}_A, \overline{I}_B$ and \overline{I}_C are the measured phase currents

$$a = 1 \cdot e^{j \frac{2\pi}{3}} = -0.5 + j \frac{\sqrt{3}}{2}$$

7. Compare the result with the set value of the negative-sequence operating current. Consider that the set value $3I2<$ is in percentage of the base current $IBase$.

10.7.1.3

Measuring the operate value for the zero-sequence function

Measure the operate value for the zero-sequence function, if included in the IED.

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.
2. Slowly decrease the measured voltage in one phase until the BLKV signal appears.
3. Record the measured voltage and calculate the corresponding zero-sequence voltage according to the equation (observe that the voltages in the equation are phasors):

$$3 \cdot \overline{V_0} = \overline{V_A} + \overline{V_B} + \overline{V_C}$$

(Equation 28)

Where:

$$\overline{V_A}, \overline{V_B} \text{ and } \overline{V_C}$$

are the measured phase voltages

4. Compare the result with the set value of the zero-sequence operating voltage (consider that the set value $3V0Pickup$ is in percentage of the base voltage.)
5. Repeat steps [1](#) and [2](#). Then slowly increase the measured current in one phase until the BLKV signal disappears.
6. Record the measured current and calculate the corresponding zero-sequence current according to the equation (observe that the currents in the equation are phasors):

$$3 \cdot \overline{I_0} = \overline{I_A} + \overline{I_B} + \overline{I_C}$$

(Equation 30)

Where:

$$\overline{I_A}, \overline{I_B} \text{ and } \overline{I_C}$$

are the measured phase currents

7. Compare the result with the set value of the zero-sequence operating current. Consider that the set value $3I0<$ is in percentage of the base current I_{Base} .

10.7.1.4

Measuring the operate value for the dead line detection function

1. Apply three-phase voltages with their rated value and zero currents.
2. Decrease the measured voltage in one phase until the DLD1PH signal appears.
3. This is the point at which the dead line condition is detected. Check the value of the decreased voltage with the set value V_{DLDPU} (V_{DLDPU} is in percentage of the base voltage V_{Base}).
4. Apply three-phase currents with their rated value and zero voltages.
5. Decrease the measured current in one phase until the DLD1PH signal appears.
6. This is the point at which the dead line condition is detected. Check the value of the decreased current with the set value I_{DLDPU} (I_{DLDPU} is in percentage of the base current I_{Base}).

10.7.1.5 Checking the operation of the dv/dt and di/dt based function

Check the operation of the dv/dt and di/dt based function if included in the IED.

1. Simulate normal operating conditions with the three-phase currents in phase with their corresponding phase voltages and with all of them equal to their rated values.
2. Change the voltages and currents in all three phases simultaneously.
The voltage change must be higher than the set value *DVPU* and the current change must be lower than the set value *DIPU*.
 - The BLKV and BLKZ signals appear without any time delay. The BLKZ signal will be activated only if the internal deadline detection is not activated at the same time.
 - 3PH should appear after 5 seconds, if the remaining voltage levels are lower than the set *VDLDPU* of the dead line detection function.
3. Apply normal conditions as in step [1](#).
The BLKV, BLKZ and 3PH signals should reset, if activated, see step [1](#) and [2](#).
4. Change the voltages and currents in all three phases simultaneously.
The voltage change must be higher than the set value *DVPU* and the current change must be higher than the set value *DIPU*.
The BLKV, BLKZ and 3PH signals should not appear.
5. Repeat step [2](#).
6. Connect the nominal voltages in all three phases and feed a current below the operate level in all three phases.
7. Keep the current constant. Disconnect the voltage in all three phases simultaneously.
The BLKV, BLKZ and 3PH signals should not appear.
8. Change the magnitude of the voltage and current for phase 1 to a value higher than the set value *DVPU* and *DIPU*.
9. Check that the pickup output signals PU_DV_A and PU_DI_A and the general pickup signals PU_DV or PU_DI are activated.
10. Check that the pickup output signals for the current and voltage phases 2 and 3 are activated by changing the magnitude of the voltage and current for phases 2 and 3.

10.7.1.6 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.7.2 Fuse failure supervision

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

Checking the operation of binary input and output

1. Simulate normal operation conditions with three-phase voltage on the main fuse group and the pilot fuse group. Ensure the values are equal to their rated values.
2. Disconnect one of the phase voltage from the main fuse group or the pilot fuse group. Observe the binary outputs of the IED. The MAINFUF or the PILOTFUF signals are simultaneously activated. Only the output circuit related to the open phase will be active i.e either MAINFUF or PILOTFUF.
3. Establish a normal voltage operating condition and observe the corresponding output signals. MAINFUF or PILOTFUF should change to 0 in about 27 ms.
4. Set normal conditions as mentioned in step 1.
5. Enable the BLOCK binary input and repeat step 2. MAINFUF or PILOTFUF should not appear.

Checking the operation of MAINFUF and PILOTFUF

1. Simulate normal operation conditions with three-phase voltage on the main fuse group and the pilot fuse group. Ensure the values are equal to their rated values.
2. Decrease one of the three-phase voltages on main fuse group or pilot fuse group. The voltage change must be greater than the set value for *Vdif Main block* or *Vdif Pilot alarm*. MAINFUF or PILOTFUF signals are activated without any time delay.
3. Set normal conditions as mentioned in step 1. MAINFUF or PILOTFUF signals should reset.
4. Set *SealIn* to On, *Vdif Main block* to 20% of *VBase* and *VSealIn* to 70% of *VBase*.
5. Apply three-phase voltages with the value slightly below *VSealIn* level.
6. Decrease one of the three-phase voltages on main fuse group. The voltage change must be greater than the set value for *Vdif Main block*. MAINFUF signal is activated.
7. After more than 5 seconds increase the measured voltage back to the value slightly below *VSealIn* level. MAINFUF signal should not reset.
8. Slowly increase measured voltage to the value slightly above *VSealIn* until MAINFUF signal resets.
9. Record the measured voltage and compare with the set value *VSealIn*.

10.7.2.1

Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.8 Control

10.8.1 Synchrocheck, energizing check, and synchronizing SESRSYN (25)

This section contains instructions on how to test the synchrocheck/synchronism check, energizing check, and synchronizing function SESRSYN (25) for single, double and breaker-and-a-half arrangements.

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

At commissioning and periodical checks, the functions shall be tested with the used settings. To test a specific function, it might be necessary to change some setting parameters, for example:

- *AutoEnerg* = *Disabled/DLLB/DBLL/Both*
- *ManEnerg* = *Disabled*
- *Operation* = *Disabled/Enabled*
- Activation of the voltage selection function if applicable

The tests explained in the test procedures below describe the settings, which can be used as references during testing before the final settings are specified. After testing, restore the equipment to the normal or desired settings.

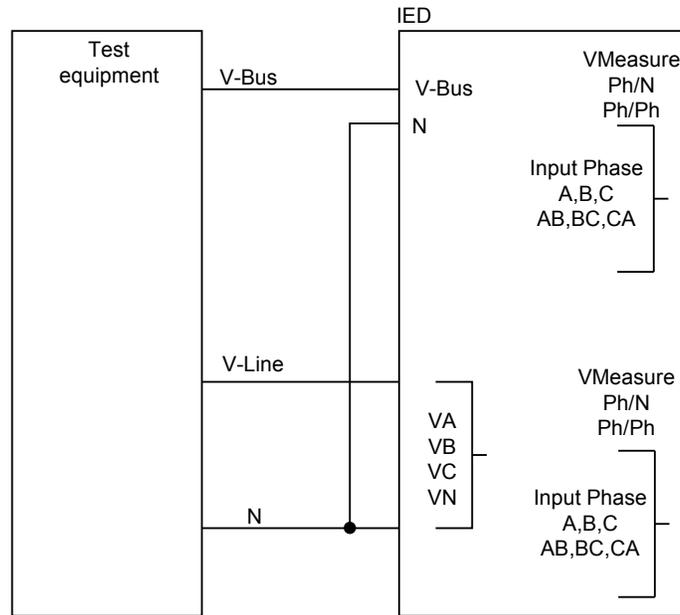
A secondary injection test set with the possibility to alter the phase angle and amplitude of the voltage is needed. The test set must also be able to generate different frequencies on different outputs.



The description below applies for a system with a nominal frequency of 60 Hz but can be directly applicable to 50 Hz. SESRSYN (25) can be set to use different phases, phase to ground or phase to phase. Use the set voltages instead of what is indicated below.

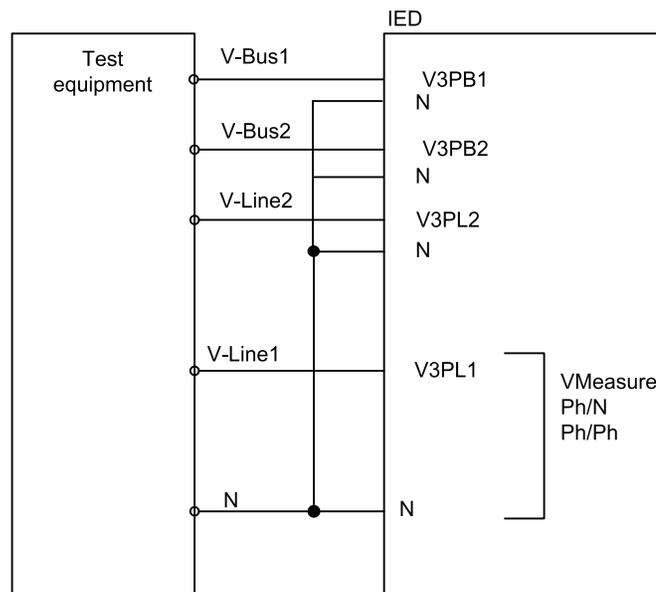
Figure [19](#) shows the general test connection principle, which can be used during testing. This description describes the test of the version intended for one bay.

Figure [20](#) shows the general test connection for a breaker-and-a-half diameter with one-phase voltage connected to the line side.



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Figure 19: General test connection with three-phase voltage connected to the line side



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Figure 20: General test connection for a breaker-and-a-half diameter with one-phase voltage connected to the line side

10.8.1.1 Testing the synchronizing function

The voltage inputs used are:

V3PL1	VA, VB or VC line 1 voltage inputs on the IED
V3PBB1	Bus1 voltage input on the IED

Testing the frequency difference

The frequency difference test should verify that operation is achieved when the frequency difference between bus and line is less than set value of *FreqDiffMax* and above set value of *FreqDiffMin*. The test procedure below will depend on the settings used. Input STARTSYN must be activated during the test.

$$FreqDiffMax = 50.2 \text{ Hz}$$

$$FreqDiffMin = 50.01 \text{ Hz}$$

$$tBreaker = 0.080 \text{ s}$$

1. Apply voltages
 - 1.1. V-Line = 100% *VBaseLine* and f-Line = 60.0 Hz
 - 1.2. V-Bus = 100% *VBaseBus* and f-Bus = 60.15Hz
2. Check that a closing pulse is submitted at a closing angle equal to calculated phase angle value from the formula below. Modern test sets will evaluate this automatically.

$$\text{Closing Angle} = |((f_{Bus} - f_{Line}) * tBreaker * 360 \text{ degrees})|$$

f_{Bus} = Bus frequency
 f_{Line} = Line frequency
 $tBreaker$ = Set closing time of the breaker
3. Repeat with
 - 3.1. V-Bus = 100% *VBaseBus* and f-bus = 60.25 Hz, to verify that the function does not operate when frequency difference is above limit.
4. Verify that the closing command is not issued when the frequency difference is less than the set value *FreqDiffMin*.

10.8.1.2 Testing the synchrocheck check

During the test of SESRSYN (25) for a single bay arrangement, these voltage inputs are used:

V-Line	VA, VB or VC line 1 voltage input on the IED according to the connection in SMT
V-Bus	V5 voltage input on the IED according to the connection in SMT

Testing the voltage difference

Set the voltage difference to 0.15 p.u. on the local HMI, and the test should check that operation is achieved when the voltage difference $VDiffSC$ is lower than 0.15 p.u.

The settings used in the test shall be final settings. The test shall be adapted to site setting values instead of values in the example below.

Test with no voltage difference between the inputs.

Test with a voltage difference higher than the set $VDiffSC$.

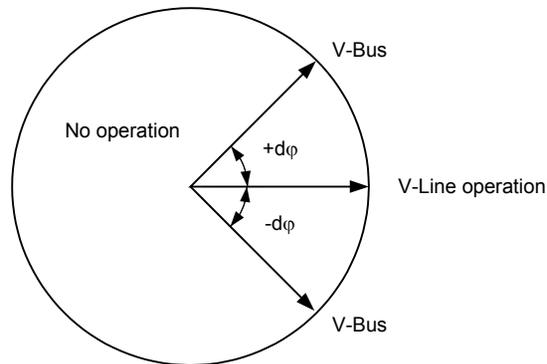
1. Apply voltages V-Line (for example) = 80% $GblBaseSelLine$ and V-Bus = 80% $GblBaseSelBus$ with the same phase-angle and frequency.
2. Check that the AUTOSYOK and MANSYOK outputs are activated.
3. The test can be repeated with different voltage values to verify that the function operates within the set $VDiffSC$. Check with both V-Line and V-Bus respectively lower than the other.
4. Increase the V-Bus to 110% $GblBaseSelBus$, and the V-Line = 90% $GblBaseSelLine$ and also the opposite condition.
5. Check that the two outputs for manual and auto synchronism are not activated.

Testing the phase angle difference

The phase angle differences $PhaseDiffM$ and $PhaseDiffA$ respectively are set to their final settings and the test should verify that operation is achieved when the phase angle difference is lower than this value both leading and lagging.

Test with no voltage difference.

1. Apply voltages V-Line (for example) = 100% $GblBaseSelLine$ and V-Bus = 100% $GblBaseSelBus$, with a phase difference equal to 0 degrees and a frequency difference lower than $FreqDiffA$ and $FreqDiffM$.
2. Check that the AUTOSYOK and MANSYOK outputs are activated.
The test can be repeated with other phase difference values to verify that the function operates for values lower than the set ones, $PhaseDiffM$ and $PhaseDiffA$. By changing the phase angle on the voltage connected to V-Bus, between $\pm d\phi$ degrees, the user can check that the two outputs are activated for a phase difference lower than the set value. It should not operate for other values. See figure [21](#).



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Figure 21: Test of phase difference

3. Change the phase angle between $+d\phi$ and $-d\phi$ and verify that the two outputs are activated for phase differences between these values but not for phase differences outside, see figure 21.

Testing the frequency difference

The frequency difference test should verify that operation is achieved when the *FreqDiffA* and *FreqDiffM* frequency difference is lower than the set value for manual and auto synchronizing check, *FreqDiffA* and *FreqDiffM* respectively and that operation is blocked when the frequency difference is greater.

Test with frequency difference = 0 mHz

Test with a frequency difference outside the set limits for manual and auto synchronizing check respectively.

1. Apply voltages V-Line equal to 100% *GblBaseSelLine* and V-Bus equal to 100% *GblBaseSelBus*, with a frequency difference equal to 0 mHz and a phase difference lower than the set value.
2. Check that the AUTOSYOK and MANSYOK outputs are activated.
3. Apply voltage to the V-Line equal to 100% *GblBaseSelLine* with a frequency equal to 50 Hz and voltage V-Bus equal to 100% *GblBaseSelBus*, with a frequency outside the set limit.
4. Check that the two outputs are not activated. The test can be repeated with different frequency values to verify that the function operates for values lower than the set ones. If a modern test set is used, the frequency can be changed continuously.

Testing the reference voltage

1. Use the same basic test connection as in figure 19.

- The voltage difference between the voltage connected to V-Bus and V-Line should be 0%, so that the AUTOSYOK and MANSYOK outputs are activated first.
2. Change the V-Line voltage connection to V-Line2 without changing the setting on the local HMI. Check that the two outputs are not activated.

10.8.1.3 Testing the energizing check

During the test of the energizing check function for a single bay arrangement, these voltage inputs are used:

V-Line	VA, VB or VC line1 voltage inputs on the IED
V-Bus	Bus voltage input on the IED

General

When testing the energizing check function for the applicable bus, arrangement shall be done for the energizing check functions. The voltage is selected by activation of different inputs in the voltage selection logic.

Live voltage level is fixed to 80% *VBase* and dead voltage level to fixed 40% *VBase*.

The test shall be performed according to the settings for the station. Test the alternatives below that are applicable.

Testing the dead line live bus (DLLB)

The test should verify that the energizing check function operates for a low voltage on the V-Line and for a high voltage on the V-Bus. This corresponds to the energizing of a dead line to a live bus.

1. Apply a single-phase voltage 100% *GblBaseSelBus* to the V-Bus, and a single-phase voltage 30% *GblBaseSelLine* to the V-Line.
2. Check that the AUTOENOK and MANENOK outputs are activated after set *tAutoEnerg* respectively *tManEnerg*.
3. Increase the V-Line to 60% *GblBaseSelLine* and V-Bus to be equal to 100% *GblBaseSelBus*. The outputs should not be activated.
4. The test can be repeated with different values on the V-Bus and the V-Line.

Testing the dead bus live line (DBLL)

The test should verify that the energizing check function operates for a low voltage on the V-Bus and for a high voltage on the V-Line. This corresponds to an energizing of a dead bus to a live line.

1. Verify the settings *AutoEnerg* or *ManEnerg* to be *DBLL*.
2. Apply a single-phase voltage of 30% *GblBaseSelBus* to the V-Bus and a single-phase voltage of 100% *GblBaseSelLine* to the V-Line.
3. Check that the AUTOENOK and MANENOK outputs are activated after set *tAutoEnerg* respectively *tManEnerg*.
4. Decrease the V-Line to 60% *GblBaseSelLine* and keep the V-Bus equal to 30% *GblBaseSelBus*. The outputs should not be activated.
5. The test can be repeated with different values on the V-Bus and the V-Line.

Testing both directions (DLLB or DBLL)

1. Verify the local HMI settings *AutoEnerg* or *ManEnerg* to be *Both*.
2. Apply a single-phase voltage of 30% *GblBaseSelLine* to the V-Line and a single-phase voltage of 100% *GblBaseSelBus* to the V-Bus.
3. Check that the AUTOENOK and MANENOK outputs are activated after set *tAutoEnerg* respectively *tManEnerg*.
4. Change the connection so that the V-Line is equal to 100% *GblBaseSelLine* and the V-Bus is equal to 30% *GblBaseSelBus*. The outputs should still be activated.
5. The test can be repeated with different values on the V-Bus and the V-Line.

Testing the dead bus dead line (DBDL)

The test should verify that the energizing check function operates for a low voltage on both the V-Bus and the V-Line, that is, closing of the breaker in a non-energized system. Test is valid only when this function is used.

1. Verify the local HMI setting *AutoEnerg* to be *Disabled* and *ManEnerg* to be *DBLL*.
2. Set the parameter *ManEnergDBDL* to *Enabled*.
3. Apply a single-phase voltage of 30% *GblBaseSelBus* to the V-Bus and a single-phase voltage of 30% *GblBaseSelLine* to the V-Line.
4. Check that the MANENOK output is activated after set *tManEnerg*.
5. Increase the V-Bus to 80% *GblBaseSelBus* and keep the V-Line equal to 30% *GblBaseSelLine*. The outputs should not be activated.
6. Repeat the test with *ManEnerg* set to *DLLB* with different values on the V-Bus and the V-Line voltage.

10.8.1.4

Testing the voltage selection

Testing the voltage selection for single CB arrangements

This test should verify that the correct voltage is selected for the measurement in the SESRSYN function used in a double-bus arrangement. Apply a single-phase voltage of 100% *GblBaseSelLine* to the V-Line and a single-phase voltage of 100% *GblBaseSelBus* to the V-Bus.

If the VB1/2OK inputs for the fuse failure are used, they must be activated, during tests below. Also verify that deactivation prevents operation and gives an alarm.

1. Connect the signals above to binary inputs and binary outputs.
2. Connect the voltage inputs to the analog inputs used for each bus or line depending of the type of busbar arrangement and verify that correct output signals are generated.

Testing the voltage selection for double breaker

This test should verify that correct voltage is selected for the measurement in the SESRSYN function used for a diameter in a Breaker-and-a-half arrangement. Apply a single-phase voltage of 100% *GblBaseSelLine* to the V-Line and a single-phase voltage of 100% *GblBaseSelBus* to the V-Bus. Verify that correct output signals are generated.

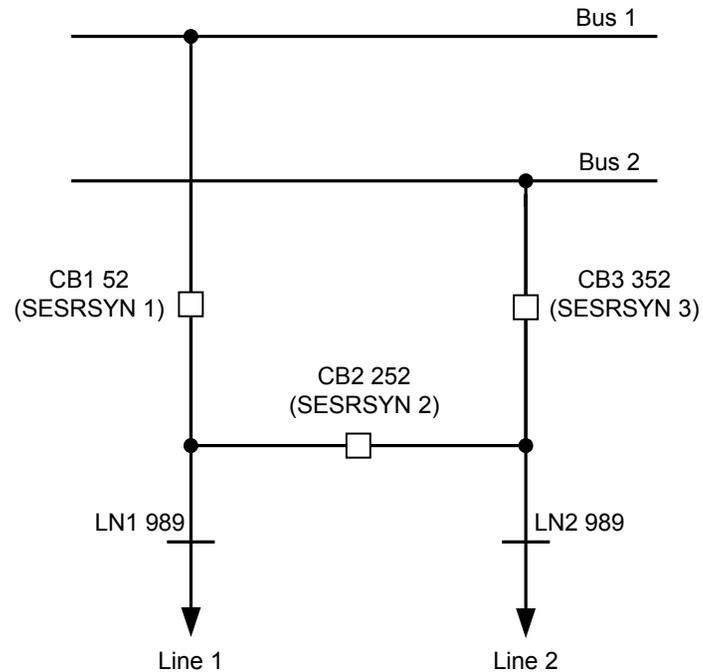
1. Connect the analog signals to the voltage inputs, in pair of two for V1 and V2. (Inputs V3PB1, V3PB2, V3PL1, V3PL2)
2. Activate the binary signals according to the used alternative. Verify the measuring voltage on the synchronizing check function SESRSYN (25). Normally it can be good to verify synchronizing check with the same voltages and phase angles on both voltages. The voltages should be verified to be available when selected and not available when another input is activated so connect only one voltage transformer reference at each time.
3. Record the voltage selection tests in a matrix table showing read values and AUTOSYOK/MANSYOK signals to document the test performed.

Testing the voltage selection for 1 1/2 CB arrangements

At test of the SESRSYN (25) function for a breaker-and-a-half diameter the following alternative voltage inputs can be used for the three SESRSYN (SESRSYN 1, SESRSYN 2, SESRSYN 3) functions. These three SESRSYN functions can either be in one, two or three different IEDs. Table [13](#) describes the scenario when SESRSYN 1, SESRSYN 2 and SESRSYN 3 all are in the same IED. If SESRSYN 3 is in another IED, WA1 will be considered as WA2 and LINE2 as LINE1. The voltage is selected by activation of different inputs in the voltage selection logic as shown in table [13](#) and figure [22](#).

Table 13: Voltage selection logic

SESRSYN	CBConfig setting	Section to be synchronized	Activated B1QCLD input on IED from	Activated B2QCLD input on IED from	Activated LN1QCLD input on IED from	Activated LN2QCLD input on IED from	Indication from SESRSYN on IED
SESRSYN 1 (Operates on CB1 52)	breaker-and-a-half bus CB	Bus1 – Line1			LN1 989		B1SEL, LN1SEL
		Bus1 – Line2	CB2 252			LN2 989	B1SEL, LN2SEL
		Bus1 – Bus2	CB2 252	CB3 352			B1SEL, B2SEL
SESRSYN 2 (Operates on CB2 252)	Tie CB	Line1 – Line2			LN1 989	LN2 989	LN1SEL, LN2SEL
		Bus1 – Line2	CB1 52			LN2 989	B1SEL, LN2SEL
		Bus2 – Line1		CB3 352	LN1 989		B2SEL, LN1SEL
		Bus1 – Bus2	CB1 52	CB3 352			B1SEL, B2SEL
SESRSYN 3 (Operates on CB3 352)	breaker-and-a-half bus alt. CB (mirrored)	Bus2 – Line2				LN2 989	B2SEL, LN2SEL
		Bus2 – Line1	CB2 252		LN1 989		B2SEL, LN1SEL
		Bus2 – Bus1	CB2 252	CB1 52			B1SEL, B2SEL



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Figure 22: Objects used in the voltage selection logic

10.8.1.5 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.8.2 Autorecloser for 1/2/3-phase operation SMBRREC (79)

Verification of the Autorecloser for 1/2/3-phase operation function SMBRREC (79) for single-phase, two-phase or three-phase reclosing attempts can be considered to consist of two parts.

- One part to verify the internal logic and timing of the function
- One part to verify its interaction with the protection system

This section deals with verification of SMBRREC (79) itself. However, it is practical to initiate SMBRREC (79) by activating a protection function, for example, by secondary injection tests.

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

The purpose of verification before commissioning is to check that entered selections, setting parameters and configuration render the intended result. The function is flexible with many options and facilities. At commissioning only the selections and settings intended for use are verified. If one chooses to reduce some time settings in order to speed up verification, be careful to set the parameters at intended operational values at the end of the verification procedure. One such parameter is the *tReset* time that must be timed out before a new test sequence can be performed.

The verification test is performed together with protection and trip functions. Figure 23 illustrates a suggested testing arrangement, where the circuit-breaker (CB) is simulated by an external bi-stable relay (BR), for example a relay type RXMVB2 or RXMD or Breaker Simulator of ABB. The following manual switches are used:

- Switch or push-button to close (SC)
- Switch or push-button to trip (ST)
- Switch for CB ready condition (SRY)

If no bi-stable relay or breaker simulator is available, replace it with two self-reset auxiliary relays and use a self-holding connection.

Use a secondary injection IED test set to operate the protection function. The test set shall be switched off when a trip signal is given or when the BR comes to open position to simulate real conditions.

The CB simulation can be made more elaborate, including simulation of the operating gear condition, CBREADY of either the type ready for a Close-Open (CO) cycle, or the type ready for an Open-Close -Open (OCO) cycle.

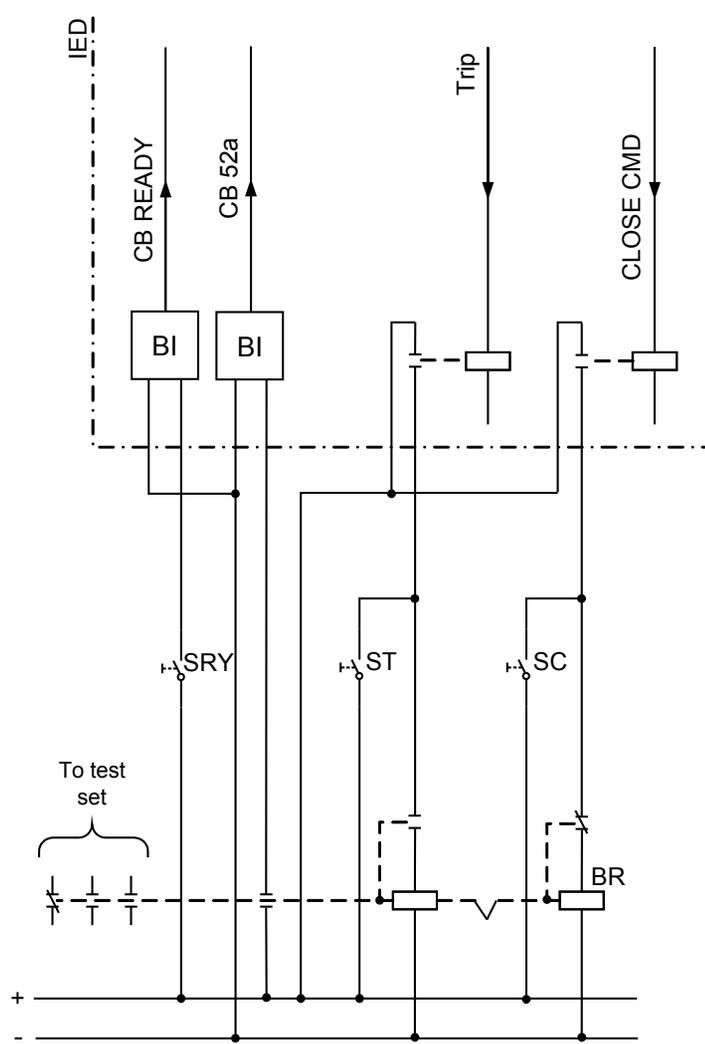
The CB condition CBREADY of a type, CO, shall be high (true) until a closing operation is performed. It then goes low (false) for a recharging time of about 5 - 10s. After that it is high again.

A CB condition CBREADY of a type, OCO shall be high (true) before and during tripping (Initiate reclosing). During tripping it goes low for a recharging time, for example, 10s. It may thus be low at the instant of reclosing. After each Open or Close operation it may need a recharging period before it goes high again.

In the example of CB simulation arrangement, the CBREADY condition is simulated by a manual switch, SRY.

Information and material for the verification:

-
- Protection or control unit, IED, configured and with settings entered.
 - Configuration diagram for the IED
 - Terminal diagram for the IED, or plant circuit diagram including the IED
 - Technical reference manual for the IED
 - IED test set for secondary injection
 - Means to indicate, measure and record operation and times, for example an event recording facility
 - A bi-stable relay (BR) or two auxiliary relays to simulate a CB
 - Two push-buttons (SC, ST) to operate the BR and a change-over switch (SRY) to simulate CBREADY
 - Possibly a switch simulation the synchronizing check SESRSYN (25) condition



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Figure 23: Simulating the CB operation by a bi-stable relay/breaker simulator and manual switches

10.8.2.1

Preparation of the verification

1. Check the function settings on the local HMI under **Main menu/Settings/Setting group N/Control/Autorecloser79,5(0→1)/SMBRREC:x**

- If any timer settings are reduced to speed up or facilitate the testing, they shall be set to normal after testing. A temporary label on the IED can be a reminder to restore normal settings after which a verification test should be performed.
2. Decide if a synchronizing check function SESRSYN (25) shall be included in the test.
If SESRSYN (25) as an internal function or external device is not operated by the injection, input signal SYNC must be connected as a permanent high signal or controlled by a switch.
 3. Read and make notes of the reclosing operation counters on the local HMI under **Main menu/Test/Function status/Control/AutoRecloser79,5(0→1)/SMBRREC:x**
Possibly reset the counters to *Zero*. Counters are reset in the reset menu.
 4. Make arrangements for the simulation of the CB, for example as in figure 23.
 5. Make arrangements for indication, recording and time measurements.
The signals for ,52a, RI, CLOSECMD, READY and other relevant signals should preferably be arranged for event recording with time tagging. If that is not possible, other means of time measurement and recording should be arranged.

10.8.2.2

Switching the autorecloser for 1/2/3-phase operation function to *Enabled* and *Disabled*

1. Set the *Operation* setting to *Disabled* and check the state.
2. Set the *Operation* setting to *Enabled* and check the state, including SETON and READY.
The CB should be closed and ready.
3. If external control inputs OFF/ON are used, check that they work. Set *ExternalCtrl = On* and use the control inputs to switch On and Off, and check the state of the function.

10.8.2.3

Verifying the autorecloser function SMBRREC (79)

Select the test cases to be run according to what is applicable to the particular application. It can be, for example,

- three-phase single-shot reclosing
- two-shot reclosing
- single-phase and three-phase single-shot reclosing

Below, a case with single-phase and three-phase single-shot reclosing is described.

1. Set *Operation = Enabled*.
2. If the synchronizing check SESRSYN (25) is not to be operated, ensure that the signal SYNC input is activated. If SESRSYN (25) is to be included, ensure that it is supplied with the appropriate AC quantities.
3. Simulate CB closed position by closing switch SC to make the BR relay pick-up.
4. Simulate CBREADY by closing the switch SRY, and leave it closed.
5. Inject AC quantities to give a trip, for example, one-pole trip, to the BR and to the RI input.
Observe and preferably record the operation. The BR relay shall trip and reclose (pick-up). After reclosing, the SRY switch can be opened for about 5s and then closed again.
The autoreclosing open time and the sequence should be checked, for example in the event recording. Check also the operation indications (disturbance report) and the operation counters on the local HMI under **Main menu/Test/Function status/Control/AutoRecloser79,5(0→1)/SMBRREC:x**
Should the operation not be as expected, this should be investigated. It could be caused by an inappropriate setting or missing condition such as CBREADY.
6. Repeat the sequence by simulating a permanent fault.
Shortly after the reclosing shot, a new fault is applied. If a single-shot reclosing program is selected, there shall be one reclosing operation and then blocking of SMBRREC (79) for the set Reset time.
Before a new reclosing sequence can be run, the CBREADY and 52a (CB closed) must be set manually.
7. Repeat the sequence by simulating a three-phase transient and permanent faults, and other applicable cases, such as signal to RI_HS and high-speed reclosing.
If just single-phase reclosing is selected, *FirstShot = 1ph*, a check can be run to make sure that a three-pole trip does not result in any reclosing. Other similar cases can be checked as required.

10.8.2.4

Checking the reclosing conditions

When checking the influence of a releasing condition it is suggested to first run a sequence with the condition fulfilled. When the condition signal is removed, and a new sequence is run, it indicates that the result was due to the changed condition. In case of a blocking signal the procedure should be similar. Start without the blocking or inhibit signal, and then run a sequence with the blocking or inhibit signal added.

Checking the influence of the INHIBIT signal

1. Check that the autorecloser function SMBRREC (79) is operative, for example, by making a reclosing shot without the INHIBIT signal.
2. Apply a fault and thereby a RI signal. At the same time, or during the open time, apply a signal to the input INHIBIT.
3. Check that the reclosing sequence is interrupted and no reclosing takes place.

Check closing onto a fault

1. Check that the autorecloser function SMBRREC (79) is operative, for example by making a reclosing shot.
Keep the CBREADY signal high.
2. Set the breaker simulating relay BR in Open position.
3. Close the BR relay and apply immediately a fault and thereby a RI signal.
4. Check that no reclosing takes place.

Checking the influence of CB not ready for reclosing

1. Check that the autorecloser function SMBRREC (79) is operative, for example by making a reclosing shot.
Keep the CB simulator BR closed. Remove the CBREADY signal by opening SRY.
2. Apply a fault and thereby a RI signal.
3. Check that no reclosing takes place.

Checking the influence of synchronizing check (at three-pole reclosing)

1. Check that the autorecloser function SMBRREC (79) is operative, for example, by making a three-pole reclosing shot with the SESRSYN (25) synchronizing check condition.
Set the SESRSYN (25) function to *Off* to eliminate the signal connected to input signal SYNC.
2. Apply a fault causing three-phase trip and thereby a RI and a TR3P signal.
3. Wait for the t_{Sync} time out limit.
Check that no reclosing is made.

Checking the response when autoreclosing is *Off*

Procedure

1. Check that the autorecloser function SMBRREC (79) is operative, for example by making a reclosing shot.
Set the autoreclosing operation to *Off*, for example by external control.

- The output READY shall be low, and PREP3P shall be high.
2. Apply a single phase fault and thereby a RI signal.
 3. Check that a definitive three phase trip and no reclosing takes place.

Testing autoreclosing in a multi-breaker arrangement

The usual arrangement is to have an autorecloser function SMBRREC (79) per circuit-breaker. They can be in different CB related IEDs or in a common IED.

- A master SMBRREC (79) function is set with *Priority = High*.
- A slave SMBRREC (79) function is set with *Priority = Low*.



See the application manual for an illustration of typical interconnections.

The two functions can be checked individually by carefully applying RI, WAIT, and INHIBIT signals.

It is also possible to verify the two functions together by using CB simulating equipment for two CB circuits. There should be interconnections from the master to the slave function, WFMASTER - WAIT, and UNSUCCL - INHIBIT, as shown in the illustration referred to above.

Restoring equipment

After the tests, restore the equipment to normal or desired state. Check the following items in particular:

1. Check the operation counters.
Reset the counters to zero, if that is the user's preference. The counter reset function is found on the local HMI under **Main menu/Reset/Reset counters/ AutoRecloser79,5(0→1)/SMBRREC:x**
2. Restore settings that may have been modified for the tests back to normal.
3. Disconnect the test switch, CB simulating arrangement and test circuits.
Reconnect any links or connection terminals, which may have been opened for the tests.
4. Reset indications, alarms and disturbance recordings.
Clearing of the disturbance report can be done via the Disturbance Handling in PCM600 or the local HMI.

10.8.2.5

Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.8.3 Apparatus control APC

The apparatus control function consists of four types of function blocks, which are connected in a delivery-specific way between bays and to the station level. For that reason, test the total function in a system, that is, either in a complete delivery system as an acceptance test (FAT/SAT) or as parts of that system.



If a block/unblock command is sent from remote to function, while the IED is shut down, this command will not be recognized after the start up, thus the command that was sent prior to the shut down is used. In such cases, where there is a mismatch, the user is advised to make a complete cycle of block/unblock operations to align the statuses.

10.8.4 Single command, 16 signals SINGLECMD

For the single command function block, it is necessary to configure the output signal to corresponding binary output of the IED. The operation of the single command function (SINGLECMD) is then checked from the local HMI by applying the commands with *Mode = Off, Steady or Pulse*, and by observing the logic statuses of the corresponding binary output. Command control functions included in the operation of different built-in functions must be tested at the same time as their corresponding functions.

10.8.5 Interlocking

Prepare the IED for verification of settings outlined in section ["Preparing the IED to verify settings"](#).

Values of the logical signals are available on the local HMI under **Main menu/Tests/Function status/Control/<Function>/<Function:1>**. The Signal Monitoring in PCM600 shows the same signals that are available on the local HMI.

The interlocking function consists of a bay-level part and a station-level part. The interlocking is delivery specific and is realized by bay-to-bay communication over the station bus. For that reason, test the function in a system, that is, either in a complete delivery system as an acceptance test (FAT/SAT) or as parts of that system.

10.9 Monitoring

10.9.1 Gas medium supervision SSIMG

Prepare the IED for verification of settings as outlined in section ["Testing the liquid medium supervision for alarm and lock out conditions"](#) and section ["Completing the test"](#) in this chapter.

Check that the input logical signal BLOCK is logical zero and that on the local HMI, the logical signals PRES_ALM, PRES_LO, TEMP_ALM and TEMP_LO are equal to logical zero.

10.9.1.1 Testing the liquid medium supervision for alarm and lock out conditions

1. Connect binary inputs to consider gas pressure and gas density to initiate the alarms.
2. Consider the analogue pressure input PRESSURE to initiate the alarms.
3. Gas pressure lock out input can be used to set PRES_LO signal, check the signal status in local HMI under **Main menu/Test/Function status/Monitoring/Gas medium supervision SSIMG/PRES_LO**
4. Reduce the pressure level input below *PresAlmLimit*, check for PRES_ALM signal status in local HMI under **Main menu/Test/Function status/Monitoring/Gas medium supervision SSIMG/PRES_ALM**
5. Activate BLOCK binary input, the signals PRES_ALM, PRES_LO should disappear.
6. Reset the BLOCK binary input.
7. Check for reset lock out input RESET_LO to reset PRES_LO lock out signal.
8. Conduct these steps for temperature input as well to detect and reset TEMP_ALM and TEMP_LO signals.
9. Continue to test another function or end the test by changing the *TestMode* setting to *off*.

10.9.1.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Off*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.9.2 Liquid medium supervision SSIML

Prepare the IED for verification of settings as outlined in section ["Liquid medium supervision SSIML"](#) and section ["Completing the test"](#) in this chapter.

Check that the input logical signal BLOCK is logical zero and that on the local HMI, the logical signals LVL_ALM, LVL_LO, TEMP_ALM and TEMP_LO are equal to logical zero.

10.9.2.1 Testing the liquid medium supervision for alarm and lock out conditions

1. Connect the binary inputs to consider liquid level to initiate the alarms.
2. Consider the analogue level input LEVEL to initiate the alarms.
3. Liquid level lock out input can be used to set LVL_LO signal, check the signal status in local HMI under **Main menu/Test/Function status/Monitoring/Liquid medium supervision SSIML/LVL_LO**
4. Reduce the liquid level input below LevelAlmLimit, check for LVL_ALM signal status in local HMI under **Main menu/Test/Function status/Monitoring/Liquid medium supervision SSIML/LVL_ALM**
5. Activate BLOCK binary input, the signals LVL_ALM, LVL_LO should disappear.
6. Reset the BLOCK binary input.
7. Check for reset lock out input RESET_LO to reset the LVL_LO lock out signal.
8. Conduct these steps for temperature input as well to detect and reset TEMP_ALM and TEMP_LO signals.
9. Continue to test another function or end the test by changing the *TestMode* setting to *Off*.

10.9.2.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Off*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.9.3 Breaker monitoring SSCBR

Prepare the IED for verification of settings outlined in section “Testing the IED operation”.

The Signal Monitoring tool in PCM600 shows the service values that are available on the Local HMI as well.

Values of the logical signals belong to the breaker monitoring are available on the local HMI under: **Main menu/Test/Function status/Monitoring/BreakerMonitoring/SSCBR:x**

10.9.3.1

Verifying the settings

1. Connect the test set for the injection of a three-phase current to the appropriate current terminals of the IED.
2. If current need to be injected for a particular test, it should be done in the phase selected by the *PhSel* parameter.
3. Follow the sequence for positioning the auxiliary contacts before testing:

POSCLOSE	0	1	0
POSOPEN	0	0	1

4. Test of CB contact travel time
 - 4.1. Test the set timing defined by *OpenTimeCorr*, *CloseTimeCorr*, *tTrOpenAlm* and *tTrCloseAlm*.
 - 4.2. Change the status of the auxiliary contacts such that travel time to open TTRVOP and travel time to close TTRVCL exceed the respective set values (*tTrOpenAlm* and *tTrCloseAlm*). The measured travel time for opening and closing is shown on TTRVOP and TTRVCL respectively.
 - 4.3. Check that TRVTOPAL and TRVTCLAL are activated.
5. Test of CB status
 - 5.1. Test the set current level defined by *AccStopCurr*.
 - 5.2. Check the CLOSEPOS output by changing the *POSOPEN* to 0 and *POSCLOSE* to 1.
 - 5.3. Check the OPENPOS output by changing the *POSOPEN* to 1 and *POSCLOSE* to 0 and also inject the current in the selected phase slightly lower and higher than *AccStopCurr* set value. Only for a current lower than set *AccStopCurr* should activate the output POSOPEN.
 - 5.4. Check the circuit breaker is in INVDPoS if auxiliary contacts read same value or CB is open and inject the current in selected phase more than *AccStopCurr* set value.
6. Test of remaining life of CB
 - 6.1. Test the set timing defined by *RatedOperCurr*, *RatedFltCurr*, *OperNoRated*, *OperNoFault*, *DirCoef*, *CBLifeAlmLevel*.
 - 6.2. Vary the phase current in the selected phase from below rated operated current, *RatedOperCurr* to above rated fault current, *RatedFltCurr* of a breaker.
 - 6.3. The remaining life of CB output CBLIFE_{PH} is estimated when the CB is changed from closed to open position. Check that the output CBLIFE_{PH} is decreased with a value that corresponds to the injected current.
 - 6.4. CBLIFE_{AL} is activated as soon as CBLIFE_{PH} is below the set *CBLifeAlmLevel* value.
7. Test of accumulated energy

- 7.1. Test the actual set values defined by *AccSelCal* to *Aux Contact*, *ContTrCorr* and *AlmAccCurrPwr*.
- 7.2. Inject phase current in the selected phase such that its value is greater than set *AccStopCurr* value.
- 7.3. When the breaker goes to open position, accumulated energy *IPOWPH* is calculated. The calculated value can be seen on the output *IPOWPH*.
- 7.4. Alarm signal *IPOWALPH* appears when *IPOWPH* is greater than set *AlmAccCurrPwr* value.
- 7.5. Lockout signal *IPOWLOPH* appears if *IPOWPH* exceeds further to the threshold value *LOAccCurrPwr*.
- 7.6. Calculation of accumulated energy *IPOWPH* is stopped when injected current is lower than set *AccStopCurr* value.
8. Test of CB operation cycles
 - 8.1. Test the actual set values defined by *OperAlmLevel* and *OperLOLevel*.
 - 8.2. The operation counter, *NOOPER* is updated for every close-open sequence of the breaker by changing the position of auxiliary contacts *POSCLOSE* and *POSOPEN*.
 - 8.3. *OPERALM* is activated when *NOOPER* value exceeds the set *OperAlmLevel* value. The actual value can be read on the output *NOOPER*.
 - 8.4. *OPERLO* is activated when *NOOPER* value exceeds the set *OperLOLevel* value.
9. Test of CB spring charge monitoring
 - 9.1. Test the actual set value defined by *SpChAlmTime*.
 - 9.2. Enable *SPRCHRST* input. Also activate *SPRCHRD* after a time greater than set time *SpChAlmTime*.
 - 9.3. At this condition, *SPCHALM* is activated.
10. Test of CB gas pressure indication
 - 10.1. Test the actual set value defined by *tDGasPresAlm* and *tDGasPresLO*.
 - 10.2. The output *GPRESALM* is activated after a time greater than set time of *tDGasPresAlm* value if the input *PRESALM* is enabled.
 - 10.3. The output *GPRESLO* is activated after a set time of *tDGasPresLO* value if the input *PRESLO* is enabled.

10.9.3.2

Completing the test

1. Continue to test another function or end the test by changing the *Test mode* setting to *Disabled*.
2. Restore connections and settings to their original values if they were changed for testing purposes.

10.9.4 Event function EVENT

Prepare the IED for verification of settings as outlined in section [""](#) and section ["Preparing for test"](#) in this chapter.

During testing, the IED can be set when in test mode from PST. The functionality of the event reporting during test mode is set in the Parameter Setting tool in PCM600.

- Use event masks
- Report no events
- Report all events

In test mode, individual event blocks can be blocked from PCM600.

10.9.5 Limit counter L4UFCNT

The Limit counter function L4UFCNT can be tested by connecting a binary input to the counter and applying pulses to the counter. The speed of the pulses must not exceed the cycle time of the function. Normally the counter will be tested when testing the function that the counter is connected to, such as the trip function. When the function is configured, test it together with the function that operates it. Trig the function and check that the counter result corresponds to the number of operations.

10.9.5.1 Completing the test

Continue to test another function or end the test by changing the Test mode setting to *Off*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.10 Metering

10.10.1 Pulse-counter logic PCFCNT

The test of the Pulse-counter logic function PCFCNT requires the Parameter Setting tool in PCM600 or an appropriate connection to the local HMI with the necessary functionality. A known number of pulses with different frequencies are connected to the pulse counter input. The test should be performed with settings *Operation = Enable* or *Operation = Disable* and the function blocked or unblocked. The pulse counter value is then checked in PCM600 or on the local HMI.

10.10.2 Function for energy calculation and demand handling ETPMMTR

Prepare the IED for verification of settings as outlined in section "Overview" and section "Preparing for test" in this chapter.

10.10.2.1 Verifying the settings

Common test equipment can be used to determine the injection of current and voltage and time measurement.

Verification of EAFACC & ERFACC output

1. Connect the test set for injection of three-phase currents and three phase voltage to the appropriate current and voltage terminals of the IED.
2. Ensure the instantaneous values of active and reactive power from CVMMXN function block are connected to ETPMMTR function block active and reactive power inputs.
3. Enable the *EnaAcc* setting and set *tEnergy* as 1 minute.
4. Activate the STARTACC input and supply the IED with three phase currents and voltages at their rated value.
5. Check that the ACCINPRG signal appears continuously.
6. Note the EAFACC and ERFACC value after 1 minute and compare it with calculated energy value.
7. Similarly check after each 1 minute whether the calculated integrated energy value and EAFACC and ERFACC outputs are matching.
8. After some time (multiple of minute) remove the current and voltage input from CVMMXN function block.
9. Check the EAFACC and ERFACC output in the next 1 minute cycle for the retaining the same value.
10. Activate STOPACC input after some time and supply the IED with same current and voltage.
11. Check that the ACCINPRG signal disappears immediately and EAFACC and ERFACC outputs also stop updating.
12. Similarly the testing can be done for EAFACC and ERFACC outputs by changing the power inputs directions through direction settings.

Verification of MAXPAFD & MAXPRFD outputs

1. Repeat the above test steps 1 to 2.
2. Set *tEnergy* setting as 1 minute and supply the IED with three phase currents and voltages at their rated value till 1 minute.
3. Check the MAXPAFD and MAXPRFD outputs after 1 minute and compare it with last 1 minute average power values.
4. Increase either three phase current or voltage above the last 1 minute value.
5. After 1 minute check the MAXPAFD and MAXPRFD whether it is showing the last 1 minute average power value as maximum.
6. Next 1 minute cycle reduce the current or voltage below previous value.
7. Check after 1 minute whether the MAXPAFD and MAXPRFD outputs are retaining the old maximum value.
8. Similarly the testing can be done for MAXPAFD and MAXPRFD outputs by changing the power inputs directions through direction settings.

Verification of EAFALM & ERFALM outputs

1. Repeat the above test steps 1 to 2.
2. Set *tEnergy* setting as 1 minute and supply the IED with three phase currents and voltages at their rated value till 1 minute.
3. Ensure that the active and reactive energy values are less than the *EALim* and *ERLim* setting default values respectively.
4. Check that EAFALM and ERFALM are low.
5. Increase the supply currents or voltage in next 1 minute cycle such that the active or reactive energy values are greater than the *EALim* and *ERLim* setting default values respectively.
6. Check that EAFALM and ERFALM are high after 1 minute.
7. Similarly the testing can be done for EARALM and ERRALM outputs by changing the power inputs directions through direction settings.

10.10.2.2

Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.11 Station communication

10.11.1 Multiple command and transmit MULTICMDRCV / MULTICMDSND

The multiple command and transmit function (MULTICMDRCV / MULTICMDSND) is only applicable for horizontal communication.

Test of the multiple command function block and multiple transmit is recommended to be performed in a system, that is, either in a complete delivery system as an acceptance test (FAT/SAT) or as parts of that system, because the command function blocks are connected in a delivery-specific way between bays and the station level and transmit.

Command and transmit function blocks included in the operation of different built-in functions must be tested at the same time as their corresponding functions.

10.12 Remote communication

10.12.1 Binary signal transfer BinSignReceive, BinSignTransm

Prepare the IED for verification of settings as outlined in section ["Preparing the IED to verify settings"](#).

To perform a test of Binary signal transfer function (BinSignReceive/BinSignTransm), the hardware (LDCM) and binary input and output signals to transfer must be configured as required by the application.

There are two types of internal self supervision of BinSignReceive/BinSignTransm

- The I/O-circuit board is supervised as an I/O module. For example it generates FAIL if the board is not inserted. I/O-modules not configured are not supervised.
- The communication is supervised and the signal COMFAIL is generated if a communication error is detected.

Status for inputs and outputs as well as self-supervision status are available from the local HMI under

- Self-supervision status: **Main menu/Diagnostics/Internal events**
- Status for inputs and outputs: **Main menu/Test/Function status**, browse to the function group of interest.
- Remote communication related signals: **Main menu/Test/Function status/Communication/Remote communication**

Test the correct functionality by simulating different kind of faults. Also check that sent and received data is correctly transmitted and read.

A test connection is shown in figure 24. A binary input signal (BI) at End1 is configured to be transferred through the communication link to End2. At End2 the received signal is configured to control a binary output (BO). Check at End2 that the BI signal is received and the BO operates.

Repeat the test for all the signals configured to be transmitted over the communication link.

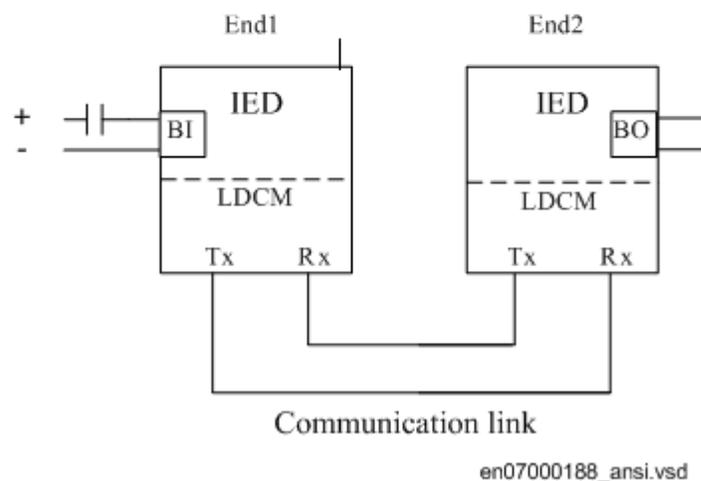


Figure 24: Test of RTC with I/O

10.13 Basic IED functions

10.13.1 Parameter setting group handling SETGRPS

Prepare the IED for verification of settings as outlined in section "" and section "[Preparing for test](#)" in this chapter.

10.13.1.1 Verifying the settings

1. Check the configuration of binary inputs that control the selection of the active setting group.
2. Browse to the **ActiveGroup** menu to achieve information about the active setting group.
The **ActiveGroup** menu is located on the local HMI under **Main menu/Test/Function status/Setting groups/ActiveGroup**
3. Connect the appropriate dc voltage to the corresponding binary input of the IED and observe the information presented on the local HMI.
The displayed information must always correspond to the activated input.
4. Check that the corresponding output indicates the active group.
Operating procedures for the PC aided methods of changing the active setting groups are described in the corresponding PCM600 documents and instructions for the operators within the SCS are included in the SCS documentation.

10.13.1.2 Completing the test

Continue to test another function or end the test by changing the *TestMode* setting to *Disabled*. Restore connections and settings to their original values, if they were changed for testing purposes.

10.14 Exit test mode

The following procedure is used to return to normal operation.

1. Navigate to the test mode folder.
2. Change the *Enable* setting to *Disable*. Press the 'E' key and the left arrow key.
3. Answer *YES*, press the 'E' key and exit the menus.

Section 11 Primary injection testing

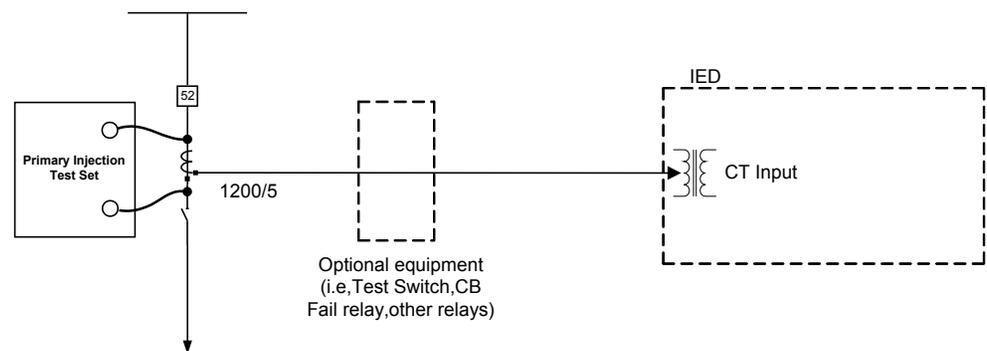


Whenever it becomes necessary to work on primary equipment, it is essential that all the necessary switching, locking, grounding and safety procedures are observed and obeyed in a rigid and formalized manner. Operating and testing procedures should be strictly followed in order to avoid exposure to live equipment.

A test with primary current through the protected zone is usually a final check that the current circuits are correctly connected to the IED protection scheme. It is important to have an appropriate source, which is able to inject sufficient current in the primary circuit in order to distinguish between noise and real injected current. Therefore it is recommended that the injection current should be at least 10% of rated CT primary current.

11.1 Operation of the busbar differential protection

The primary injection tests of a differential IED consist of applying a suitable current source across the primary winding of the CT connected to the current input of the IED. The testing is normally carried out on one phase at a time. If the primary current is bigger than the set value of the *DiffOperLevel* parameter, the IED shall issue the trip command as well. The primary current injection test should be repeated for every CT until all current circuits in all phases are checked. The typical connection for the primary injection test is shown in figure 25.



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Figure 25: Typical test connection for primary injection testing

Testing will be explained from one general current input CT_x (that is, $x = 1, 2, \dots, N_{\max}$; where N_{\max} is equal to the maximum number of used CT inputs).

Follow the following test instructions for all used current inputs in an IED.

Procedure

1. Connect the test set for injection primary current to the main CT connected to the current terminals of CT_x input of the IED as shown in figure [25](#).
2. Make sure that current measurement from the CT_x input are included in one of the differential zones.
3. Inject the primary current in phase A and note the incoming and differential currents on the local HMI of the IED. The values of the incoming and the differential currents shall correspond to the injected primary current.
4. Check that the current is present only in the phase being tested.
5. If the injected current is high enough, check that trip contacts operate accordingly to the scheme wiring.
6. Check that trip information is stored in the disturbance recorder and event list (if connected).
7. Switch off the current.
8. Check the function in the same way by injecting current in phases B and C.

It is recommended that each primary CB is tripped directly from the protection scheme at least once during these tests. This will confirm the trip-circuit connection between the protection scheme and the CB.

11.2 Stability of the busbar differential protection

For stability testing, one current circuit shall always be used as a reference input. The reference current circuit shall then be tested for stability against all other current circuits connected to a busbar protection scheme on a one-by-one basis. Use the current circuit connected to the CT1 current input as the reference current circuit. A typical connection for the primary current test set for this type of tests is shown in figure [26](#).

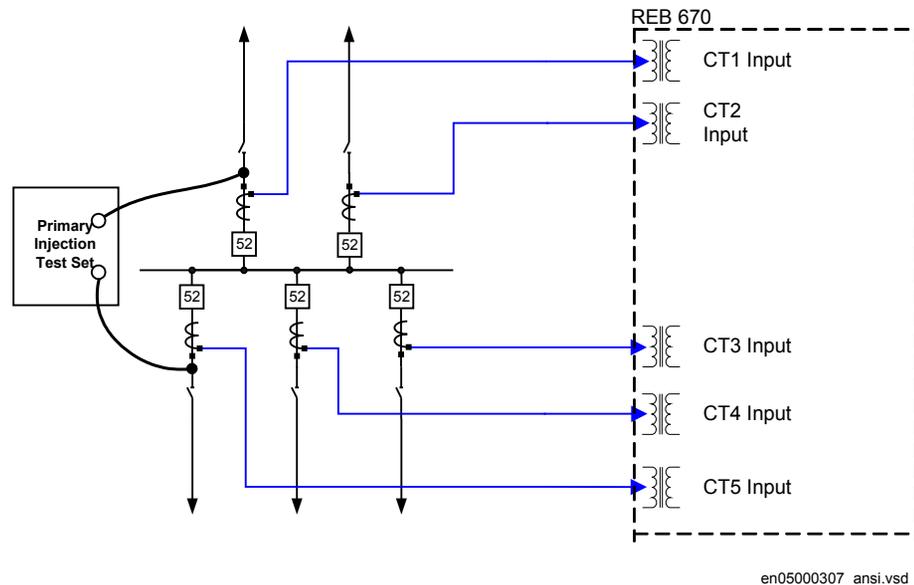


Figure 26: Typical test connection for primary injection, which should confirm the stability of the main CT connected to current inputs of the IED

For this type of primary injection tests a suitable current source should be applied across the primary windings of two CTs connected in series as shown in figure 26. The testing is normally done on one phase at the time. The currents in the secondary winding of these CTs are then opposite in phase. The differential current displayed by the IED should be negligible while the incoming current displayed should be equal to the value of the injected primary current. The IED must not issue the trip command during these tests. If it trips or the differential current has a high value it usually means that there is a wiring problem in the CT circuits connected to the current input CT_x (that is, a differential current equal to twice the injection current probably indicates wrong polarity of the main CT connected to the CT_x current input). This problem must be solved before the protection scheme is put in service.

Procedure

1. Connect the test set for primary current injection to the main CTs as shown in figure 26.
2. Make sure that current measurement from two used CT inputs are included in the same differential zone.
3. Inject the primary current in phase A and note the incoming and differential currents on the local HMI of the IED.
The value of the incoming current for phase A shall correspond to the injected primary current. The value of the differential current for phase A shall be negligible.

4. Check that the current is present only in the phase being tested.
5. Switch the current off.
6. Check the function in phases B and C by injecting current in the same way.

In busbar arrangements where a disconnector replica is used, it provides the information to the busbar protection about which of the measured CT currents shall be included within different differential zones. It is necessary to verify the auxiliary contacts from each busbar disconnector.



For more information please refer to the REB670 application manual.

Proper operation of this scheme have to be checked during commissioning, by manual operation of the primary busbar disconnectors and/or circuit breakers and verification that the associated switch status function block properly operates. Proper timing of the disconnector auxiliary contacts have to be checked as well.

The protection scheme can be put in service after all these tests have been conducted.

Section 12 Commissioning and maintenance of the fault clearing system

12.1 Commissioning tests

During commissioning all protection functions shall be verified with the setting values used at each plant. The commissioning tests must include verification of all circuits by highlighting the circuit diagrams and the configuration diagrams for the used functions.

Further, the settings for protection functions are tested and recorded carefully as outlined for the future periodic maintenance tests.

The final testing includes primary verification of all directional functions where load currents is checked on the local HMI and in PCM600. The magnitudes and angles of all currents and voltages should be checked and the symmetry verified.

Directional functions have information about the measured direction and, for example, measured impedance. These values must be checked and verified as correct with the export or import of power available.

Finally, final trip tests must be performed. This involves activation of protection functions or tripping outputs with the circuit breaker closed and the tripping of the breaker verified. When several breakers are involved, each breaker must be checked individually and it must be verified that the other involved breakers are not tripped at the same time.

12.2 Periodic maintenance tests

The periodicity of all tests depends on several factors, for example the importance of the installation, environmental conditions, simple or complex equipment, static or electromechanical IEDs, and so on.

The normal maintenance practices of the user should be followed. However, ABB's recommendation is as follows:

Every second to third year

- Visual inspection of all equipment.
- Removal of dust on ventilation louvres and IEDs if necessary.
- Periodic maintenance test for protection IEDs of object where no redundant protections are provided.

Every four to six years

- Periodic maintenance test for protection IEDs of objects with redundant protection system.



First maintenance test should always be carried out after the first half year of service.



When protection IEDs are combined with built-in control, the test interval can be increased drastically, up to for instance 15 years, because the IED continuously reads service values, operates the breakers, and so on.

12.2.1

Visual inspection

Prior to testing, the protection IEDs should be inspected to detect any visible damage that may have occurred (for example, dirt or moisture deposits, overheating).

Make sure that all IEDs are equipped with covers.

12.2.2

Maintenance tests

To be made after the first half year of service, then with the cycle as proposed above and after any suspected maloperation or change of the IED setting.

Testing of protection IEDs shall preferably be made with the primary circuit de-energized. The IED cannot protect the circuit during testing. Trained personnel may test one IED at a time on live circuits where redundant protection is installed and de-energization of the primary circuit is not allowed.

ABB protection IEDs are preferably tested by aid of components from the COMBITEST testing system or FT test systems described in information B03-9510 E. Main components are RTXP 8/18/24 test switch usually located to the left in each protection IED and RTXH 8/18/24 test handle, which is inserted in test switch at secondary testing. All necessary operations such as opening of trip circuits, short-circuiting of current circuits and opening of voltage circuits are automatically

performed in the right order to allow for simple and safe secondary testing even with the object in service.

Important components of FT test system are FT1, FT_x, FT19, FT19RS, FR19RX switches and assemblies as well as FT-1 test plug.

12.2.2.1 Preparation

Before starting maintenance testing, the test engineers should scrutinize applicable circuit diagrams and have the following documentation available:

- Test instructions for protection IEDs to be tested
- Test records from previous commissioning and maintenance tests
- List of valid settings
- Blank test records to fill in measured values

12.2.2.2 Recording

It is of utmost importance to carefully record the test results. Special test sheets covering the frequency of test, date of test and achieved test values should be used. IED setting list and protocols from previous tests should be available and all results should be compared for differences. At component failures, spare equipment is used and set to the requested value. A note of the exchange is made and the new measured values are recorded. Test records for several years of testing should be stored in a common file for a station, or a part of a station, to give a simple overview of the period of testing and achieved test values. These test records are valuable when analysis of service disturbances shall be done.

12.2.2.3 Secondary injection

The periodic maintenance test is done by secondary injection from a portable test set. Each protection shall be tested according to the secondary injection test information for the specific protection IED. Only the setting values adopted shall be checked for each protection function. If the discrepancy between obtained value and requested set value is too big the setting should be adjusted, the new value recorded and a note should be made in the test record.

12.2.2.4 Alarm test

When inserting the test handle of R_{TXP} or using FT plugs, the alarm and event signalling is normally blocked. This is done in the IED by setting the event reporting to *Disabled* during the test. This can be done when the test handle is inserted or the IED is set to test mode from the local HMI. At the end of the secondary injection test it

should be checked that the event and alarm signalling is correct by activating the events and performing some selected tests.

12.2.2.5 Self supervision check

Once secondary testing has been completed, it should be checked that no self-supervision signals are activated continuously or sporadically. Especially check the time synchronization system, GPS or other, and communication signals, both station communication and remote communication.

12.2.2.6 Trip circuit check

When the protection IED undergoes an operational check, a tripping pulse is normally obtained on one or more of the output contacts and preferably on the test switch. The healthy circuit is of utmost importance for the protection operation. If the circuit is not provided with a continuous trip-circuit supervision, it is possible to check that circuit is really closed when the test-plug handle has been removed by using a high-ohmic voltmeter and measuring between the plus and the trip output on the panel. The measurement is then done through the trip coil of the circuit breaker and therefore the complete trip circuit is checked.



Note that the breaker must be closed.



Please observe that the test system does not provide built-in security during this test. If the instrument should be set on Amp instead of Volts, the circuit breaker naturally is tripped, therefore, great care is necessary.

Trip circuit from trip IEDs to circuit breaker is often supervised by trip-circuit supervision. It can then be checked that a circuit is healthy by opening tripping output terminals in the cubicle. When the terminal is opened, an alarm shall be achieved on the signal system after a delay of some seconds.



Remember to close the circuit directly after the test and tighten the terminal carefully.

12.2.2.7 Measurement of service currents

After a maintenance test it is recommended to measure the service currents and service voltages recorded by the protection IED. The service values are checked on the local HMI or in PCM600. Ensure that the correct values and angles between voltages and currents are recorded. Also check the direction of directional functions such as Distance and directional overcurrent functions.

For transformer differential protection, the achieved differential current value is dependent on the tap changer position and can vary between less than 1% up to perhaps 10% of rated current. For line differential functions, the capacitive charging currents can normally be recorded as a differential current.

The zero-sequence current to ground-fault protection IEDs should be measured. The current amounts normally very small but normally it is possible to see if the current circuit is "alive".

The neutral-point voltage to an ground-fault protection IED is checked. The voltage is normally 0.1 to 1V secondary. However, voltage can be considerably higher due to harmonics. Normally a CVT secondary can have around 2.5 - 3% third-harmonic voltage.

12.2.2.8 Restoring

Maintenance is very important to improve the availability of the protection system by detecting failures before the protection is required to operate. There is however little point in testing healthy equipment and then putting it back into service with an open terminal, with a removed fuse or open miniature circuit breaker with an open connection, wrong setting, and so on.

Thus a list should be prepared of all items disturbed during test so that all can be put back into service quickly and without overlooking something. It should be put back into service item by item and signed by the responsible engineer.

Section 13 Troubleshooting

13.1 Checking the self supervision signals

13.1.1 Checking the self supervision function

13.1.1.1 Determine the cause of an internal failure

This procedure describes how to navigate the menus in order to find the cause of an internal failure when indicated by the flashing green LED on the HMI module.

Procedure

1. Display the general diagnostics menu.
Navigate the menus to:
Diagnostics/IED status/General
2. Scroll the supervision values to identify the reason for the failure.
Use the arrow buttons to scroll between values.

13.1.2 Self supervision HMI data

Table 14: *Signals from the General menu in the diagnostics tree.*

Indicated result	Possible reason	Proposed action
Internal fail Off	No problem detected.	None.
Internal fail On	A failure has occurred.	Check the rest of the indicated results to find the fault.
Internal warning Off	No problem detected.	None.
Internal warning On	A warning has been issued.	Check the rest of the indicated results to find the fault.
Time synch Ready	No problem detected.	None.
Time synch Fail	No time synchronization.	Check the synchronization source for problems. If the problem persists, contact your ABB representative for service.
Real time clock Ready	No problem detected.	None.
Real time clock Fail	The real time clock has been reset.	Set the clock.
ADC-module OK	No problem detected.	None.
Table continues on next page		

Indicated result	Possible reason	Proposed action
ADC-module Fail	The AD conversion module has failed.	Contact your ABB representative for service.
(Protocol name) Ready	No problem detected.	None.
(Protocol name) Fail	Protocol has failed.	
(I/O module name) Ready	No problem detected.	None.
(I/O module name) Fail	I/O modules has failed.	Check that the I/O module has been configured and connected to the IOP1- block. If the problem persists, contact your ABB representative for service.

13.2 Fault tracing

13.2.1 Internal fault indications

If an internal fault has occurred, the local HMI displays information under **Main menu/Diagnostics/IED status/General**

Under the Diagnostics menus, indications of a possible internal failure (serious fault) or internal warning (minor problem) are listed.

Indications regarding the faulty unit are outlined in table [15](#).

Table 15: *Self-supervision signals on the local HMI*

HMI Signal Name:	Status	Description
INT Fail	OFF / ON	This signal will be active if one or more of the following internal signals are active; INT--LMDERROR, INT--WATCHDOG, INT--APPERROR, INT--RTEERROR, or any of the HW dependent signals
INT Warning	OFF / ON	This signal will be active if one or more of the following internal signals are active; INT--RTCERROR, INT--IEC61850ERROR, INT--TIMESYNCHERROR
ADMnn	READY / FAIL	Analog input module n failed. Signal activation will reset the IED
BIMnn	READY / FAIL	BIM error. Binary input module Error status. Signal activation will reset the IED
BOMn	READY / FAIL	BOM error. Binary output module Error status.
IOMn	READY / FAIL	IOM-error. Input/Output Module Error status.
Table continues on next page		

HMI Signal Name:	Status	Description
MIMn	READY / FAIL	mA input module MIM1 failed. Signal activation will reset the IED
RTC	READY / FAIL	This signal will be active when there is a hardware error with the real time clock.
Time Sync	READY / FAIL	This signal will be active when the source of the time synchronization is lost, or when the time system has to make a time reset.
Application	READY / FAIL	This signal will be active if one or more of the application threads are not in the state that Runtime Engine expects. The states can be CREATED, INITIALIZED, RUNNING, etc.
RTE	READY / FAIL	This signal will be active if the Runtime Engine failed to do some actions with the application threads. The actions can be loading of settings or parameters for components, changing of setting groups, loading or unloading of application threads.
IEC61850	READY / FAIL	This signal will be active if the IEC61850 stack did not succeed in some actions like reading IEC61850 configuration, startup etc.
LMD	READY / FAIL	LON network interface, MIP/DPS, is in an unrecoverable error state.
LDCMxxx	READY / FAIL	Line Differential Communication Error status
OEM	READY / FAIL	Optical Ethernet Module error status.

Also the internal signals, such as INT--FAIL and INT--WARNING can be connected to binary output contacts for signalling to a control room.

In the IED Status - Information, the present information from the self-supervision function can be viewed. Indications of failure or warnings for each hardware module are provided, as well as information about the external time synchronization and the internal clock. All according to table 15. Loss of time synchronization can be considered as a warning only. The IED has full functionality without time synchronization.

13.2.2

Using front-connected PC

When an internal fault has occurred, extensive information about the fault can be retrieved from the list of internal events available in the SMS part:

TRM-STAT TermStatus - Internal Events

The list of internal events provides valuable information, which can be used during commissioning and fault tracing.

The internal events are time tagged with a resolution of 1ms and stored in a list. The list can store up to 40 events. The list is based on the FIFO principle, when it is full, the oldest event is overwritten. The list cannot be cleared and its content cannot be erased.

The internal events in this list not only refer to faults in the IED, but also to other activities, such as change of settings, clearing of disturbance reports, and loss of external time synchronization.

The information can only be retrieved from the Parameter Setting software package. The PC can be connected either to the port at the front or at the rear of the IED.

These events are logged as internal events.

Table 16: *Events available for the internal event list in the IED*

Event message:		Description	Generating signal:
INT--FAIL	Off	Internal fail status	INT--FAIL (reset event)
INT--FAIL			INT--FAIL (set event)
INT--WARNING	Off	Internal warning status	INT--WARNING (reset event)
INT--WARNING			INT--WARNING (set event)
IOOn--Error	Off	In/Out module No. n status	IOOn--Error (reset event)
IOOn--Error			IOOn--Error (set event)
ADMn-Error	Off	Analog/Digital module No. n status	ADMn-Error (reset event)
ADMn-Error			ADMn-Error (set event)
MIM1-Error	Off	mA-input module status	MIM1-Error (reset event)
MIM1-Error			MIM1-Error (set event)
INT--RTC	Off	Real Time Clock (RTC) status	INT--RTC (reset event)
INT--RTC			INT--RTC (set event)
INT--TSYNC	Off	External time synchronization status	INT--TSYNC (reset event)
INT--TSYNC			INT--TSYNC (set event)
INT--SETCHGD		Any settings in IED changed	
DRPC-CLEARED		All disturbances in Disturbance report cleared	

The events in the internal event list are time tagged with a resolution of 1ms.

This means that, when using the PC for fault tracing, it provides information on the:

- Module that should be changed.
- Sequence of faults, if more than one unit is faulty.
- Exact time when the fault occurred.

13.3 Repair instruction



Never disconnect the secondary connection of a current transformer circuit without short-circuiting the transformer's secondary winding. Operating a current transformer with the secondary winding open will cause a massive potential build up that may damage the transformer and may cause injuries to humans.



Never connect or disconnect a wire and/or a connector to or from a IED during normal service. Hazardous voltages and currents are present that may be lethal. Operation may be disrupted and IED and measuring circuitry may be damaged.

An alternative is to open the IED and send only the faulty circuit board to ABB for repair. When a printed circuit board is sent to ABB, it must always be placed in a metallic, ESD-proof, protection bag. The user can also purchase separate replacement modules.



Strictly follow the company and country safety regulations.

Most electronic components are sensitive to electrostatic discharge and latent damage may occur. Please observe usual procedures for handling electronics and also use an ESD wrist strap. A semi-conducting layer must be placed on the workbench and connected to ground.

Disassemble and reassemble the IED accordingly:

1. Switch off the dc supply.
2. Short-circuit the current transformers and disconnect all current and voltage connections from the IED.
3. Disconnect all signal wires by removing the female connectors.
4. Disconnect the optical fibers.
5. Unscrew the main back plate of the IED.
6. If the transformer module is to be changed:

-
- Remove the IED from the panel if necessary.
 - Remove the rear plate of the IED.
 - Remove the front plate.
 - Remove the screws of the transformer input module, both front and rear.
7. Pull out the faulty module.
 8. Check that the new module has a correct identity number.
 9. Check that the springs on the card rail are connected to the corresponding metallic area on the circuit board when the new module is inserted.
 10. Reassemble the IED.

If the IED has been calibrated with the system inputs, the calibration procedure must be performed again to maintain the total system accuracy.

13.4 Repair support

If an IED needs to be repaired, the whole IED must be removed and sent to an ABB Logistic Center. Please contact the local ABB representative to get more details.

13.5 Maintenance

The IED is self-supervised. No special maintenance is required.

Instructions from the power network company and other maintenance directives valid for maintenance of the power system must be followed.

Section 14 Glossary

AC	Alternating current
ACC	Actual channel
ACT	Application configuration tool within PCM600
A/D converter	Analog-to-digital converter
ADBS	Amplitude deadband supervision
ADM	Analog digital conversion module, with time synchronization
AI	Analog input
ANSI	American National Standards Institute
AR	Autoreclosing
ASCT	Auxiliary summation current transformer
ASD	Adaptive signal detection
ASDU	Application service data unit
AWG	American Wire Gauge standard
BBP	Busbar protection
BFOC/2,5	Bayonet fibre optic connector
BFP	Breaker failure protection
BI	Binary input
BIM	Binary input module
BOM	Binary output module
BOS	Binary outputs status
BR	External bistable relay
BS	British Standards
BSR	Binary signal transfer function, receiver blocks
BST	Binary signal transfer function, transmit blocks
C37.94	IEEE/ANSI protocol used when sending binary signals between IEDs
CAN	Controller Area Network. ISO standard (ISO 11898) for serial communication

CB	Circuit breaker
CBM	Combined backplane module
CCITT	Consultative Committee for International Telegraph and Telephony. A United Nations-sponsored standards body within the International Telecommunications Union.
CCM	CAN carrier module
CCVT	Capacitive Coupled Voltage Transformer
Class C	Protection Current Transformer class as per IEEE/ ANSI
CMPPS	Combined megapulses per second
CMT	Communication Management tool in PCM600
CO cycle	Close-open cycle
Codirectional	Way of transmitting G.703 over a balanced line. Involves two twisted pairs making it possible to transmit information in both directions
COM	Command
COMTRADE	Standard Common Format for Transient Data Exchange format for Disturbance recorder according to IEEE/ANSI C37.111, 1999 / IEC60255-24
Contra-directional	Way of transmitting G.703 over a balanced line. Involves four twisted pairs, two of which are used for transmitting data in both directions and two for transmitting clock signals
COT	Cause of transmission
CPU	Central processing unit
CR	Carrier receive
CRC	Cyclic redundancy check
CROB	Control relay output block
CS	Carrier send
CT	Current transformer
CU	Communication unit
CVT or CCVT	Capacitive voltage transformer
DAR	Delayed autoreclosing
DARPA	Defense Advanced Research Projects Agency (The US developer of the TCP/IP protocol etc.)
DBDL	Dead bus dead line

DBLL	Dead bus live line
DC	Direct current
DFC	Data flow control
DFT	Discrete Fourier transform
DHCP	Dynamic Host Configuration Protocol
DIP-switch	Small switch mounted on a printed circuit board
DI	Digital input
DLLB	Dead line live bus
DNP	Distributed Network Protocol as per IEEE Std 1815-2012
DR	Disturbance recorder
DRAM	Dynamic random access memory
DRH	Disturbance report handler
DSP	Digital signal processor
DTT	Direct transfer trip scheme
EHV network	Extra high voltage network
EIA	Electronic Industries Association
EMC	Electromagnetic compatibility
EMF	Electromotive force
EMI	Electromagnetic interference
EnFP	End fault protection
EPA	Enhanced performance architecture
ESD	Electrostatic discharge
F-SMA	Type of optical fibre connector
FAN	Fault number
FCB	Flow control bit; Frame count bit
FOX 20	Modular 20 channel telecommunication system for speech, data and protection signals
FOX 512/515	Access multiplexer
FOX 6Plus	Compact time-division multiplexer for the transmission of up to seven duplex channels of digital data over optical fibers
FUN	Function type

G.703	Electrical and functional description for digital lines used by local telephone companies. Can be transported over balanced and unbalanced lines
GCM	Communication interface module with carrier of GPS receiver module
GDE	Graphical display editor within PCM600
GI	General interrogation command
GIS	Gas-insulated switchgear
GOOSE	Generic object-oriented substation event
GPS	Global positioning system
GSAL	Generic security application
GTM	GPS Time Module
HDLC protocol	High-level data link control, protocol based on the HDLC standard
HFBR connector type	Plastic fiber connector
HMI	Human-machine interface
HSAR	High speed autoreclosing
HV	High-voltage
HVDC	High-voltage direct current
IDBS	Integrating deadband supervision
IEC	International Electrical Committee
IEC 60044-6	IEC Standard, Instrument transformers – Part 6: Requirements for protective current transformers for transient performance
IEC 60870-5-103	Communication standard for protection equipment. A serial master/slave protocol for point-to-point communication
IEC 61850	Substation automation communication standard
IEC 61850-8-1	Communication protocol standard
IEEE	Institute of Electrical and Electronics Engineers
IEEE 802.12	A network technology standard that provides 100 Mbits/s on twisted-pair or optical fiber cable
IEEE P1386.1	PCI Mezzanine Card (PMC) standard for local bus modules. References the CMC (IEEE P1386, also known as Common Mezzanine Card) standard for the mechanics and the PCI specifications from the PCI SIG (Special Interest Group) for the electrical EMF (Electromotive force).

IEEE 1686	Standard for Substation Intelligent Electronic Devices (IEDs) Cyber Security Capabilities
IED	Intelligent electronic device
I-GIS	Intelligent gas-insulated switchgear
IOM	Binary input/output module
Instance	When several occurrences of the same function are available in the IED, they are referred to as instances of that function. One instance of a function is identical to another of the same kind but has a different number in the IED user interfaces. The word "instance" is sometimes defined as an item of information that is representative of a type. In the same way an instance of a function in the IED is representative of a type of function.
IP	<p>1. Internet protocol. The network layer for the TCP/IP protocol suite widely used on Ethernet networks. IP is a connectionless, best-effort packet-switching protocol. It provides packet routing, fragmentation and reassembly through the data link layer.</p> <p>2. Ingression protection, according to IEC 60529</p>
IP 20	Ingression protection, according to IEC 60529, level IP20- Protected against solid foreign objects of 12.5mm diameter and greater.
IP 40	Ingression protection, according to IEC 60529, level IP40- Protected against solid foreign objects of 1mm diameter and greater.
IP 54	Ingression protection, according to IEC 60529, level IP54-Dust-protected, protected against splashing water.
IRF	Internal failure signal
IRIG-B:	InterRange Instrumentation Group Time code format B, standard 200
ITU	International Telecommunications Union
LAN	Local area network
LIB 520	High-voltage software module
LCD	Liquid crystal display
LDCM	Line differential communication module
LDD	Local detection device
LED	Light-emitting diode

LNT	LON network tool
LON	Local operating network
MCB	Miniature circuit breaker
MCM	Mezzanine carrier module
MIM	Milli-ampere module
MPM	Main processing module
MVAL	Value of measurement
MVB	Multifunction vehicle bus. Standardized serial bus originally developed for use in trains.
NCC	National Control Centre
NOF	Number of grid faults
NUM	Numerical module
OCO cycle	Open-close-open cycle
OCP	Overcurrent protection
OEM	Optical Ethernet module
OLTC	On-load tap changer
OTEV	Disturbance data recording initiated by other event than start/pick-up
OV	Overvoltage
Overreach	A term used to describe how the relay behaves during a fault condition. For example, a distance relay is overreaching when the impedance presented to it is smaller than the apparent impedance to the fault applied to the balance point, that is, the set reach. The relay “sees” the fault but perhaps it should not have seen it.
PCI	Peripheral component interconnect, a local data bus
PCM	Pulse code modulation
PCM600	Protection and control IED manager
PC-MIP	Mezzanine card standard
PMC	PCI Mezzanine card
POR	Permissive overreach
POTT	Permissive overreach transfer trip
Process bus	Bus or LAN used at the process level, that is, in near proximity to the measured and/or controlled components

PSM	Power supply module
PST	Parameter setting tool within PCM600
PT ratio	Potential transformer or voltage transformer ratio
PUTT	Permissive underreach transfer trip
RASC	Synchrocheck relay, COMBIFLEX
RCA	Relay characteristic angle
RISC	Reduced instruction set computer
RMS value	Root mean square value
RS422	A balanced serial interface for the transmission of digital data in point-to-point connections
RS485	Serial link according to EIA standard RS485
RTC	Real-time clock
RTU	Remote terminal unit
SA	Substation Automation
SBO	Select-before-operate
SC	Switch or push button to close
SCL	Short circuit location
SCS	Station control system
SCADA	Supervision, control and data acquisition
SCT	System configuration tool according to standard IEC 61850
SDU	Service data unit
SLM	Serial communication module.
SMA connector	Subminiature version A, A threaded connector with constant impedance.
SMT	Signal matrix tool within PCM600
SMS	Station monitoring system
SNTP	Simple network time protocol – is used to synchronize computer clocks on local area networks. This reduces the requirement to have accurate hardware clocks in every embedded system in a network. Each embedded node can instead synchronize with a remote clock, providing the required accuracy.
SOF	Status of fault

SPA	Strömberg Protection Acquisition (SPA), a serial master/slave protocol for point-to-point communication
SRY	Switch for CB ready condition
ST	Switch or push button to trip
Starpoint	Neutral/Wye point of transformer or generator
SVC	Static VAR compensation
TC	Trip coil
TCS	Trip circuit supervision
TCP	Transmission control protocol. The most common transport layer protocol used on Ethernet and the Internet.
TCP/IP	Transmission control protocol over Internet Protocol. The de facto standard Ethernet protocols incorporated into 4.2BSD Unix. TCP/IP was developed by DARPA for Internet working and encompasses both network layer and transport layer protocols. While TCP and IP specify two protocols at specific protocol layers, TCP/IP is often used to refer to the entire US Department of Defense protocol suite based upon these, including Telnet, FTP, UDP and RDP.
TEF	Time delayed ground-fault protection function
TM	Transmit (disturbance data)
TNC connector	Threaded Neill-Concelman, a threaded constant impedance version of a BNC connector
TP	Trip (recorded fault)
TPZ, TPY, TPX, TPS	Current transformer class according to IEC
TRM	Transformer Module. This module transforms currents and voltages taken from the process into levels suitable for further signal processing.
TYP	Type identification
UMT	User management tool
Underreach	A term used to describe how the relay behaves during a fault condition. For example, a distance relay is underreaching when the impedance presented to it is greater than the apparent impedance to the fault applied to the balance point, that is, the set reach. The relay does not “see” the fault but perhaps it should have seen it. See also Overreach.
UTC	Coordinated Universal Time. A coordinated time scale, maintained by the Bureau International des Poids et Mesures

(BIPM), which forms the basis of a coordinated dissemination of standard frequencies and time signals. UTC is derived from International Atomic Time (TAI) by the addition of a whole number of "leap seconds" to synchronize it with Universal Time 1 (UT1), thus allowing for the eccentricity of the Earth's orbit, the rotational axis tilt (23.5 degrees), but still showing the Earth's irregular rotation, on which UT1 is based. The Coordinated Universal Time is expressed using a 24-hour clock, and uses the Gregorian calendar. It is used for aeroplane and ship navigation, where it is also sometimes known by the military name, "Zulu time." "Zulu" in the phonetic alphabet stands for "Z", which stands for longitude zero.

UV	Undervoltage
WEI	Weak end infeed logic
VT	Voltage transformer
X.21	A digital signalling interface primarily used for telecom equipment
3I₀	Three times zero-sequence current. Often referred to as the residual or the ground-fault current
3V₀	Three times the zero sequence voltage. Often referred to as the residual voltage or the neutral point voltage

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